

Faculty of Engineering
School of Photovoltaic and Renewable Energy Engineering

Solcore Workshop – Silicon Tandem Cell Computer Modelling

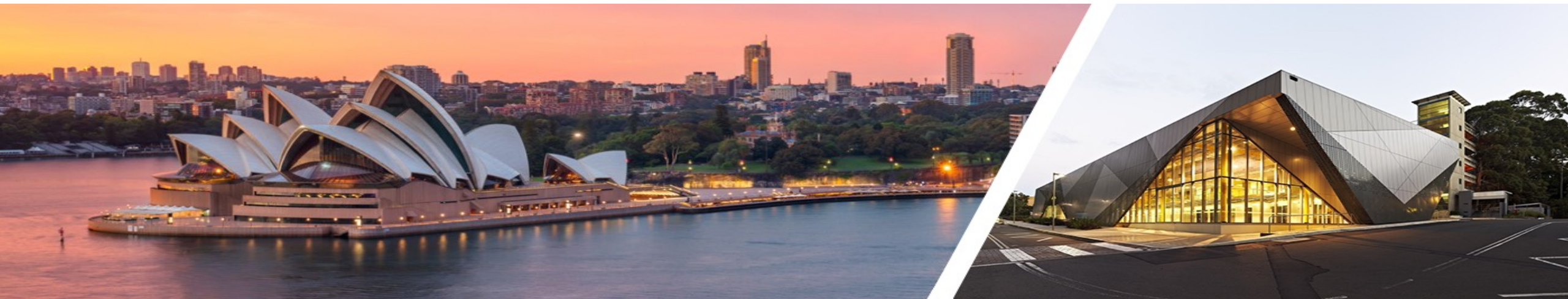
Sungkyunkwan University, 1 – 3 August 2023

N.J. Ekins-Daukes & Phoebe Pearce

 nekins@unsw.edu.au

 www.qpvgroup.org

 [EkinsNed](https://twitter.com/EkinsNed)

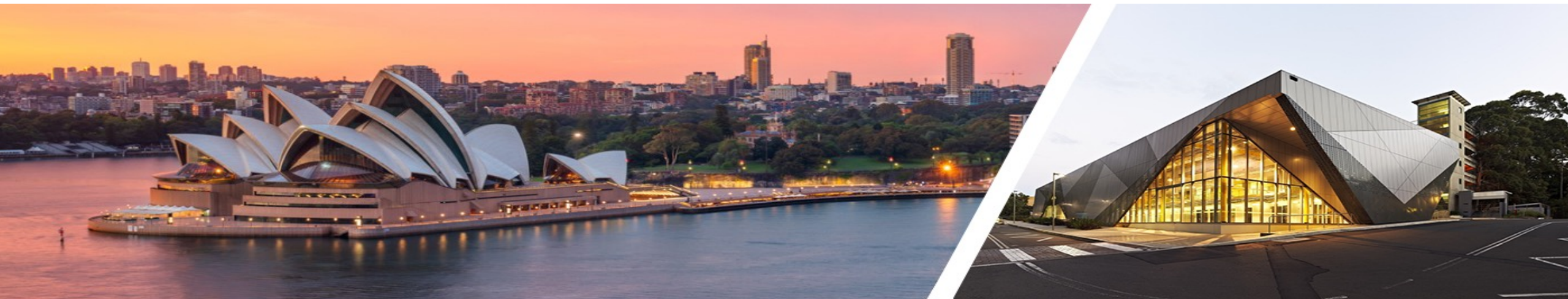


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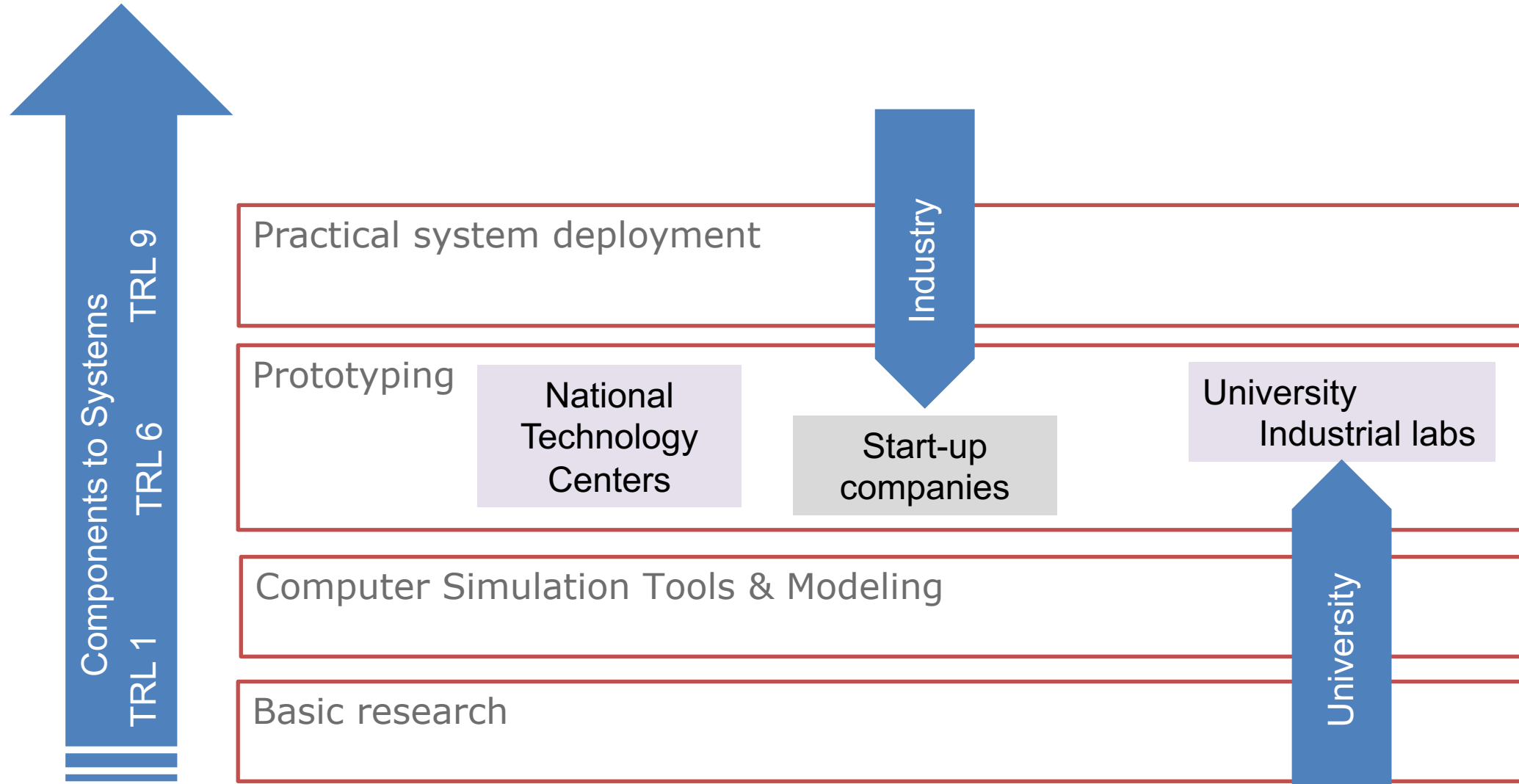
Session 1: Introduction

1 August 2023

Ned Ekins-Daukes, Phoebe Pearce



A Role for Computer Simulation in the Modern Technological Innovation Process

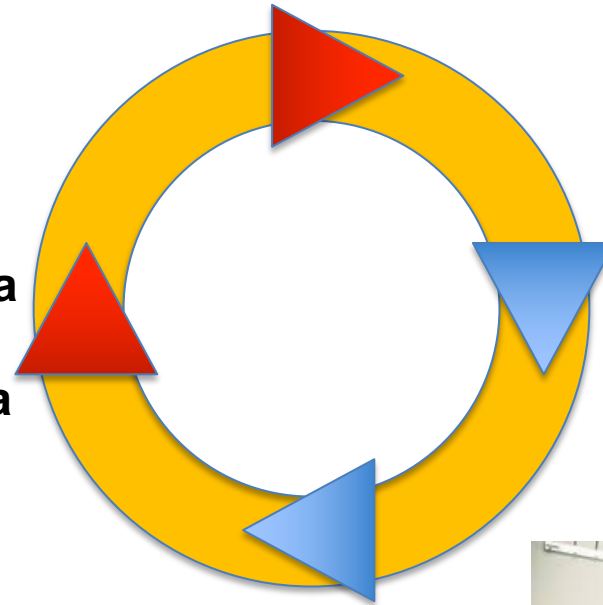


The Present Value of Computer Modelling in Research & Development

Design aided by
a computer (TCAD):



Evaluate data
through
fitting of data



Device
Fabrication



Device Test

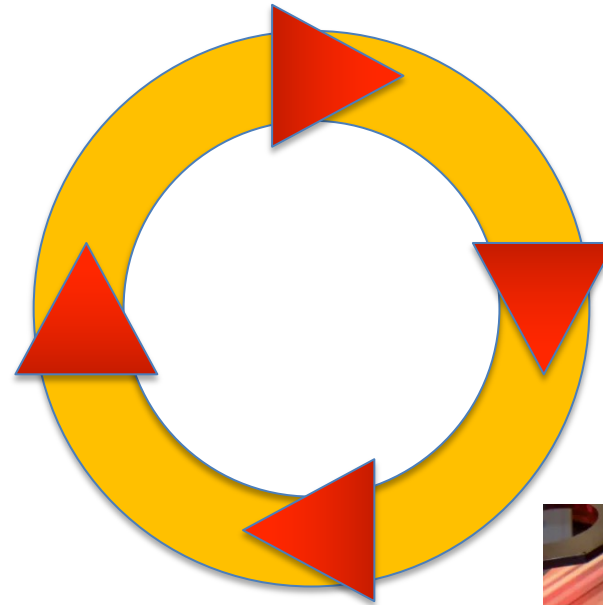


The Future Value of Computer Modelling in Research & Development

Design aided by
a computer (TCAD):



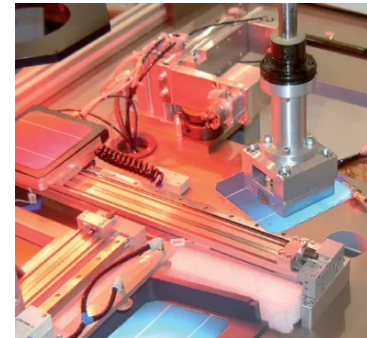
AI
assisted
fitting of
test data



Robot Device
Fabrication



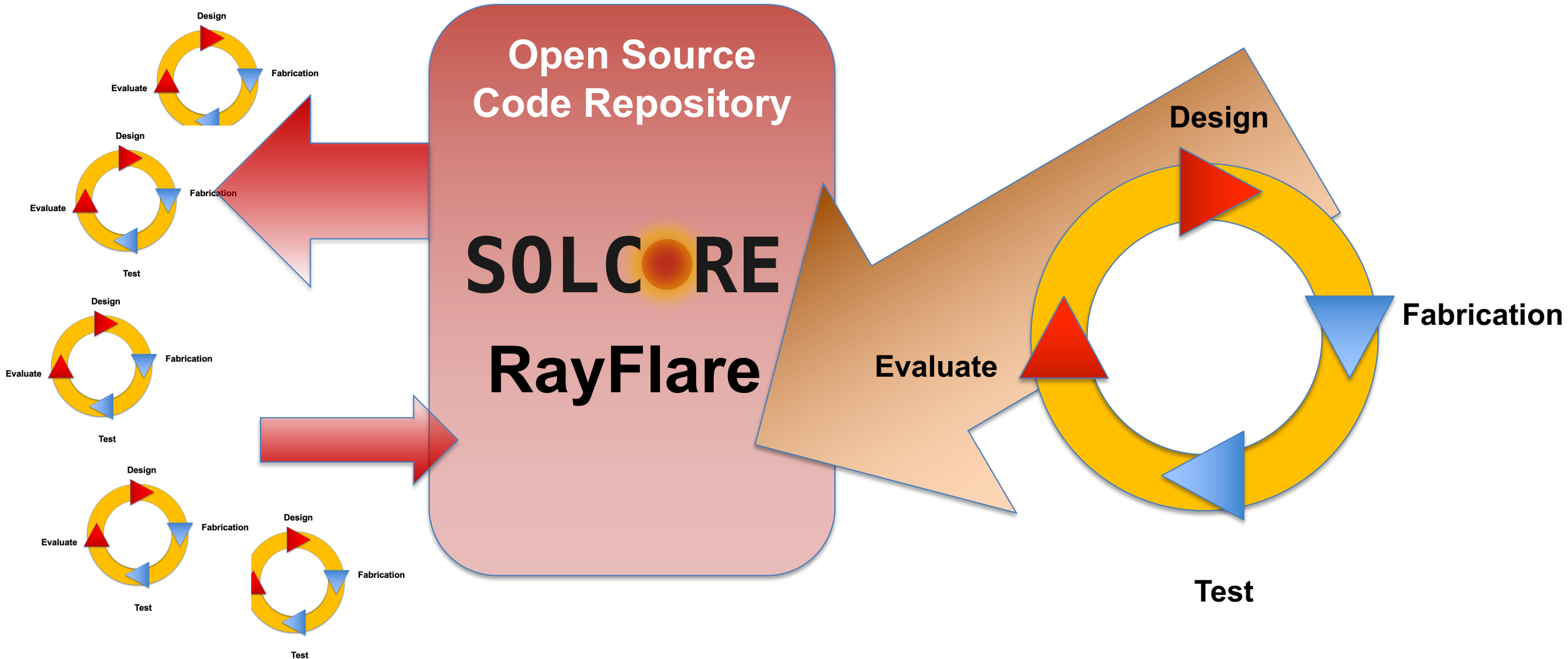
Automated
Device Test



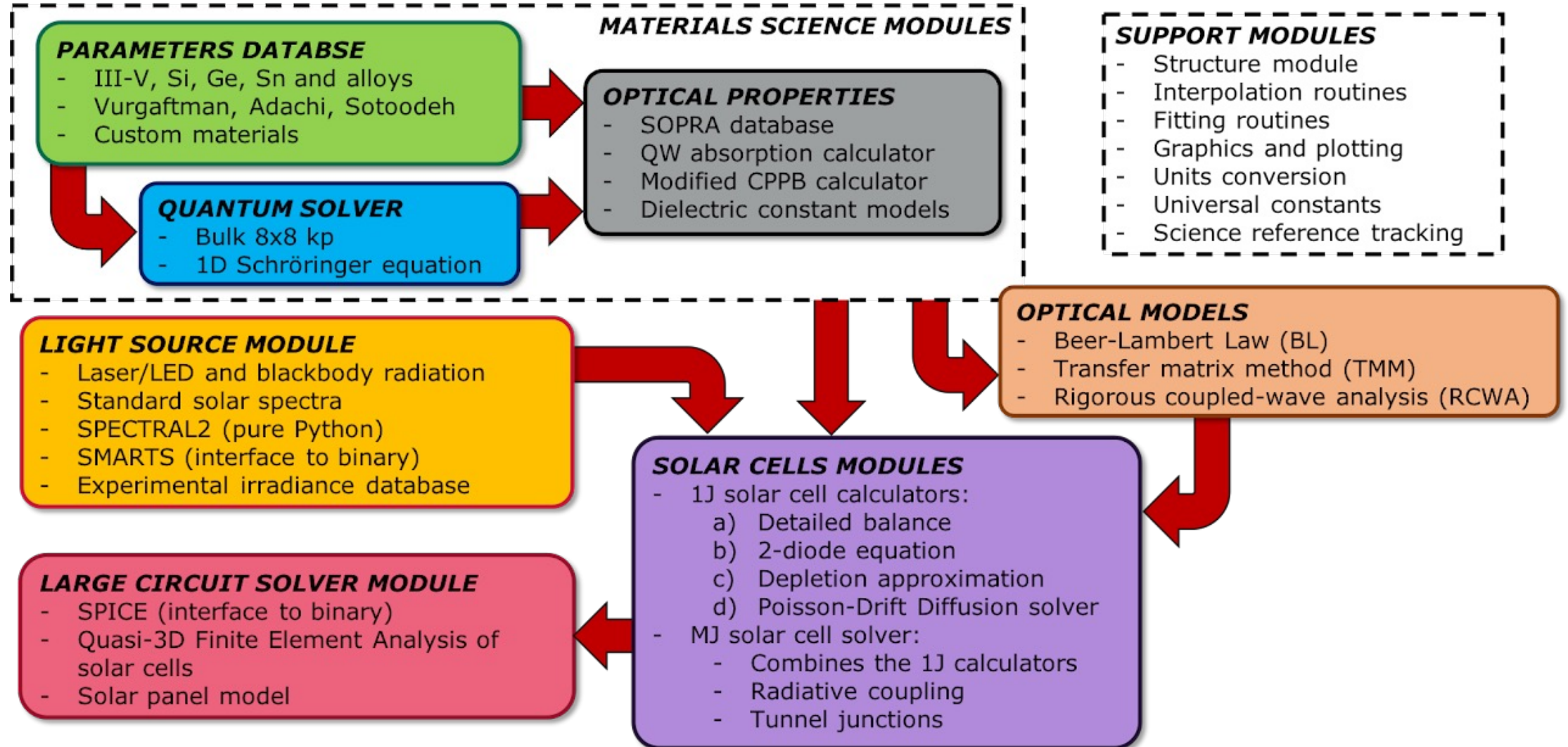
Development Process for our Computer Code:

Global PV R&D Community

QPV Research Group



Solcore capabilities



www.solcore.solar

RayFlare capabilities

Simulations using a single method



Ray-tracing: Geometric optics for large-scale textures without diffraction effects



Transfer-matrix method: Wave optics for planar layers (coherent and incoherent)



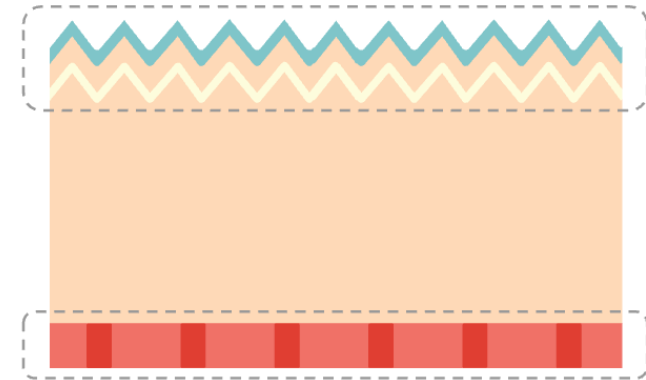
Rigorous coupled-wave analysis: Wave optics for planar or periodic structures e.g. gratings, photonic crystals

Ideal cases: E.g. perfect mirrors, Lambertian scattering

Calculate e.g. reflection, transmission, absorption per layer, depth-dependent absorption profiles

Simulations using angular redistribution matrices

Each surface is treated separately with an appropriate method



- Free, open source
- Anyone can contribute
- Modular
- Documented

<https://rayflare.readthedocs.io>

Course instructions

GitHub repository where the tutorials for this workshop are hosted:

<https://tinyurl.com/2mn6rb64>



*Look at the tutorials +
the expected outputs online*

solcore-education

Collection of teaching materials and scripts to help st

[Click here](#) to view the examples on GitHub Pages.

View/run the examples on Binder:



*Use Binder to run Python in your
browser & work through the examples*

To run Solcore & RayFlare on your own computer, you will need to install Python (version 3.7 to 3.11), and then:

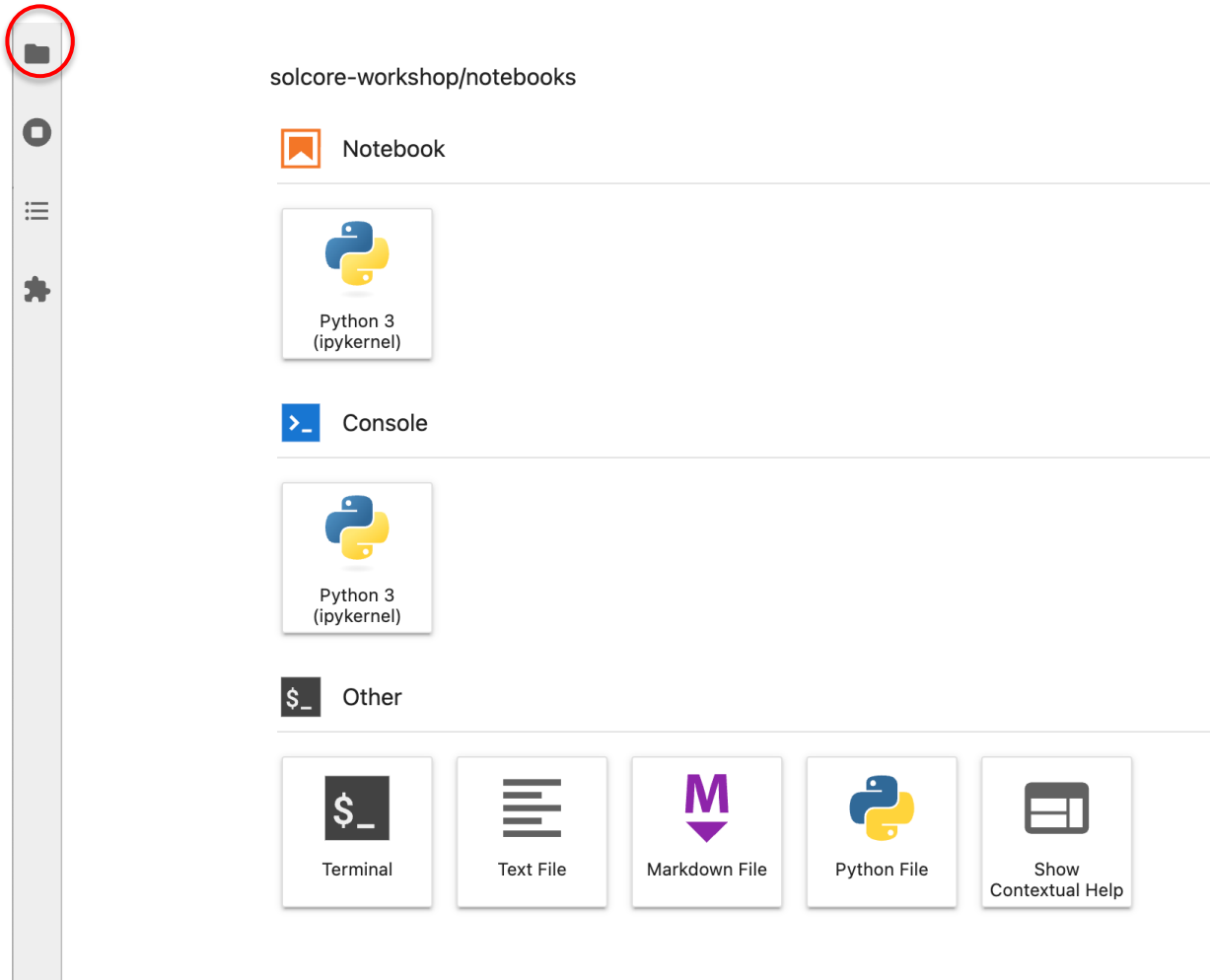
pip install solcore rayflare seaborn

Recommendations for installing Python:

- On **Windows**, use **miniconda** (<https://conda.io/miniconda.html>)
- On **MacOS**, use **Homebrew + venv** (see RayFlare's installation instructions for more detail)
- On **Ubuntu/Linux**, use **system Python + venv** (see RayFlare's installation instructions for more detail)

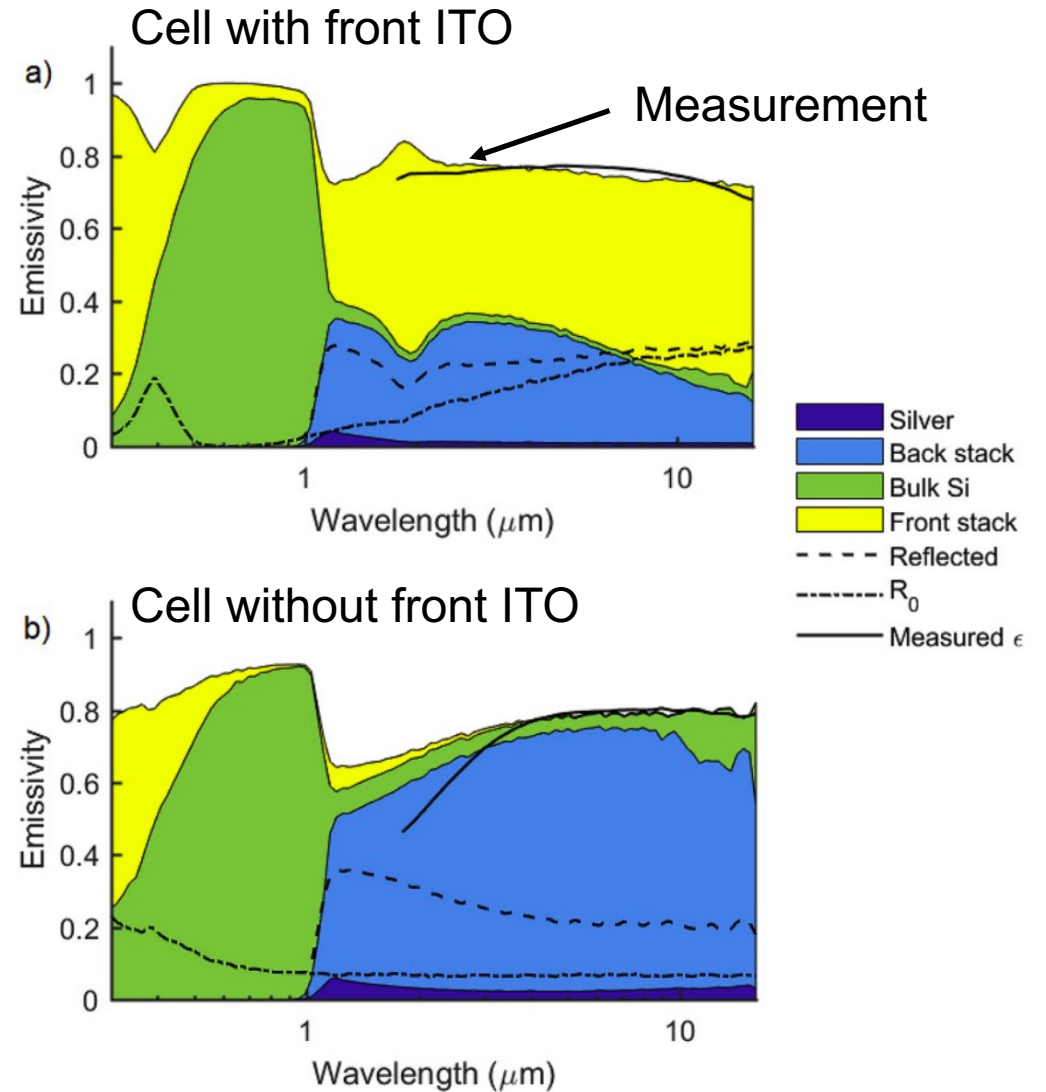
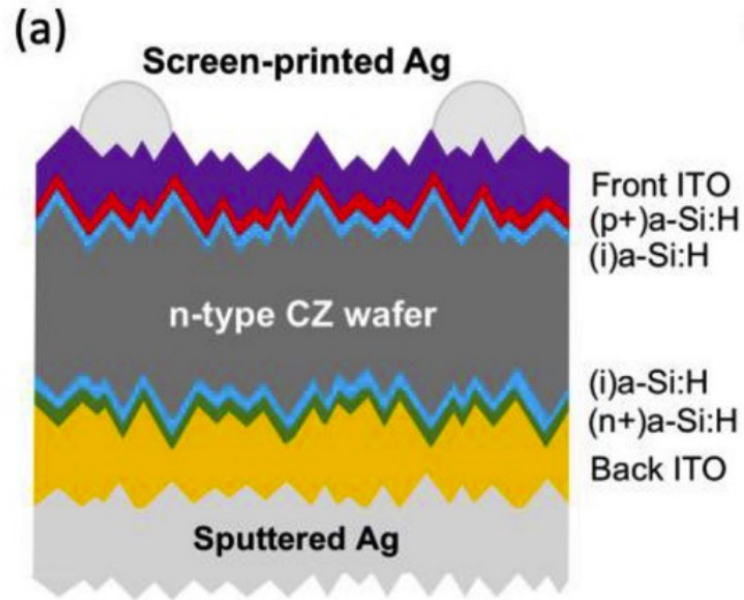
Binder

- Binder may take a long time (~ 10 minutes) to load, so please click the link to '[Launch Binder](#)' now



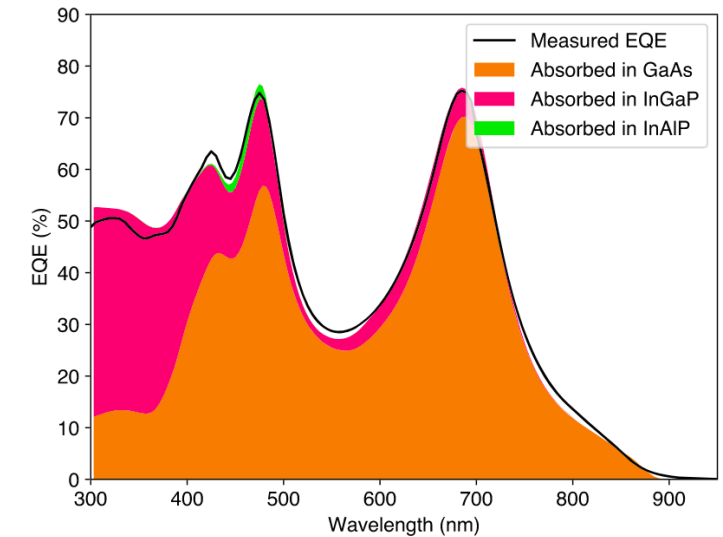
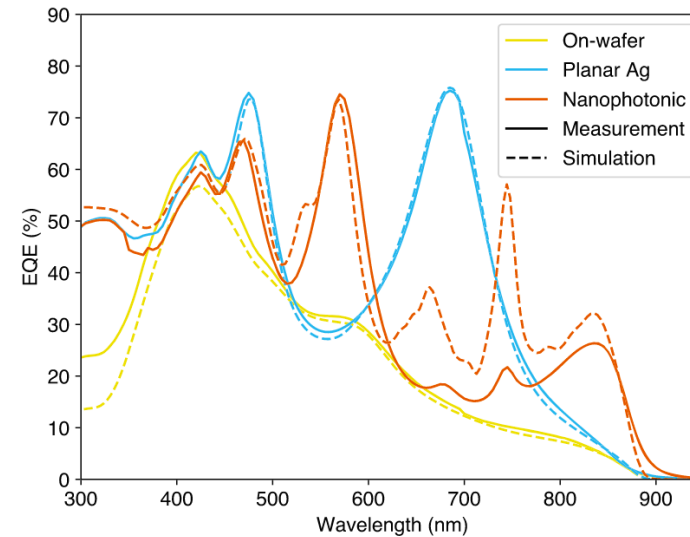
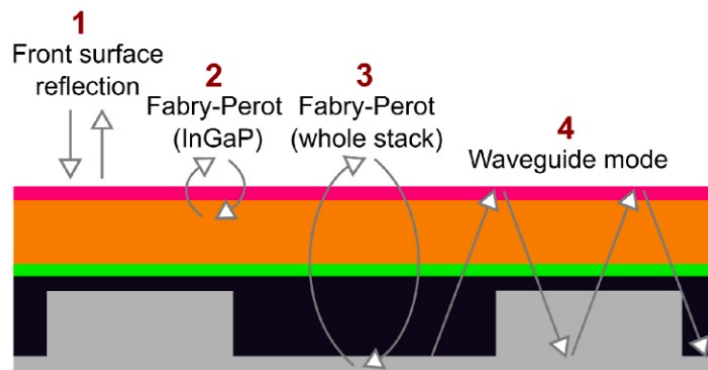
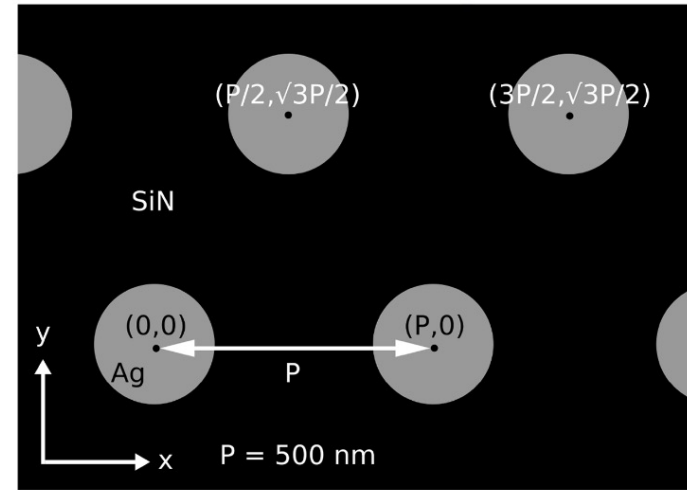
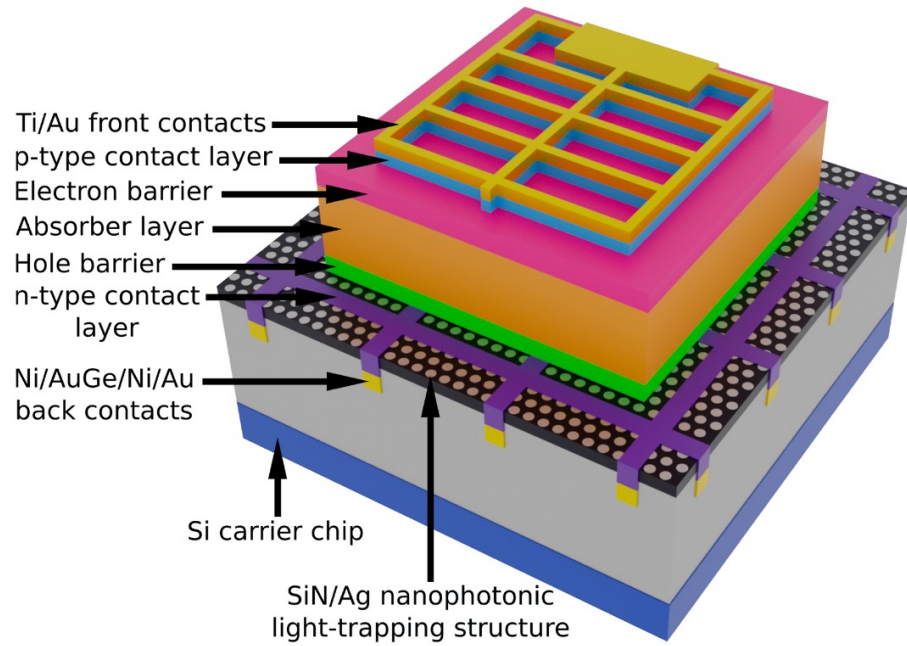
After loading, it should look like this – click circled icon to open the examples

Example: Si cell emissivity

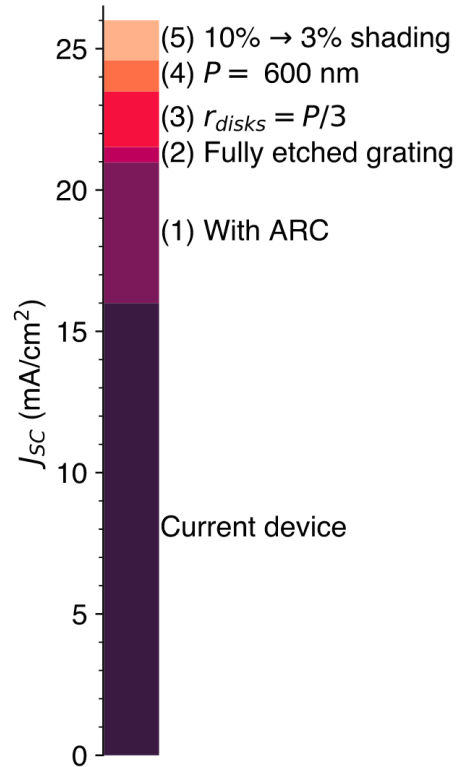


Simulations & measurement of cell absorptivity (emissivity) between 300 nm and 20 μm . This is relevant for the operating temperature of the cell. Due to free-carrier absorption in doped layers and very good light-trapping, the cell absorbs well even at wavelengths far beyond the bandgap.

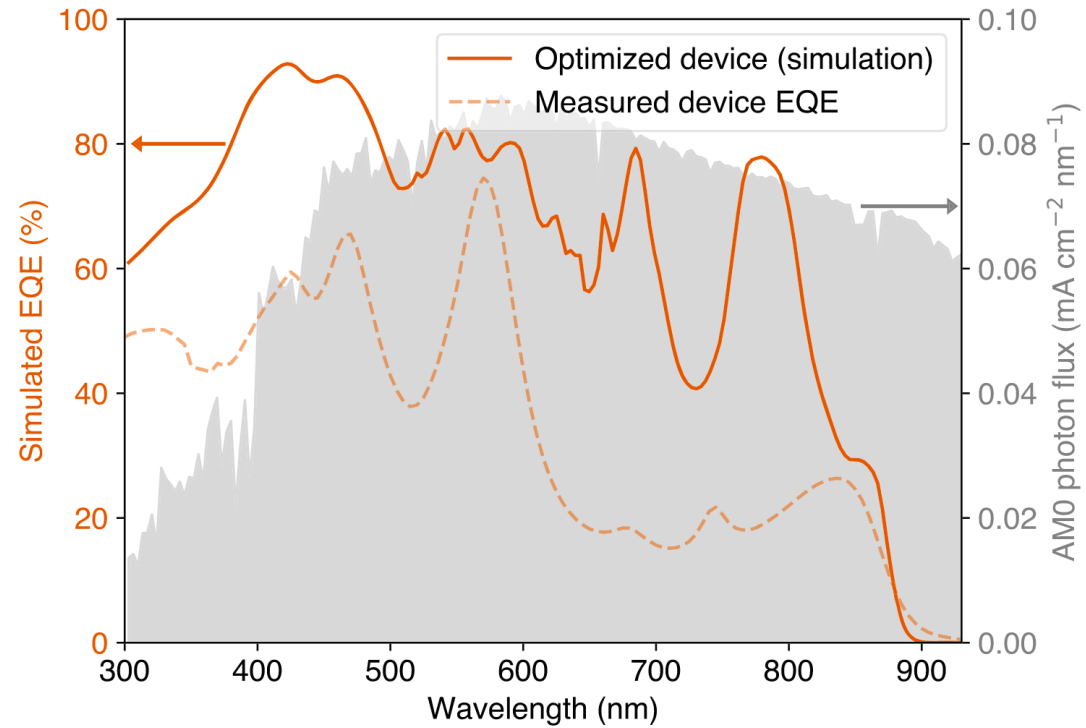
Example: ultra-thin GaAs cell



Example: ultra-thin GaAs cell (cont.)

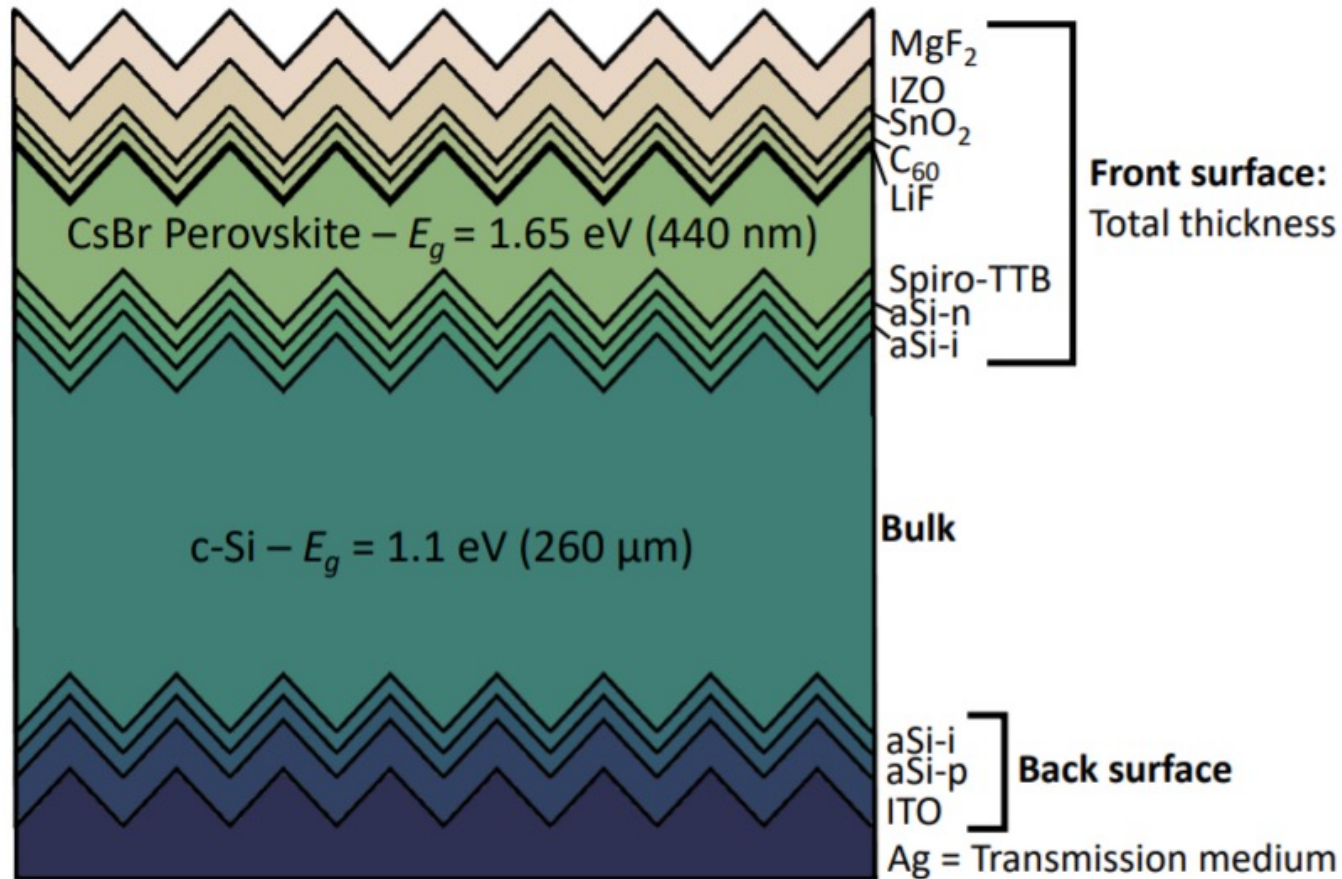


(A)



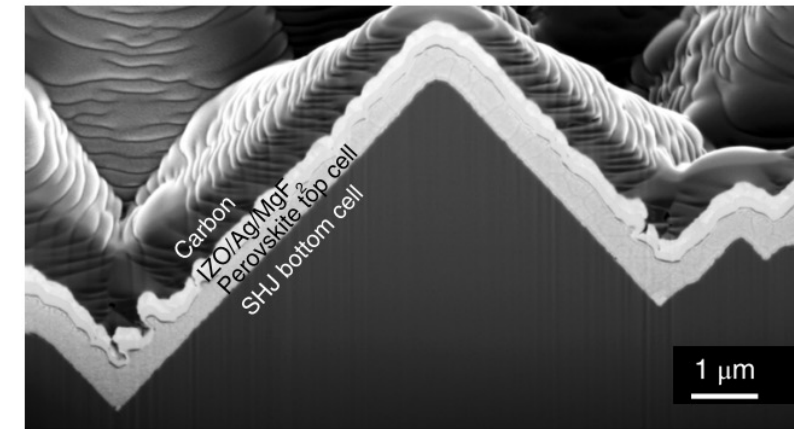
(B)

Example: Perovskite/Si tandem cell



Perovskite on silicon heterojunction (SHJ) tandem cell

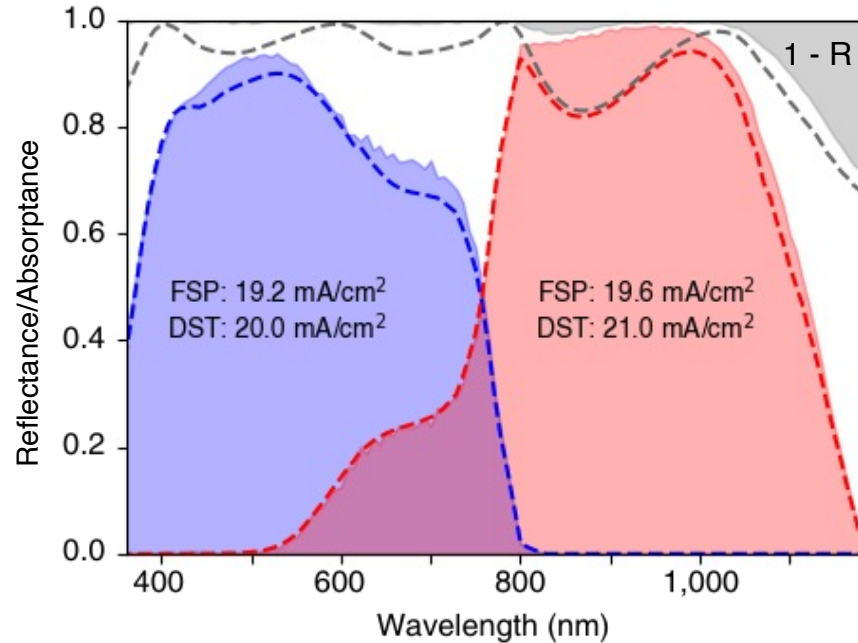
Perovskite is deposited conformally on standard etched Si pyramid texture



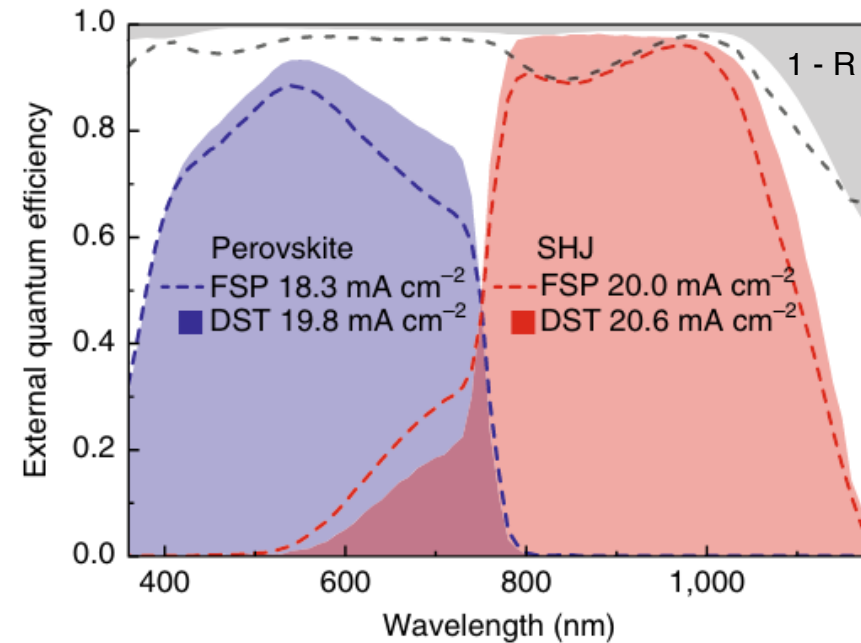
From [1]

Example: Perovskite/Si tandem cell (cont.)

RayFlare simulation



EQE measurement



FSP = Front-side polished



DST = Double-side textured



As a result of the front surface texture:

- Peak in R around 830 nm is reduced (lower front-surface reflectivity)
- Perovskite absorption slightly enhanced
- Boosts long-wavelength absorption (better light-trapping inside Si)

From [1]

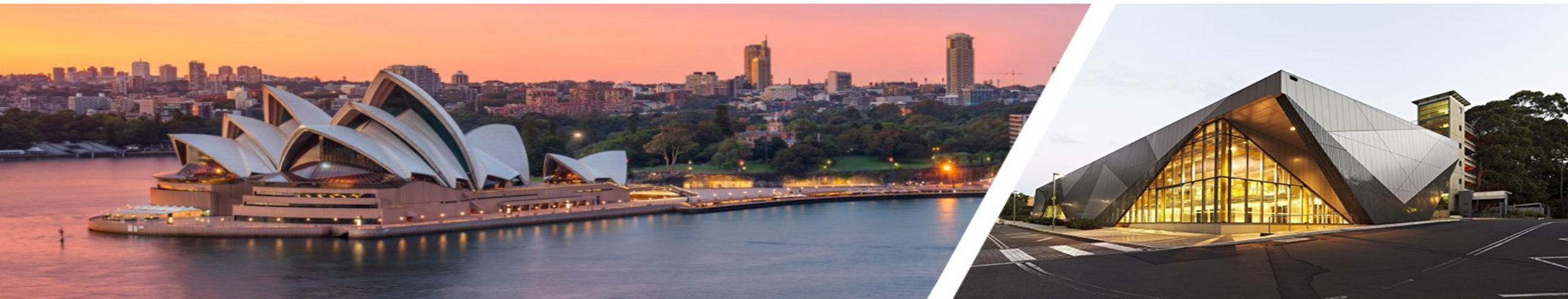
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Session 2: Hands-on exercise

Using SolCore to calculate the Shockley-Queisser Efficiency limit

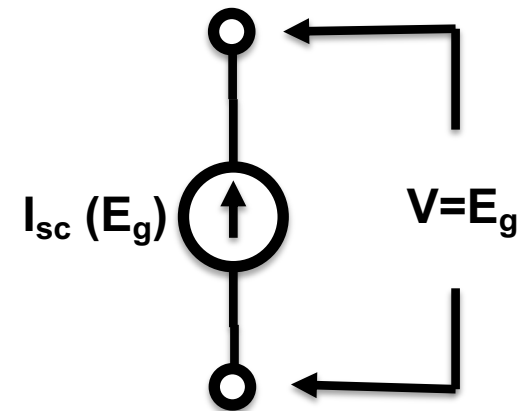
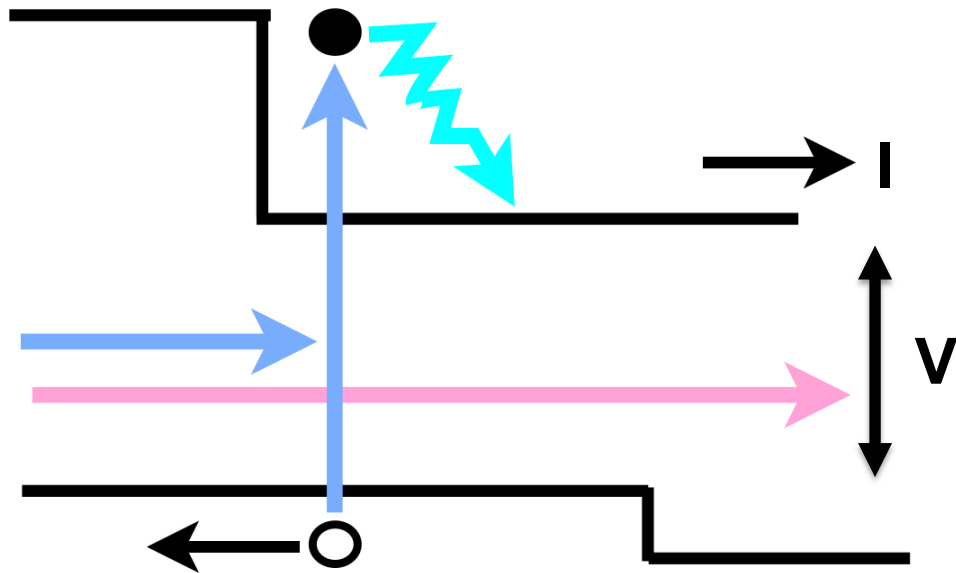
1 August 2023

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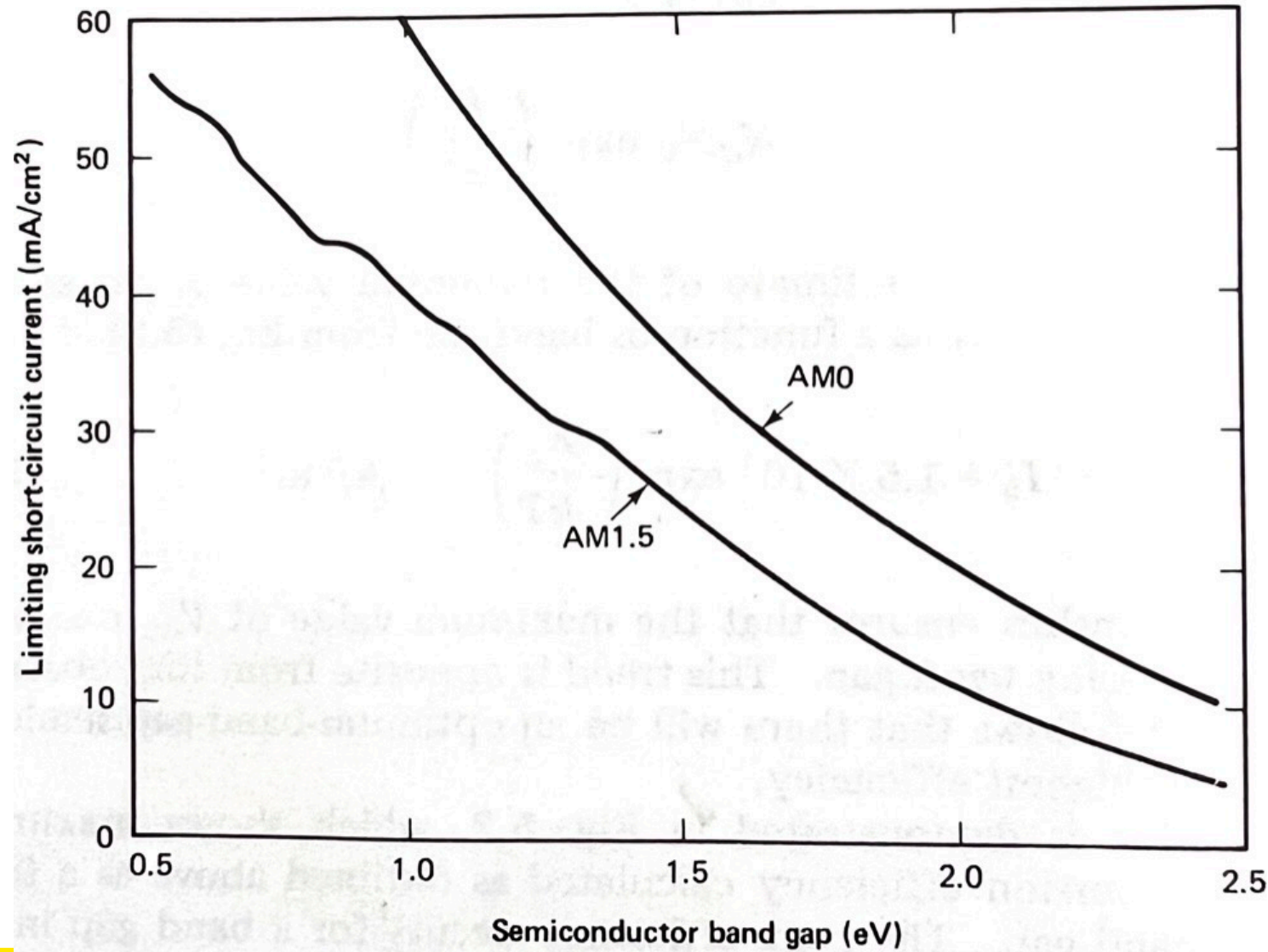
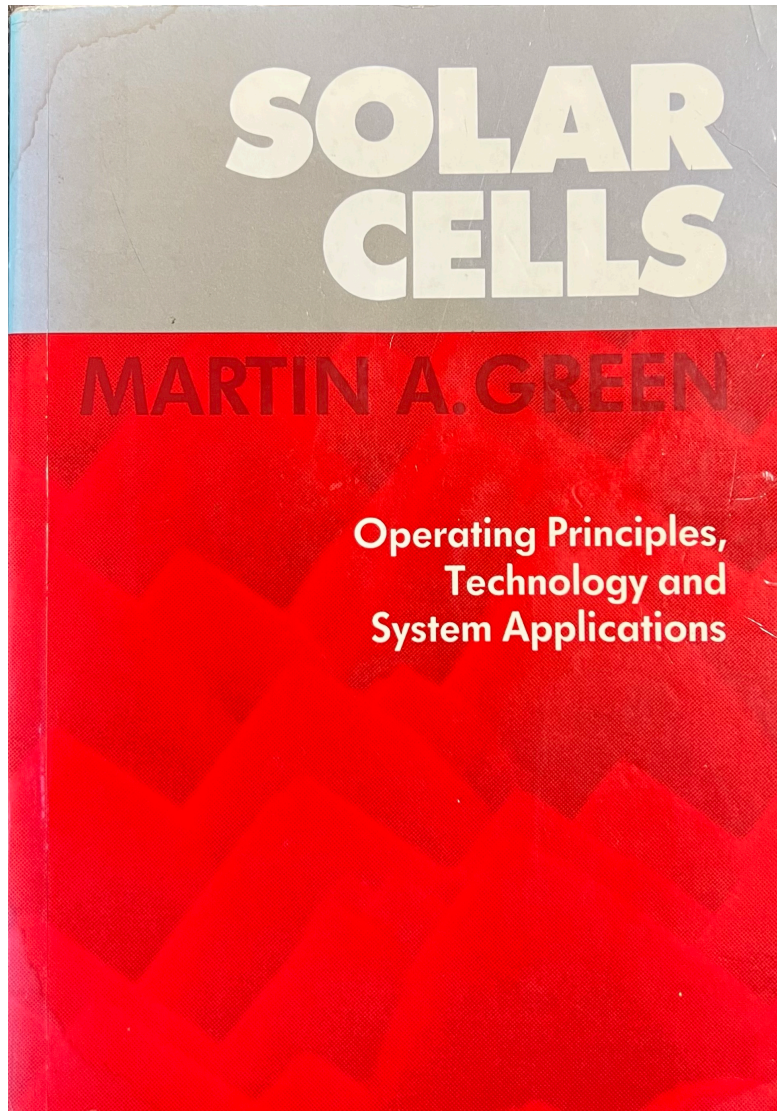
What is the Maximum Efficiency of a Solar Cell?

Trivich-Flynn Limit (1955)



Warning : Limit is invalid for $T > 0K$!

Trivich D, Flinn PA. Maximum efficiency of solar energy conversion by quantum processes. In Solar Energy Research, Daniels F, Duffie J (eds). Thames and Hudson: London, 1955.



What is the Maximum Efficiency of a Solar Cell?

Shockley Queisser limit (1961)

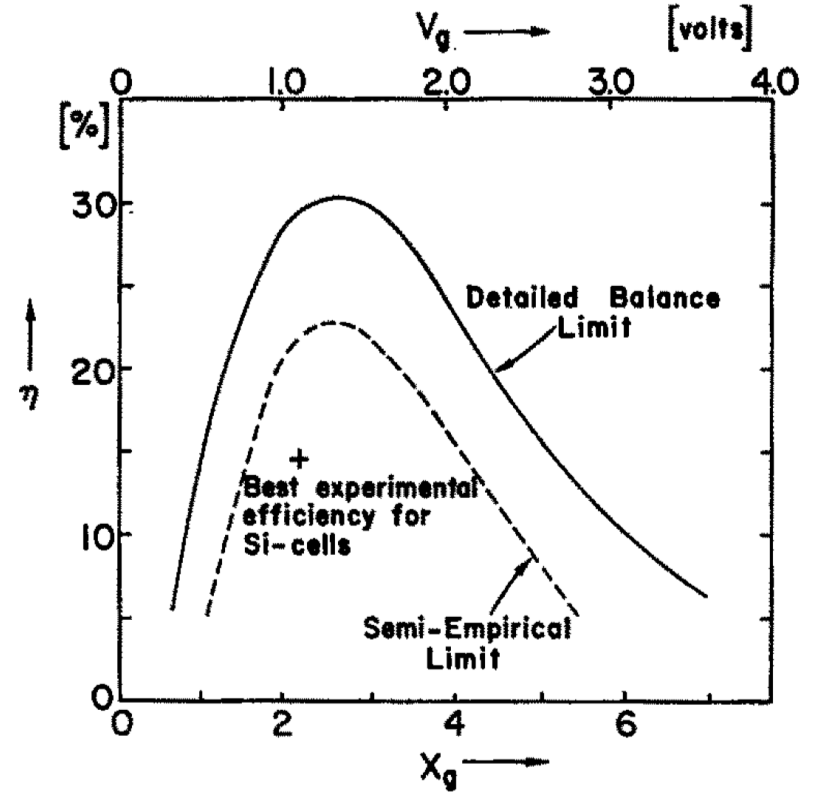
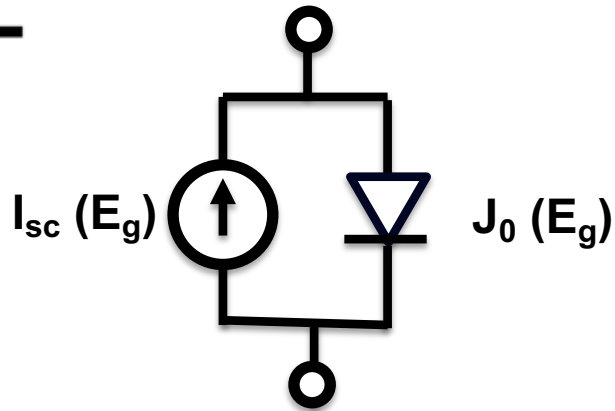
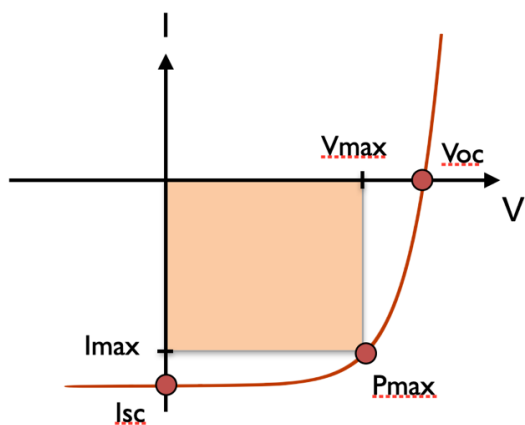
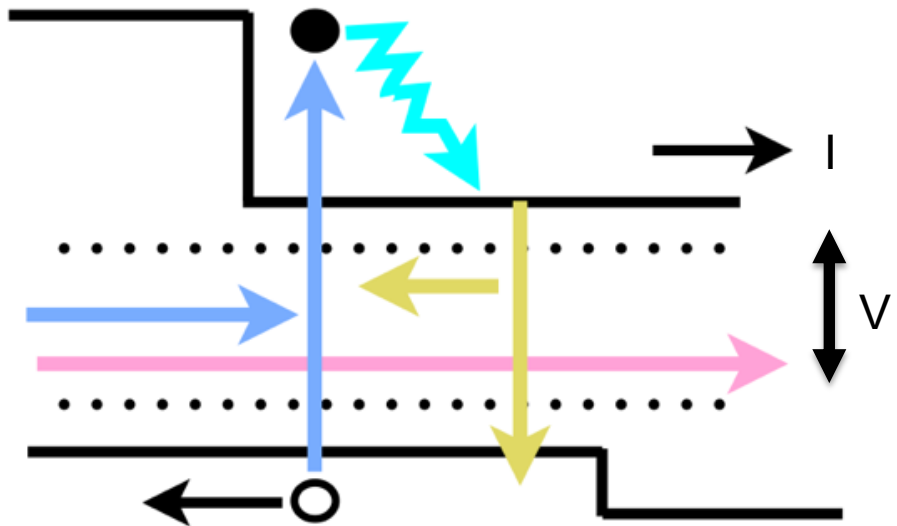


FIG. 1. Comparison of the "semiempirical limit" of efficiency of solar cells with the "detailed balance limit," derived in this paper. + represents the "best experiment efficiency to date" for silicon cells. (See footnote 6.)

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Session 3: Shockley-Queisser efficiency limit & detailed balance junction model

1st August 2023

Ned Ekins-Daukes, Phoebe Pearce

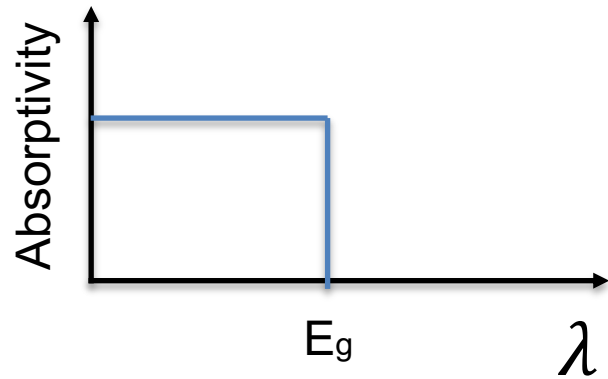


Optical Models for PV Devices

Fundamental

Shockley-Queisser (Detail Balance)

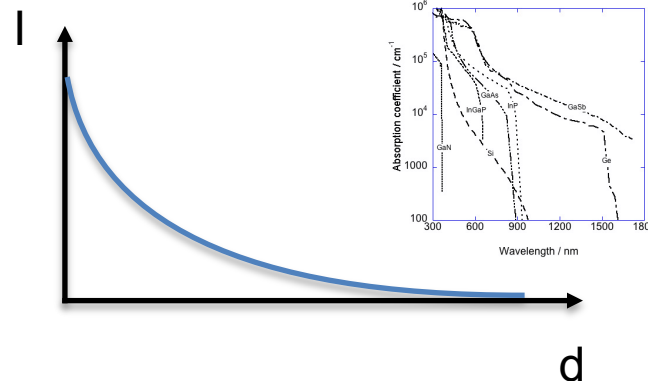
*Complete absorption to
band-gap energy E_g*



Beer Lambert Law

$$I = I_0 e^{-\alpha d}$$

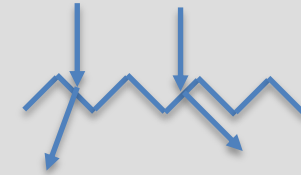
*Intensity of light is attenuated
exponentially with increasing thickness of
absorber d [m].
Absorption defined by a wavelength
dependent absorption coefficient
 $\alpha(\lambda)$ [m^{-1}]*



Ray Optics

**Non-uniform surfaces or PV
structures $\gg \lambda$**

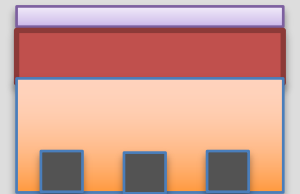
Surface texture of a silicon solar cell



Wave Optics

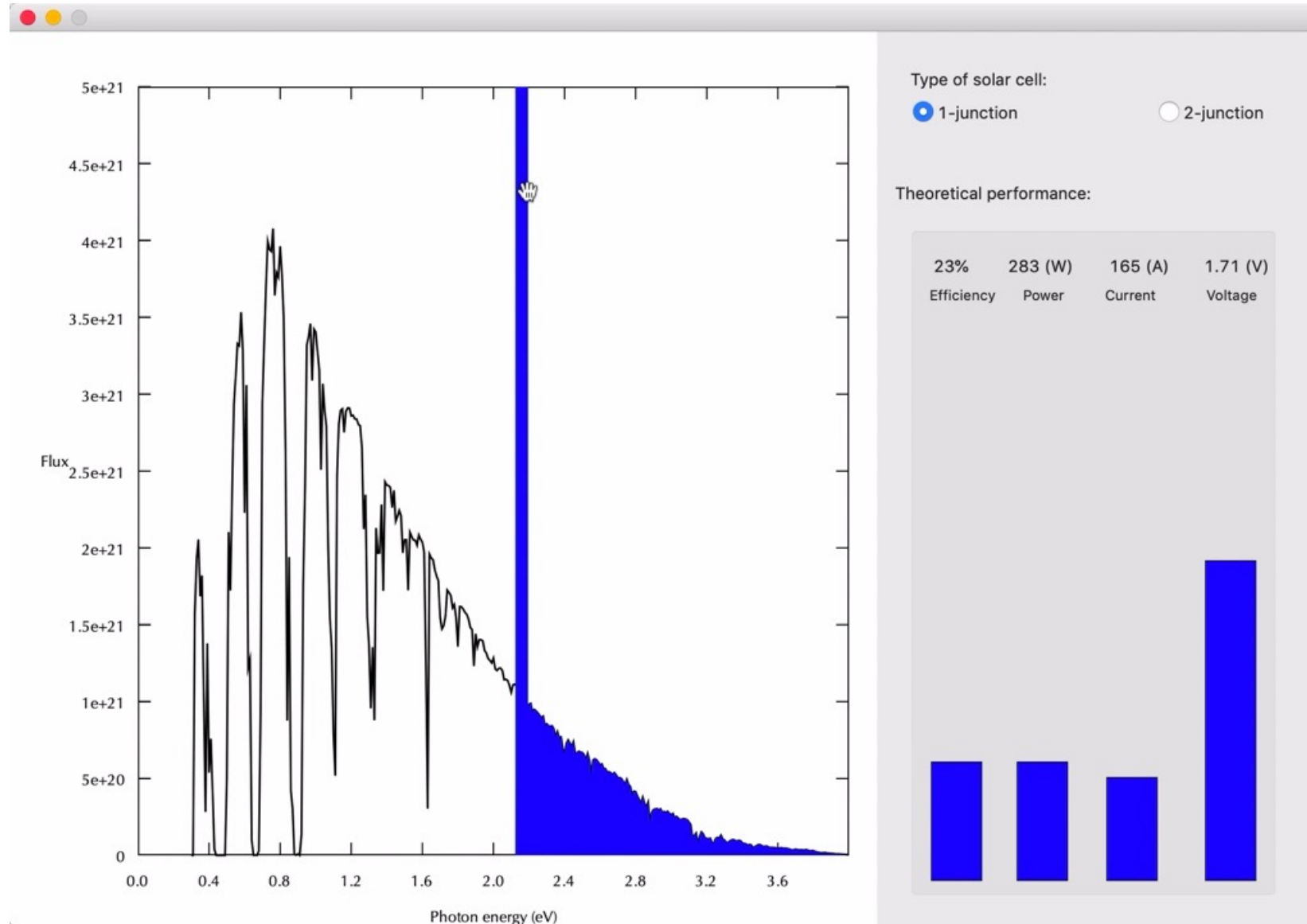
Sub-wavelength structures $\ll \lambda$

*Anti-reflection coating
90nm p-doped layer
800nm n-doped layer*

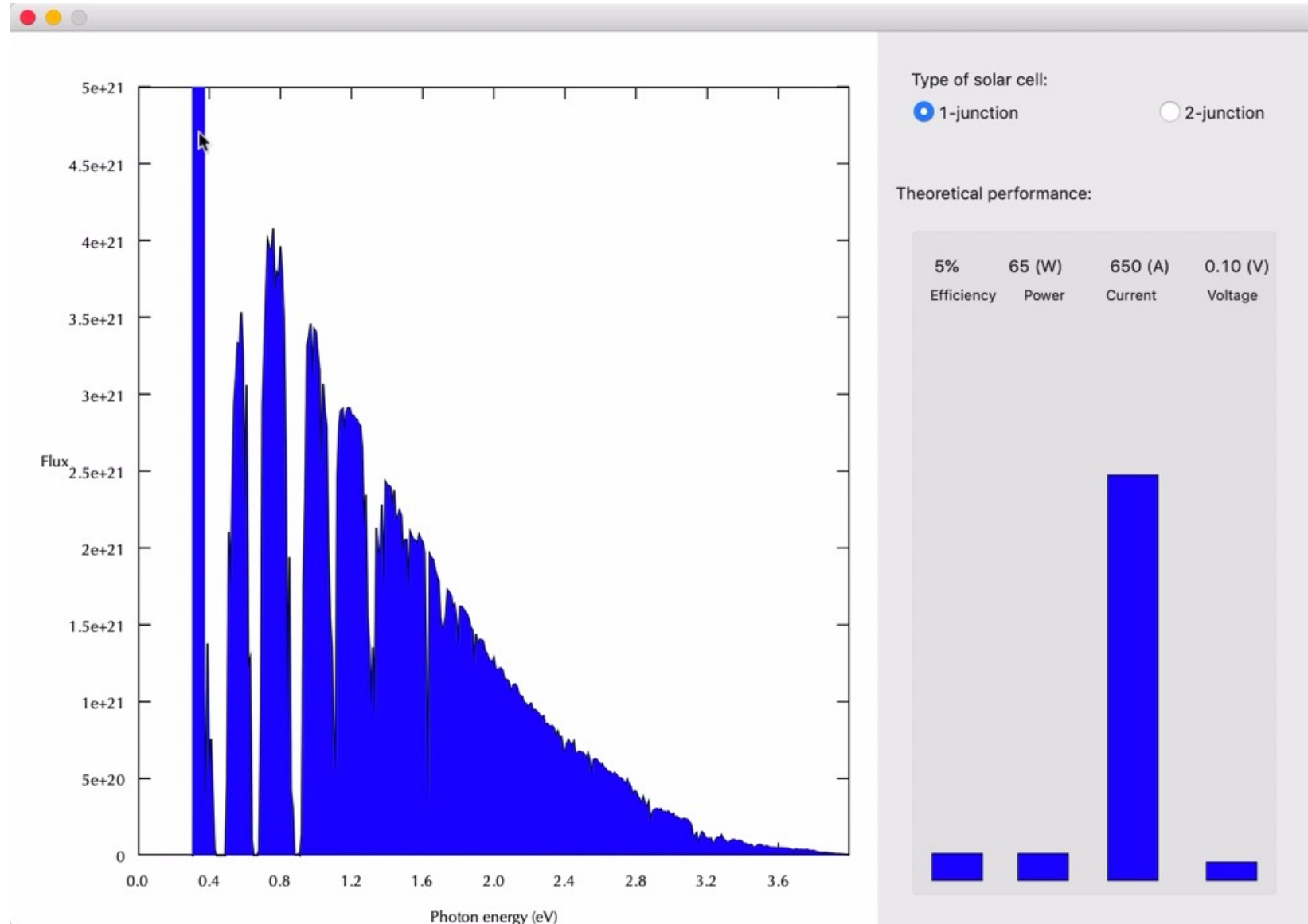


*Diffractive grating
on rear side.*

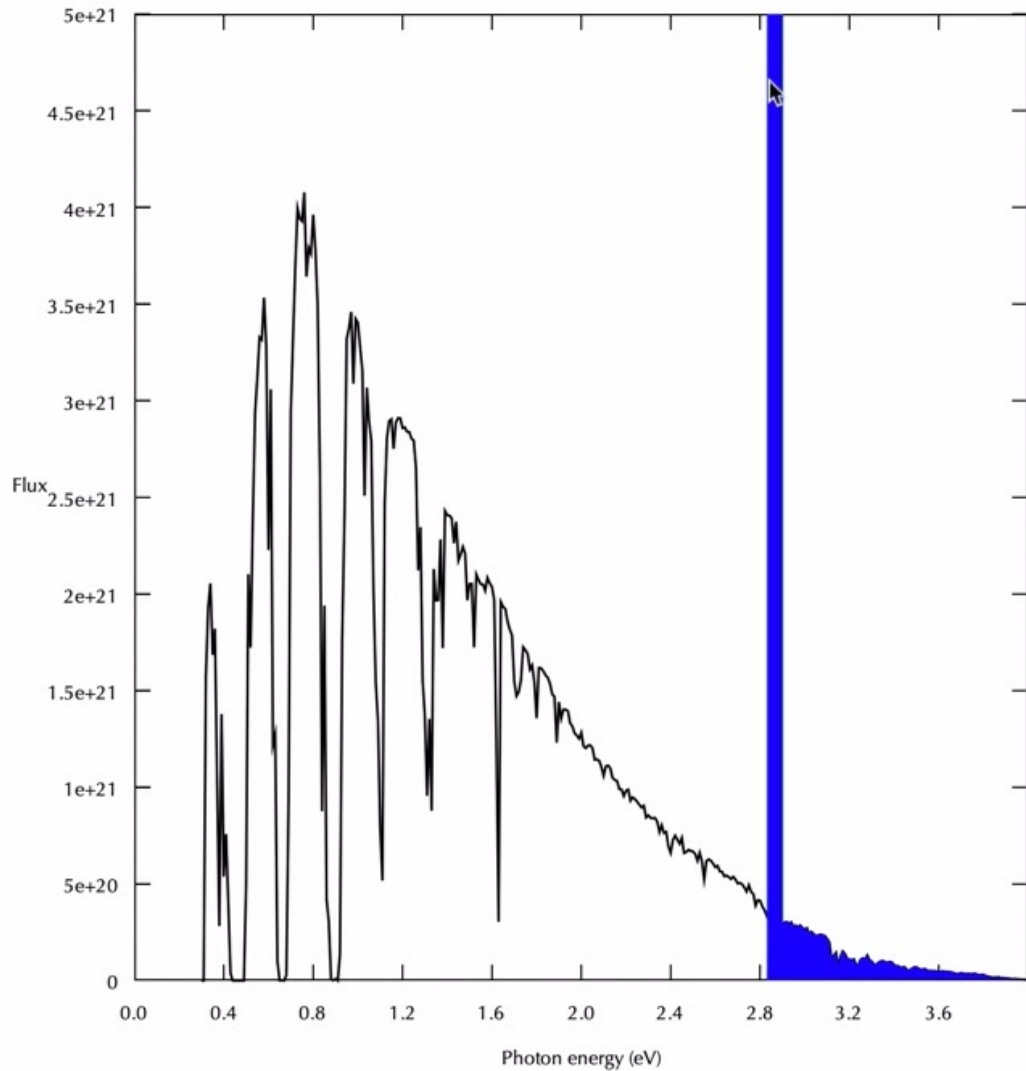
Current, Voltage, Power & Efficiency vs E_g



Current, Voltage, Power & Efficiency vs E_g



Current, Voltage, Power & Efficiency vs E_g



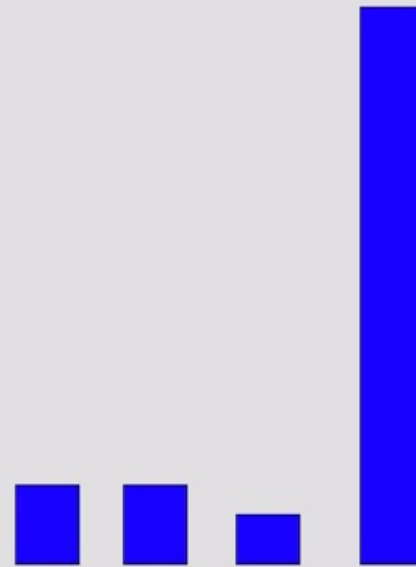
Type of solar cell:

1-junction

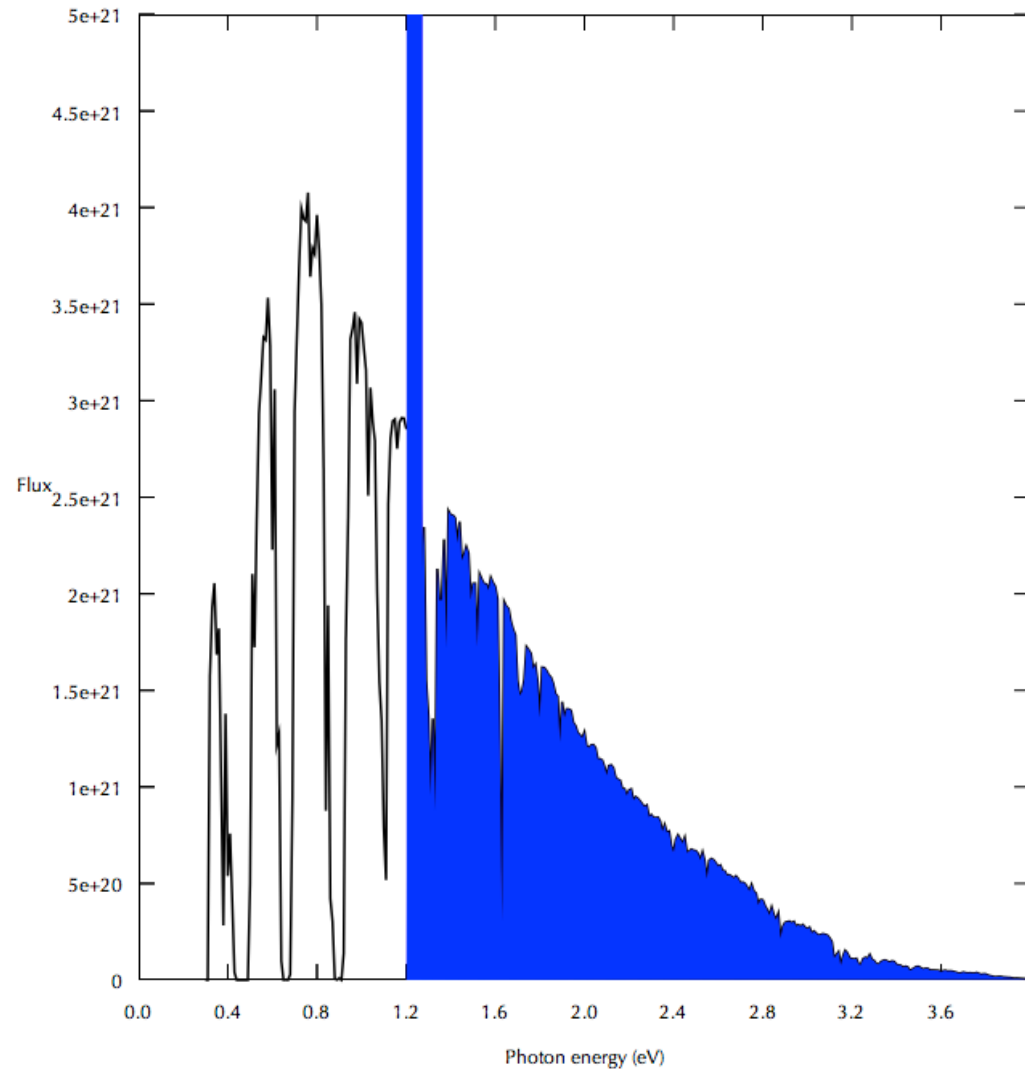
2-junction

Theoretical performance:

12%	151 (W)	64 (A)	2.37 (V)
Efficiency	Power	Current	Voltage



Current, Voltage, Power & Efficiency vs E_g



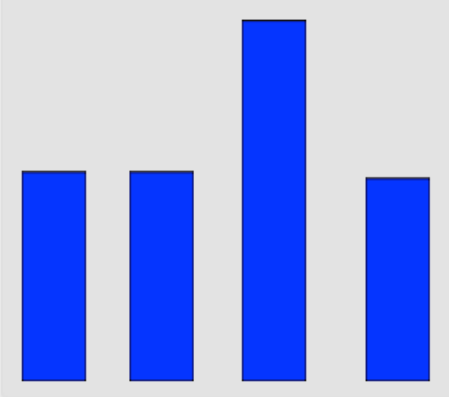
Type of solar cell:

1-junction

2-junction

Theoretical performance:

32%	397 (W)	460 (A)	0.86 (V)
Efficiency	Power	Current	Voltage



Electrical Models for PV Devices

Fundamental Shockley-Queisser (Detail Balance)

Band-gap : E_g
 Temperature : T

Depletion approximation

Analytical solutions to the drift-diffusion equations for homogeneous layers.
 Shockley Diode Eqn

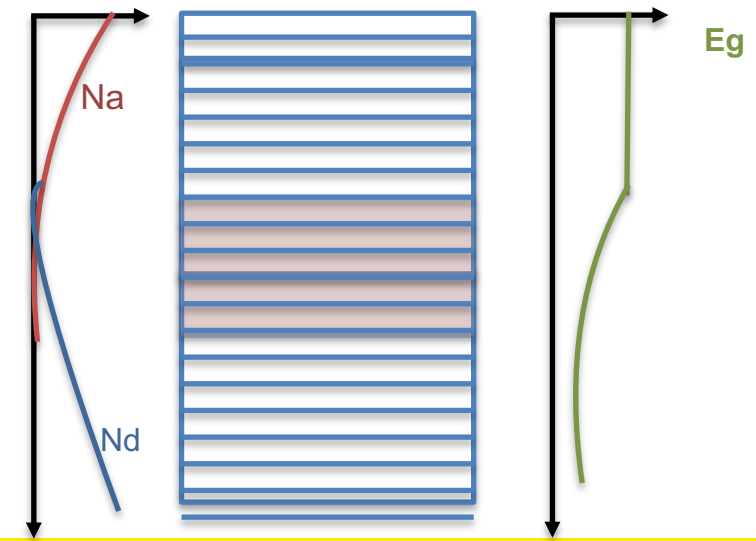
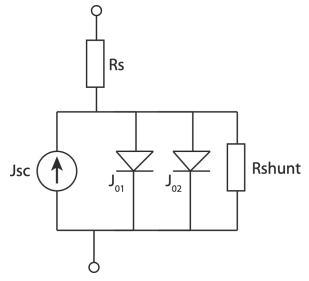
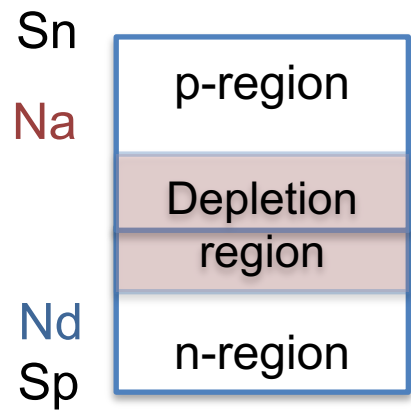
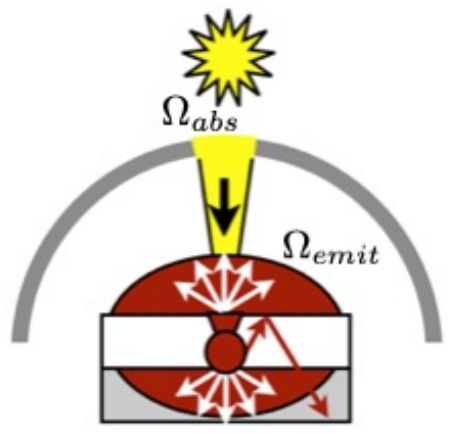
Band-gap : E_g Mobility μ
 Temperature : T Surface recombination S_n, S_p
 Diode dimensions: x Diffusion length L ,
 Doping level: N_a, N_d Absorption coefficient α
 Minority carrier lifetime τ

Drift-Diffusion

Numerical solution to the semiconductor drift-diffusion equations: 1D, 2D, 3D

Spatial variation of all parameters previously used in the depletion approximation.

- Variable doping profile within a region (silicon PV)
- Variable band-gap within a region (CIGS PV)
- Mobile ions under dark and illuminated conditions (Perovskite PV)



General Form of the Planck Equation

Stove



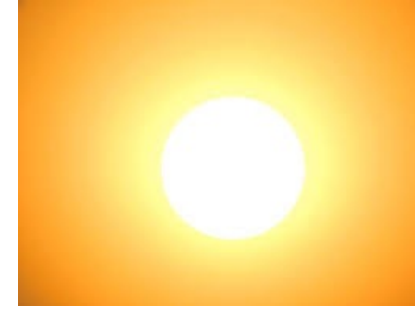
900K

Tungsten-Halogen light bulb



2800K

Sun

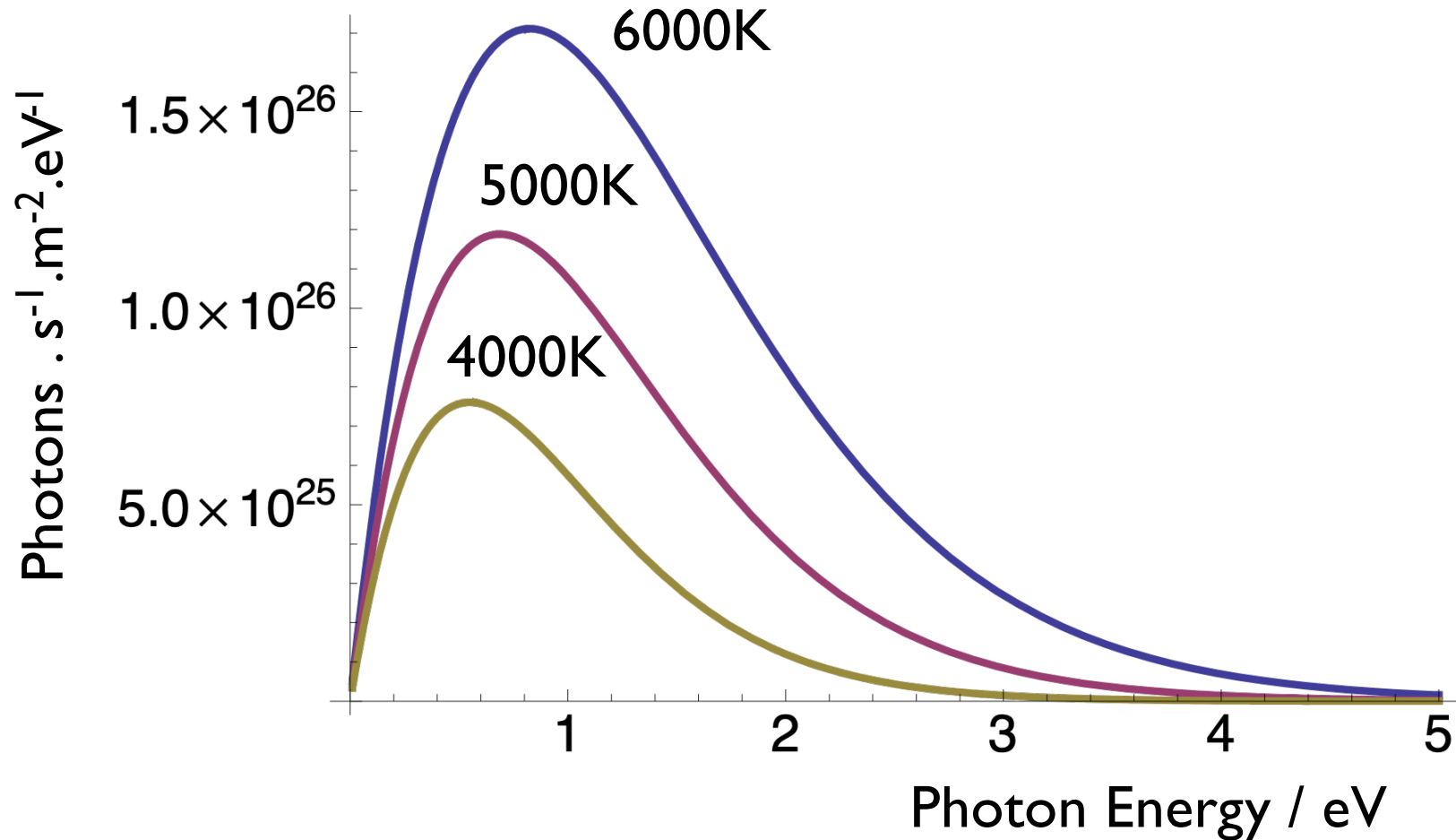


5800K

$$n(E) = \underbrace{\epsilon(E)}_{\substack{\text{Encapsulates the electronic} \\ \text{density of states.}}} \frac{\overbrace{2\pi E^2}^{\text{Photon modes}}}{\underbrace{c^2 h^3}_{\text{Occupation probability}} \underbrace{e^{\frac{E-\mu}{kT}} - 1}}_{\text{Occupation probability}}$$

Blackbody Emission

$$n(E) = \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}} - 1} \quad \begin{array}{l} \mu = 0 \\ \epsilon(E) = 1 \end{array}$$

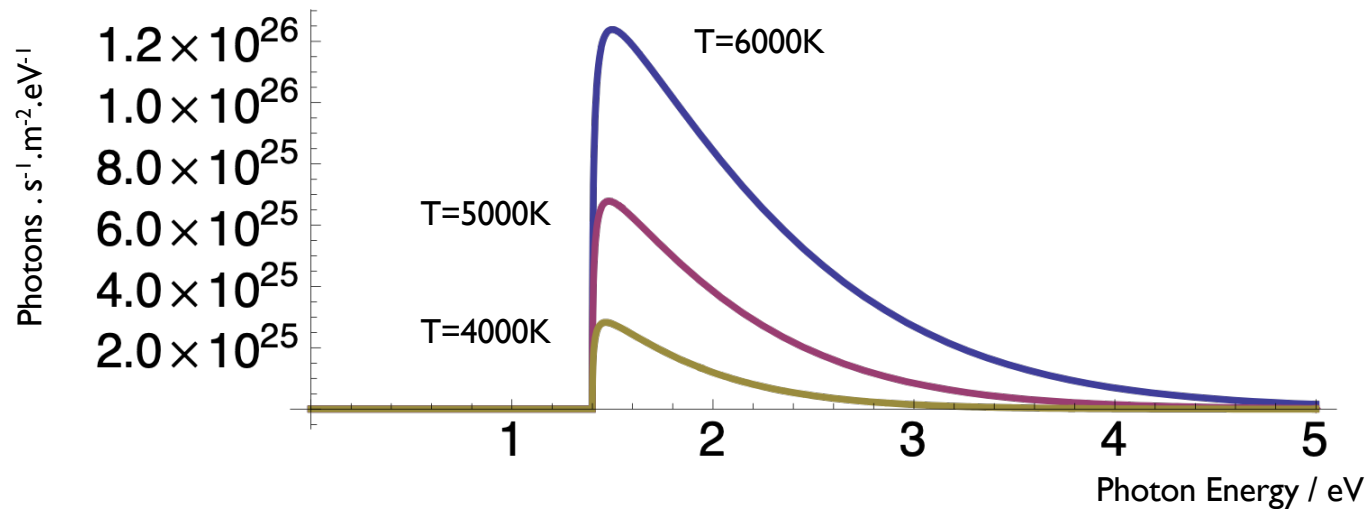
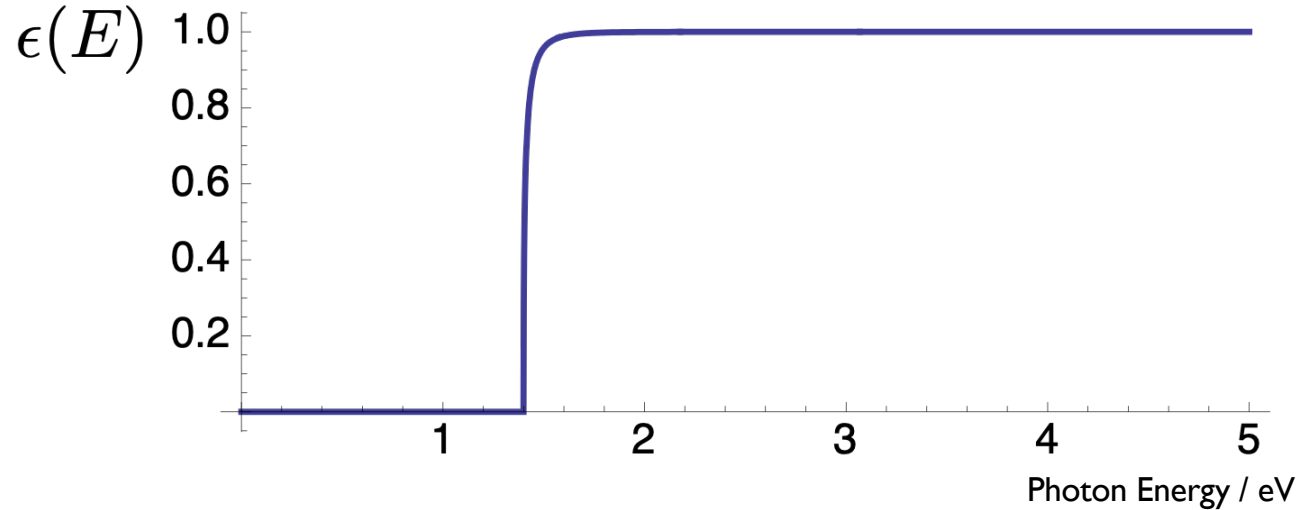


Semiconductors are “Grey” bodies

$$n(E) = \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}} - 1}$$

$$\mu = 0$$

$$T > 300K$$

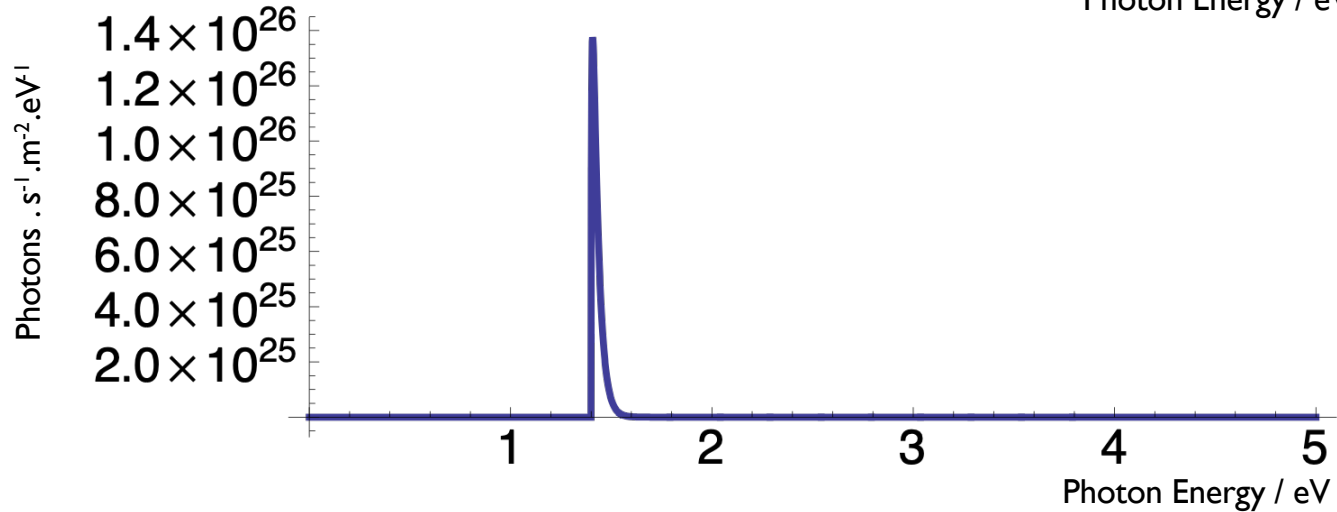
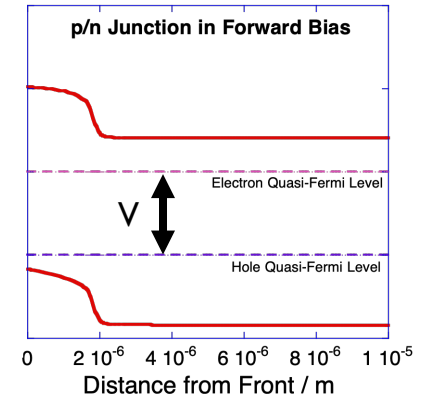
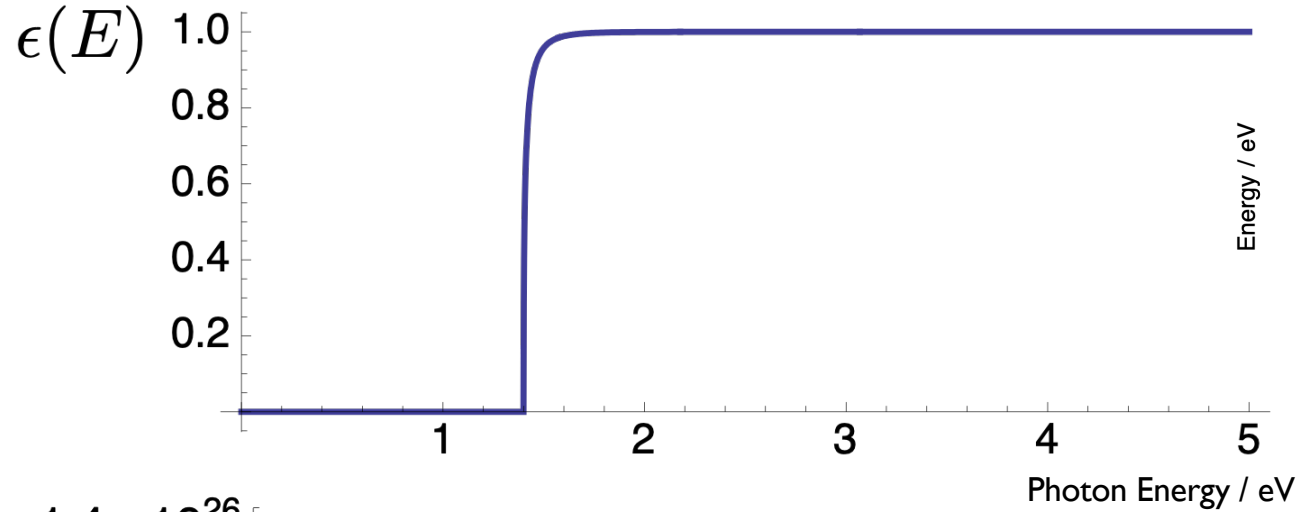


Electroluminescence

$$n(E) = \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}} - 1}$$

$$\mu = 1.35V$$

$$T = 300K$$



Verification of the Generalised Planck Expression

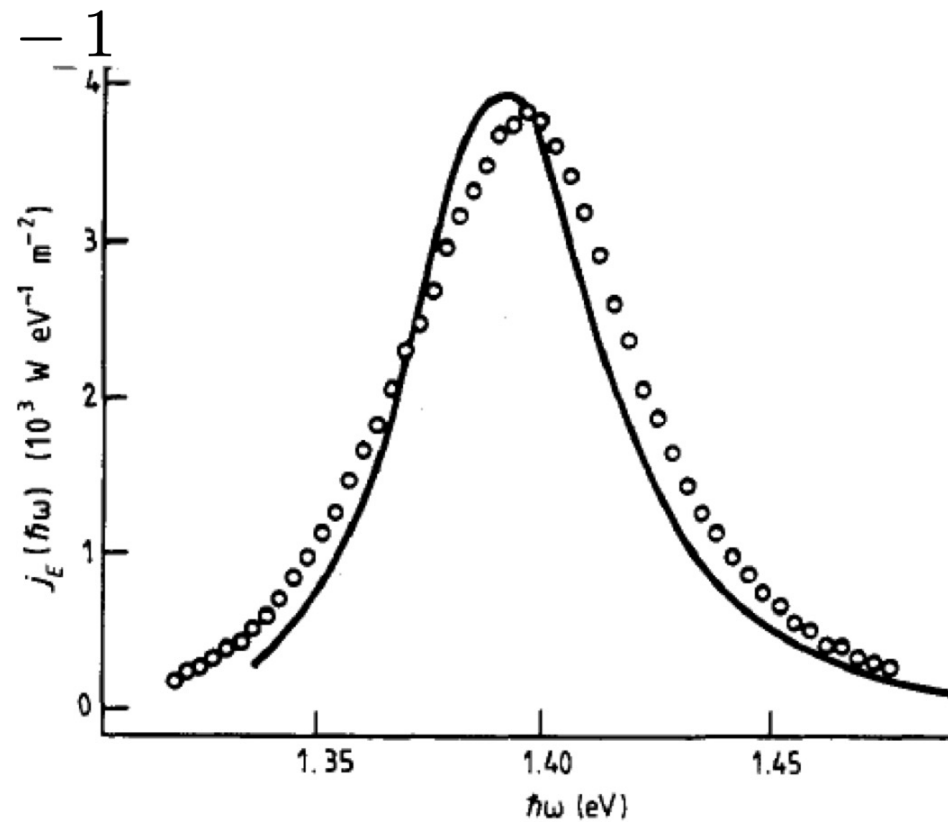
$$n(E) = \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}} - 1}$$

$$\mu = 1.206V$$

$$T = 296K$$



GaAs p/n diode

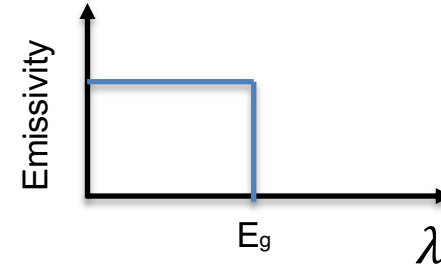


Radiative limit to J_0

$$\dot{N} = \int_{E_g}^{E_{top}} \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}} - 1} dE$$

- Assume $F(E)$ Boltzmann approximation
- Bands are infinite ($E_g \rightarrow \infty$)

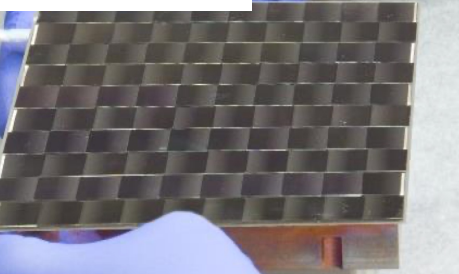
$$\begin{aligned} \dot{N} &= \int_{E_g}^{\infty} \epsilon(E) \frac{2\pi}{c^2 h^3} \frac{E^2}{e^{\frac{E-\mu}{kT}}} dE \\ &= \underbrace{(\epsilon kT (Eg^2 + 2EgkT + 2k^2T^2) e^{-\frac{Eg}{kT}})}_{\frac{J_0}{q}} e^{\frac{\mu}{kT}} \end{aligned}$$



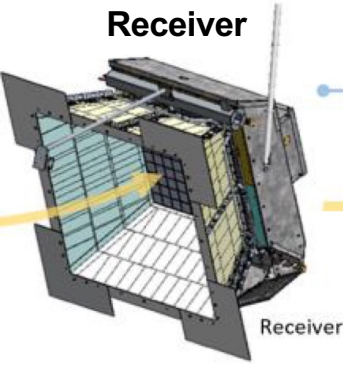
$$\mu = qV$$

$$J = J_0 e^{\frac{qV}{kT}}$$

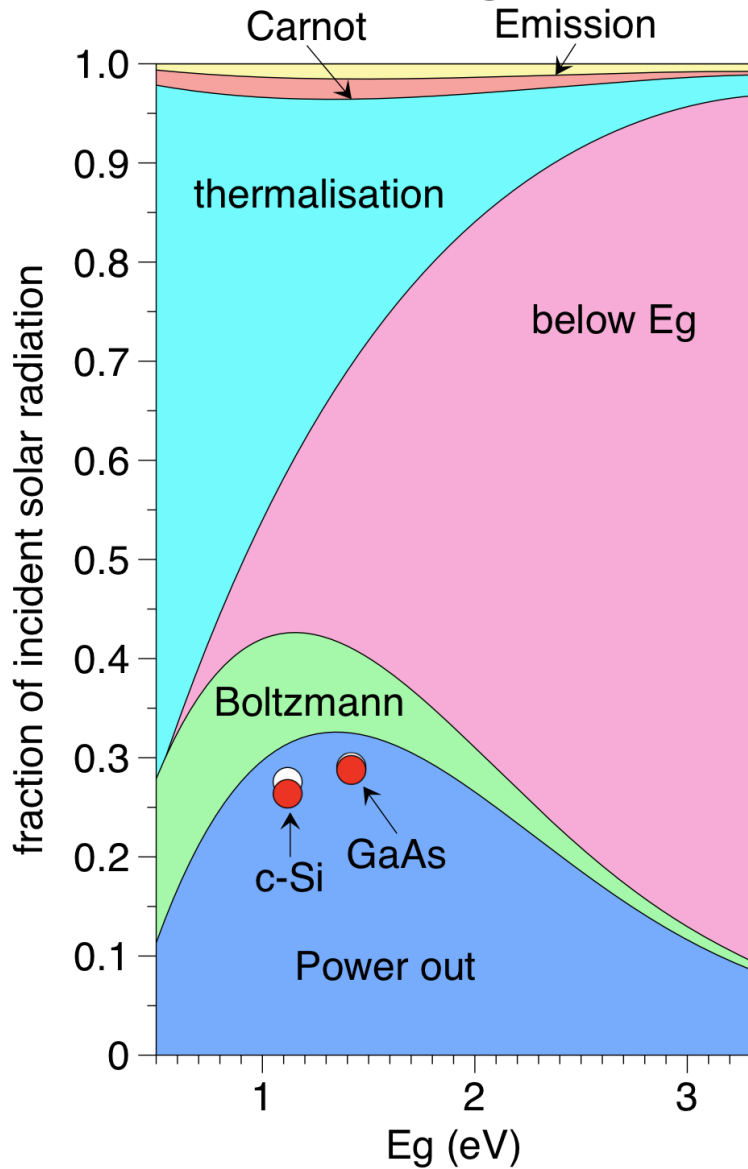
Concentrator PV Module



Receiver



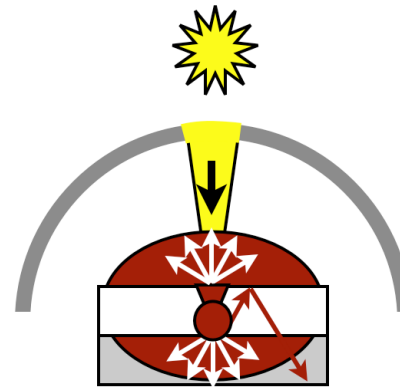
Understanding the effect of solar concentration



$$qV_{max} = E_g - E_g \frac{T_A}{T_s} - kT_A \ln \left(\frac{\Omega_{emit}}{\Omega_{abs}} \right)$$

Boltzmann loss

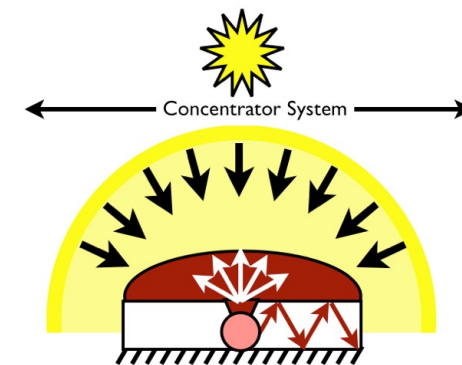
Conventional solar cell



$$\Omega_{emit} \gg \Omega_{abs}$$

Significant Boltzmann loss!

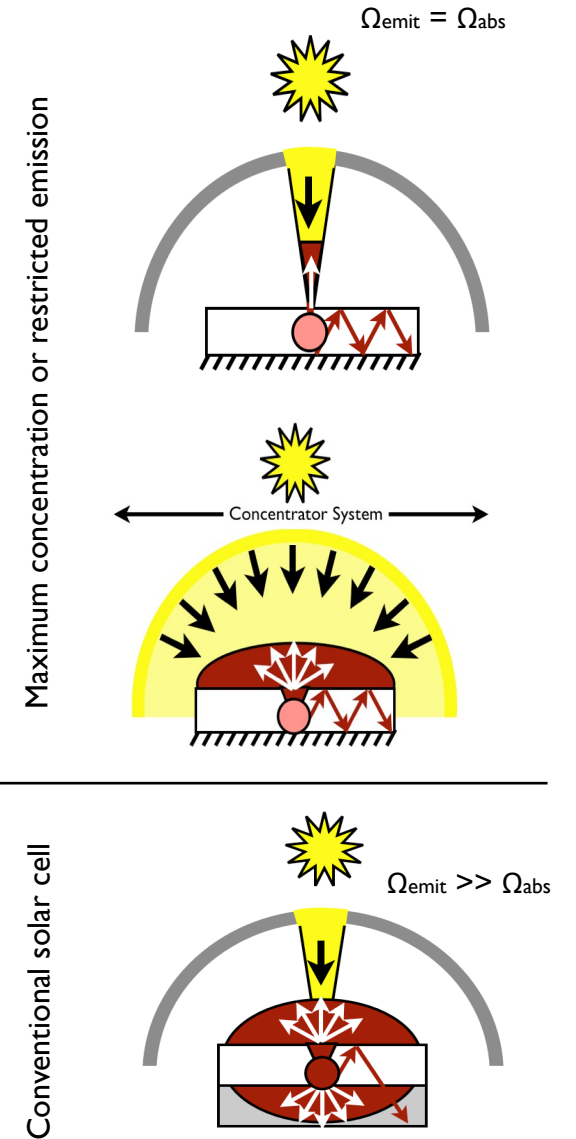
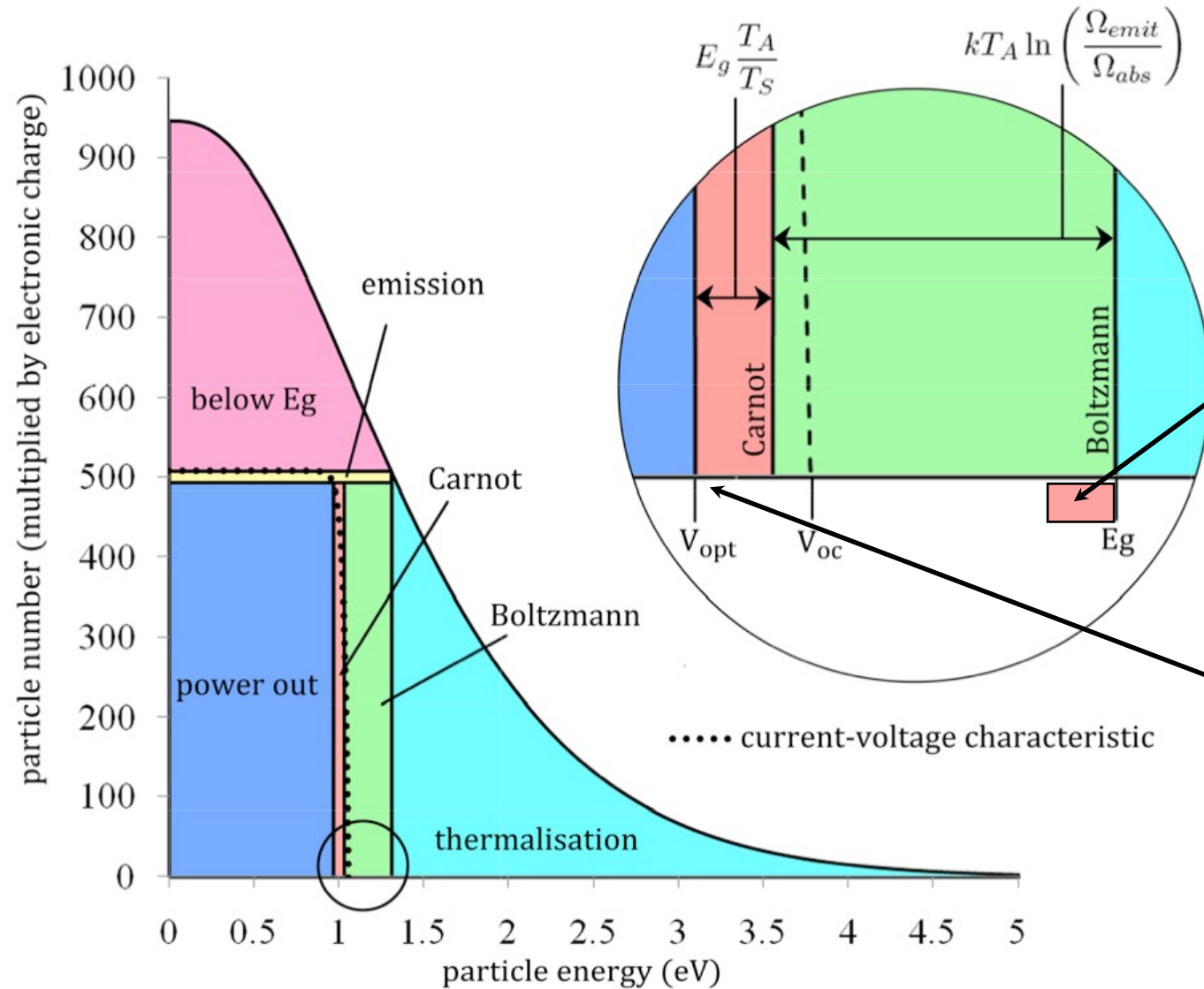
Maximum concentration



$$\Omega_{emit} = \Omega_{abs}$$

Zero Boltzmann loss.

Understanding the effect of solar concentration :



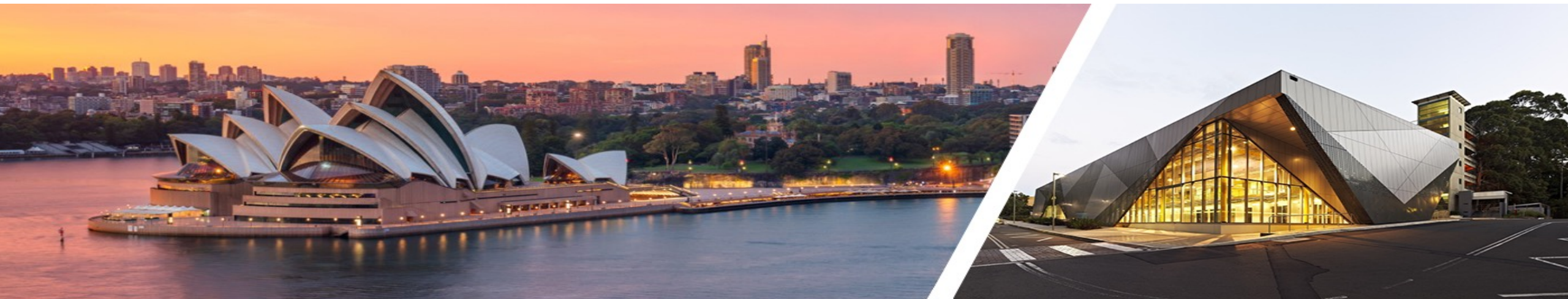
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School of Photovoltaic and Renewable Energy Engineering

Day 2 Solcore Workshop – Silicon Tandem Cell Computer Modelling

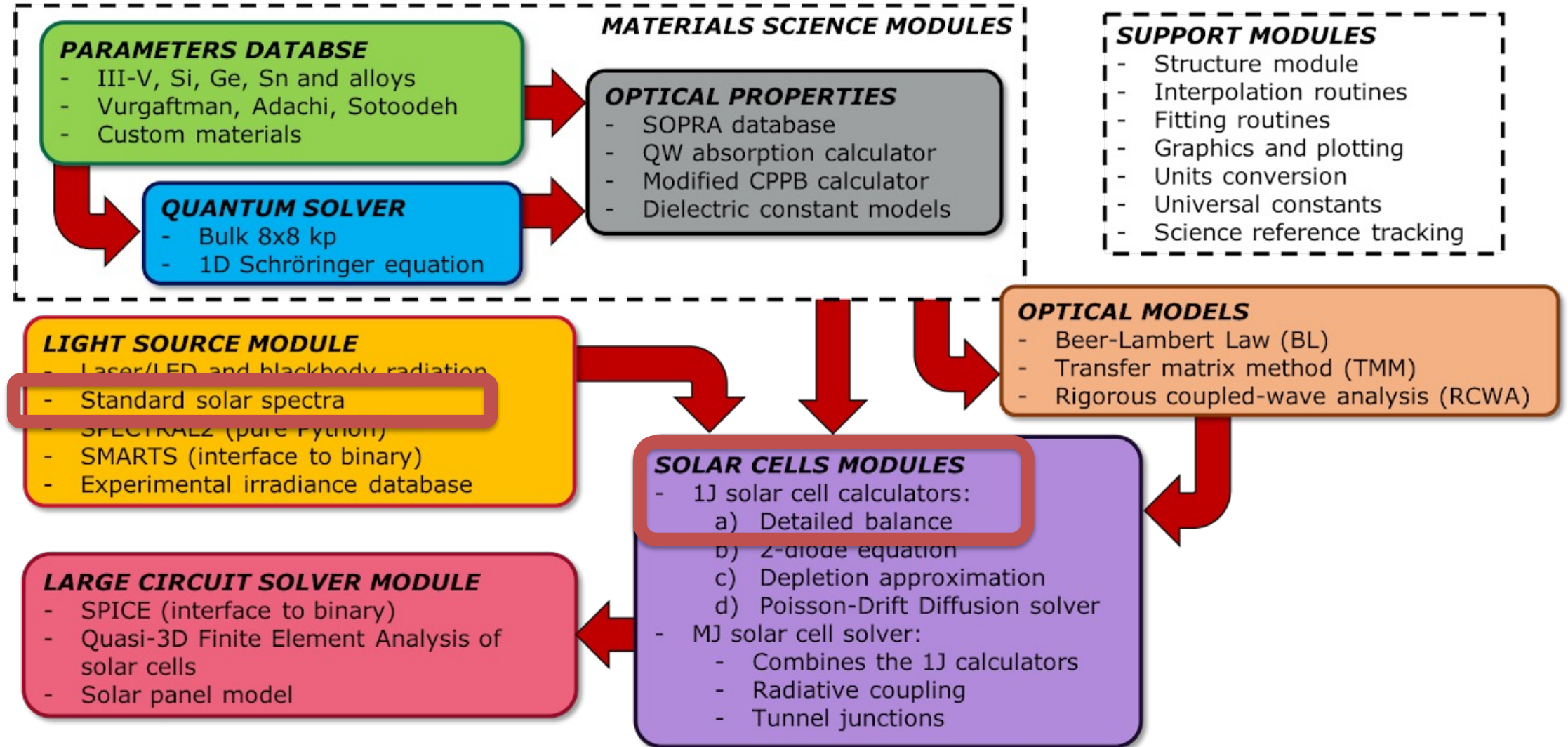
Sungkyunkwan University, 1 – 3 August 2023

*International Energy Joint R&D Project : Silicon / III-V Tandem solar cell to achieve over 40% efficiency.
Supported financially by KETEP (Korean Energy Technology Evaluation and Planning)*

Ned Ekins-Daukes & Phoebe Pearce



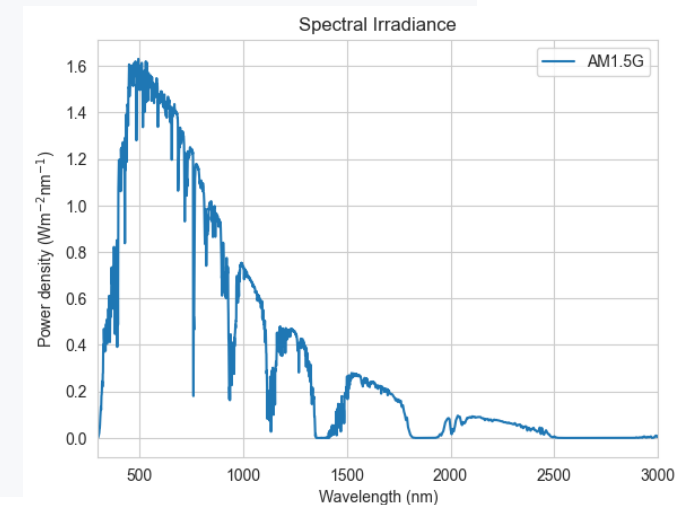
Summary of Day 1:



www.solcore.solar

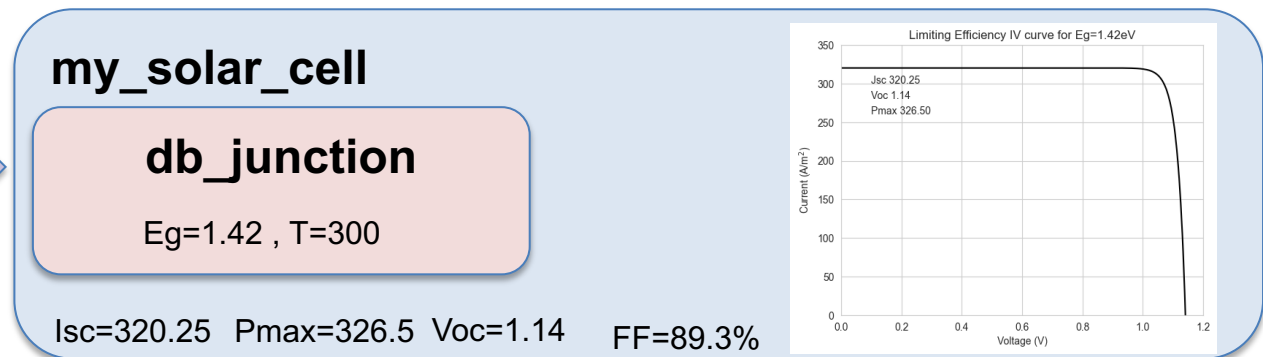
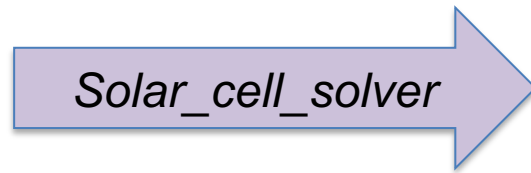
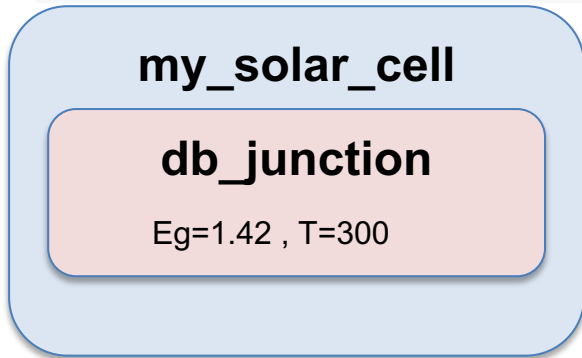
Importing the Solar Spectrum and Plotting

```
1 import numpy as np
2 import matplotlib.pyplot as plt
3 from solcore.light_source import LightSource
4 import seaborn as sns
5
6 # Setup the AM1.5G solar spectrum
7 wl = np.linspace(300, 4000, 4000) * 1e-9 #wl contains the x-ordinate in wavelength
8 am15g = LightSource(source_type='standard', x=wl*1e9, version='AM1.5g')
9
10 plt.figure(1)
11 plt.title('Spectral Irradiance')
12 plt.plot(*am15g.spectrum(wl*1e9), label='AM1.5G')
13 plt.xlim(300, 3000)
14 plt.xlabel('Wavelength (nm)')
15 plt.ylabel('Power density (Wm-2nm-1)')
16 plt.legend()
```



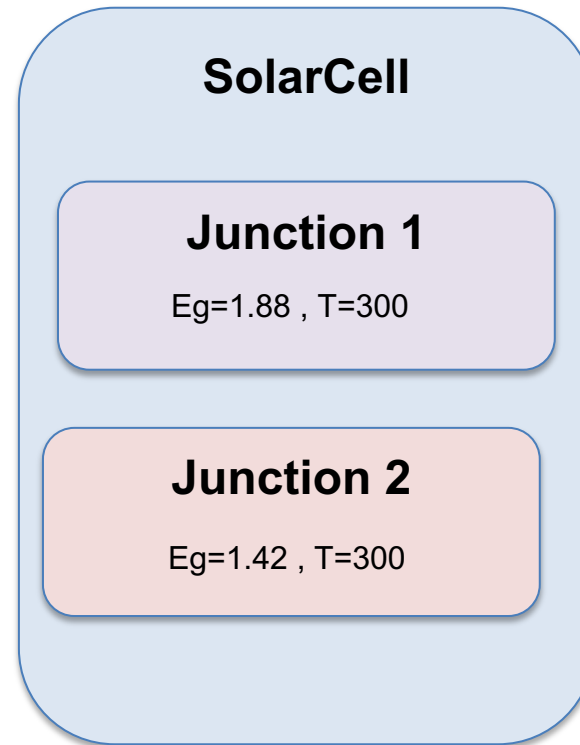
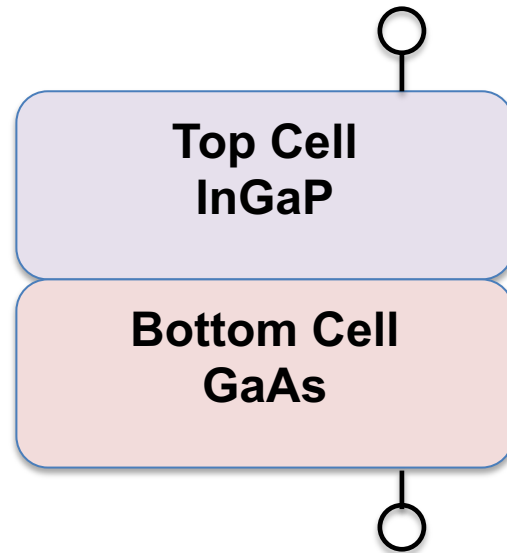
Calculating a Detailed-Balance IV curve in SolCore (Shockley-Queisser limit)

```
12 eg=1.42
13 V = np.linspace(0, 1.3, 500)
14 db_junction = Junction(kind='DB', T=300, Eg=eg, A=1, R_shunt=np.inf, n=1)
15 my_solar_cell = SolarCell([db_junction], T=300, R_series=0)
16
17 solar_cell_solver(my_solar_cell, 'iv',
18                 user_options={'T_ambient': 300, 'db_mode': 'top_hat', 'voltages': V,
19                               'light_iv': True,
20                               'internal_voltages': np.linspace(0, 1.3, 400),
21                               'wavelength': wl,
22                               'mpp': True, 'light_source': am15g})
```

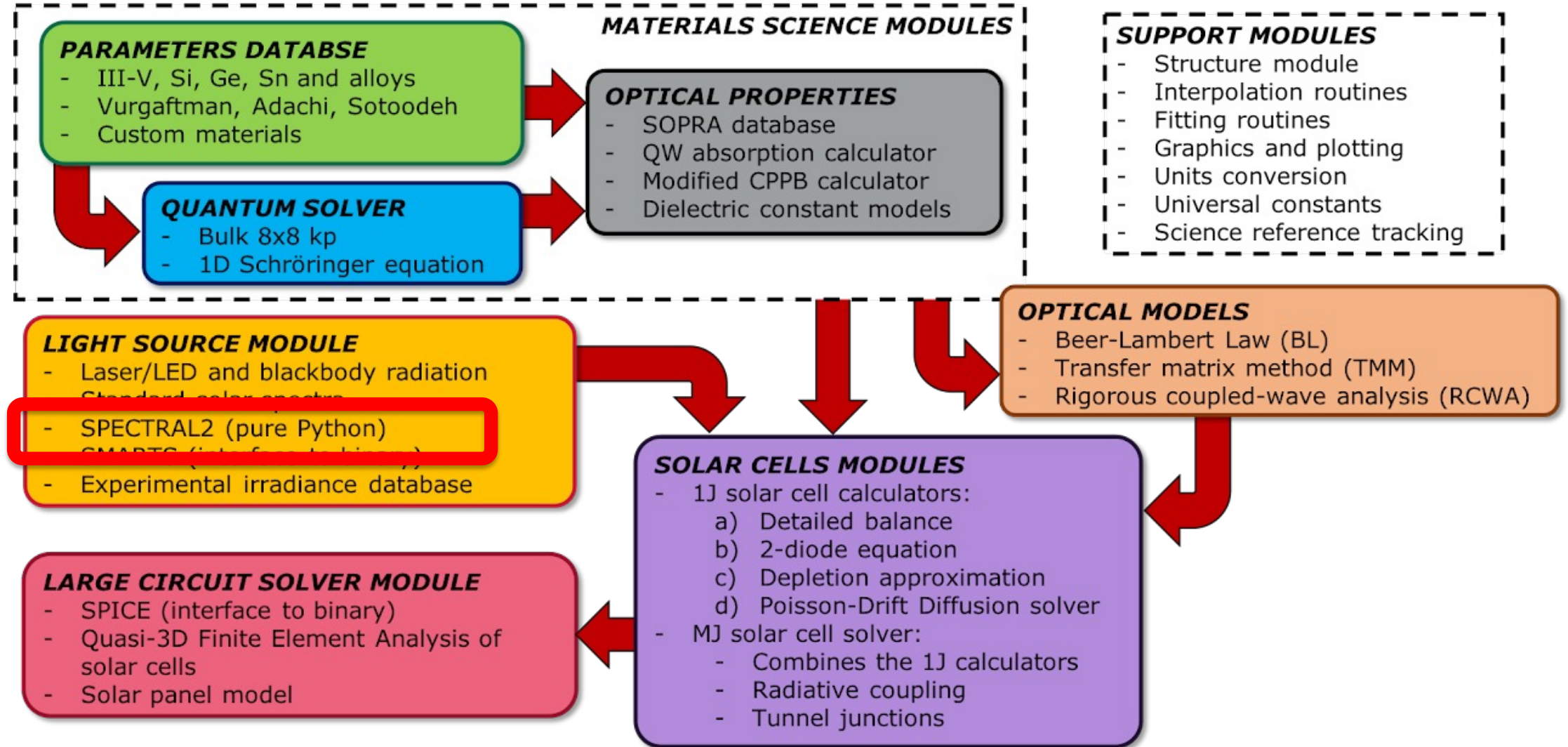


```
print (my_solar_cell.iv.Isc)
```

Detail Balance Double Junction Tandem Solar Cell

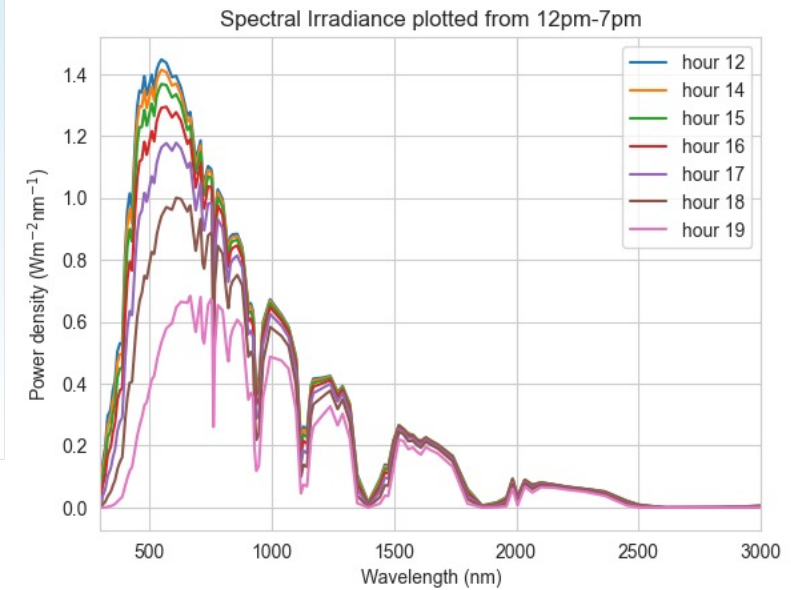
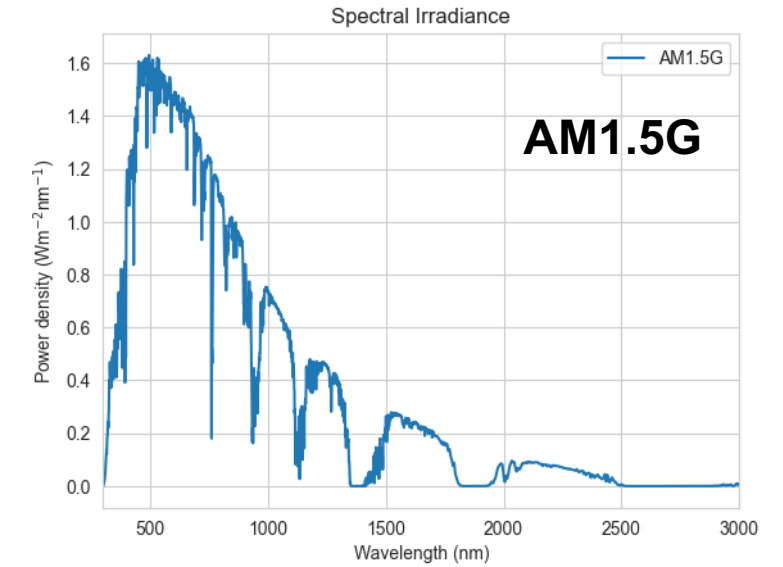
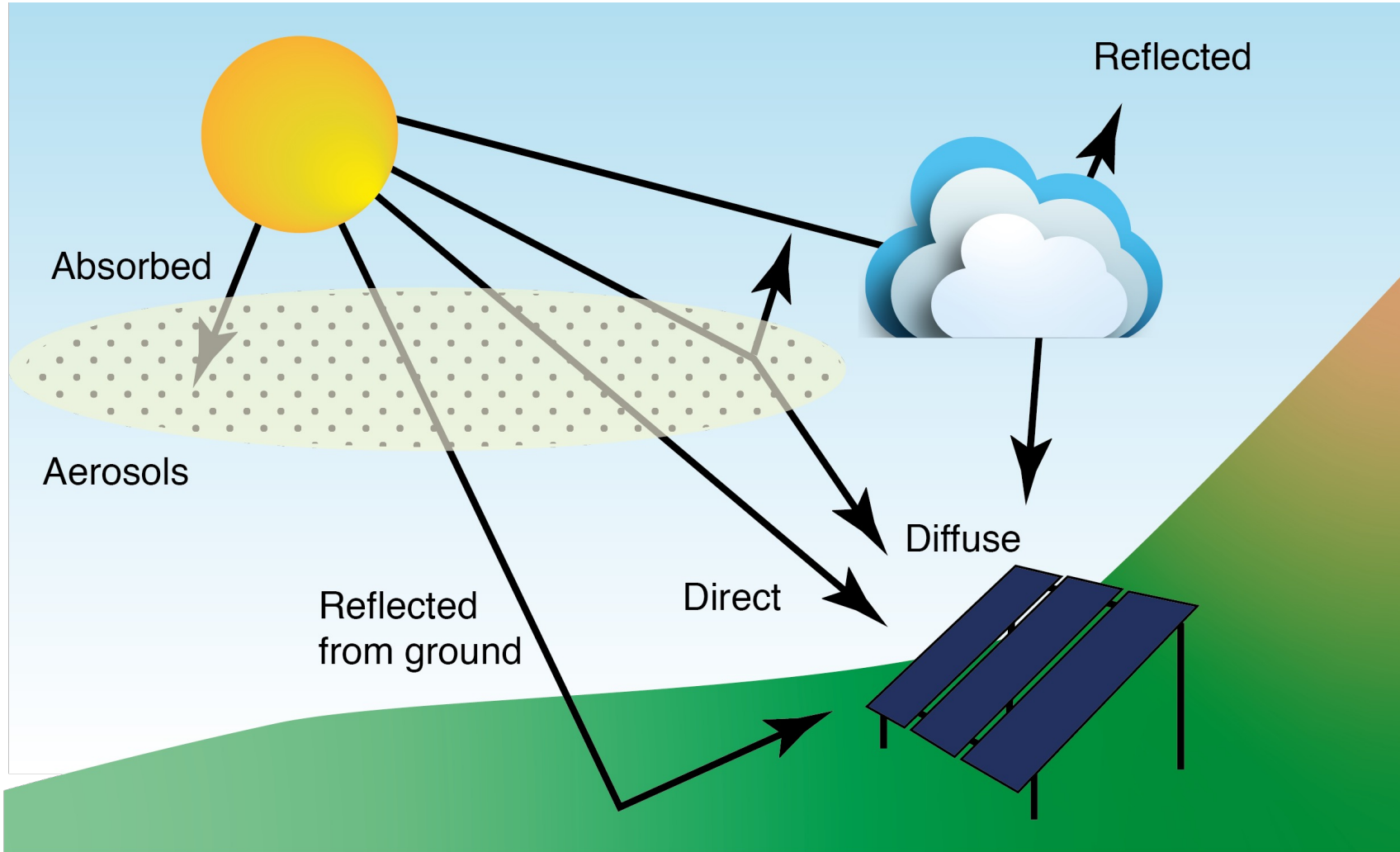


Summary of Day 1:



www.solcore.solar

Spectral Irradiance changes throughout the day:



Spectral Irradiance Models

SPCTRL2

SMARTS2

SBDart

MODTRAN

FASCODE

Clear Sky

AM1.5G standard

Clear Sky + Cloudy Conditions

Complexity / computational time



Empirical closed form transmission.

Parameterisation based on MODTRAN output.

band-model of HITRAN Database

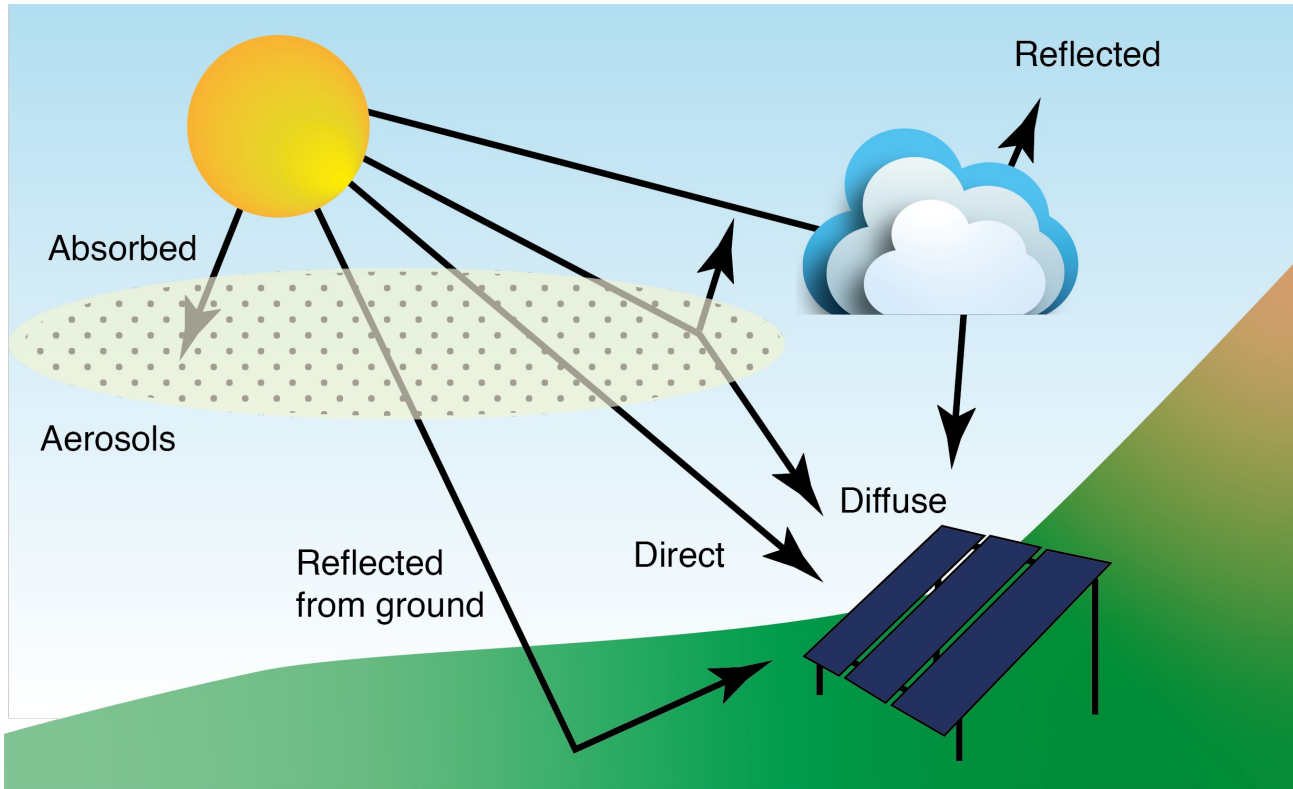
HITRAN Database

Domain of solar system engineering

Domain of atmospheric physics

Implemented in SolCore

Spectral Irradiance changes throughout the day:



$$AOD = \beta \lambda^{-\alpha}$$

SPCTRL2

SMARTS2

Clear Sky

AM1.5G standard

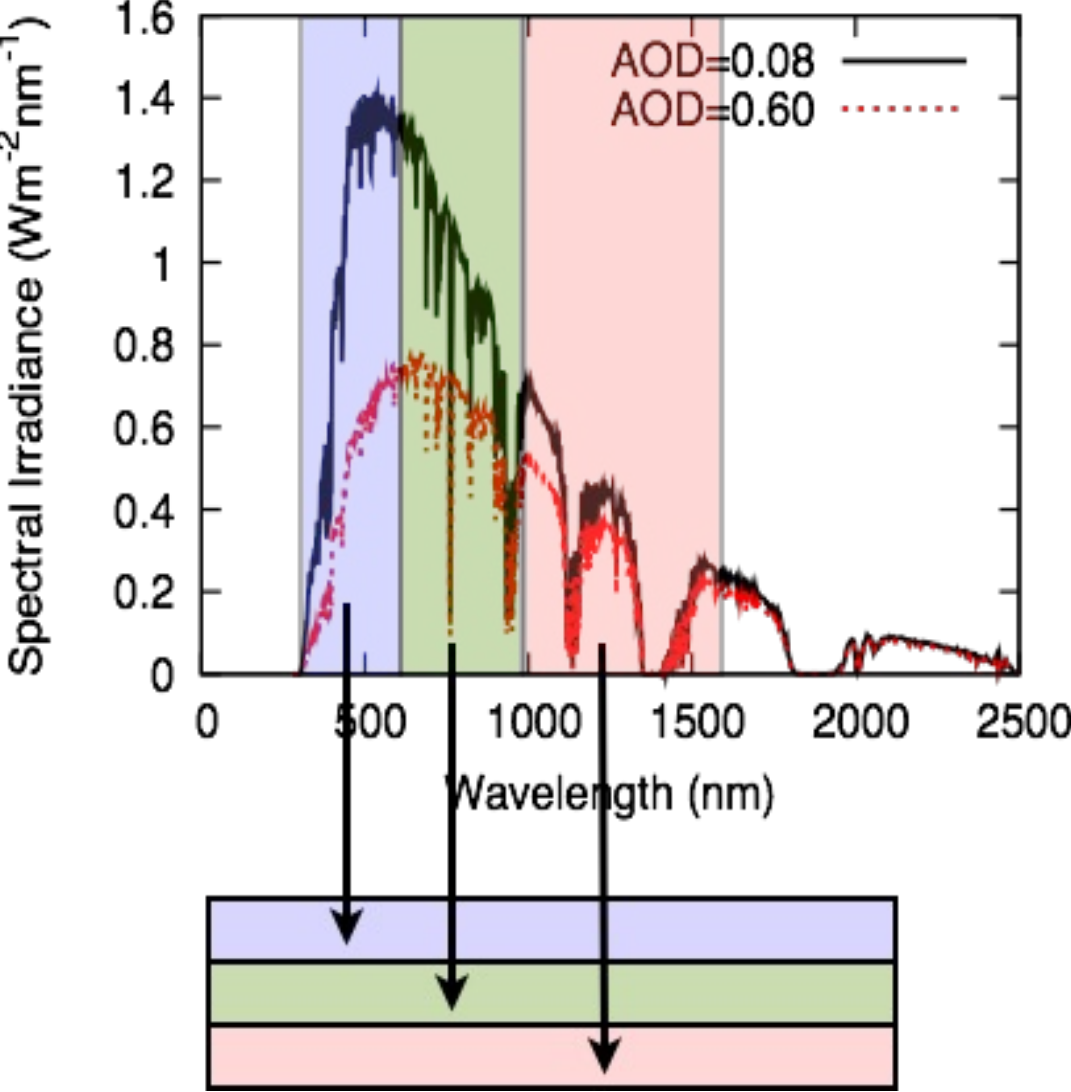
- Air Mass
 - Latitude, Longitude, Time of day
- Aerosol type :
 - Shettle & Fenn models:
 - Rural, Urban, Maritime, Tropospheric
- Aerosol concentration
 - Aerosol optical depth (AOD)
 - Atmospheric turbidity (β)
 - Ångström coefficient (α)
- Precipitable Water column thickness
- Meteorological conditions:
 - Pressure
 - Humidity
 - Ozone

Effect of Aerosol Optical Density on Solar Spectral Irradiance

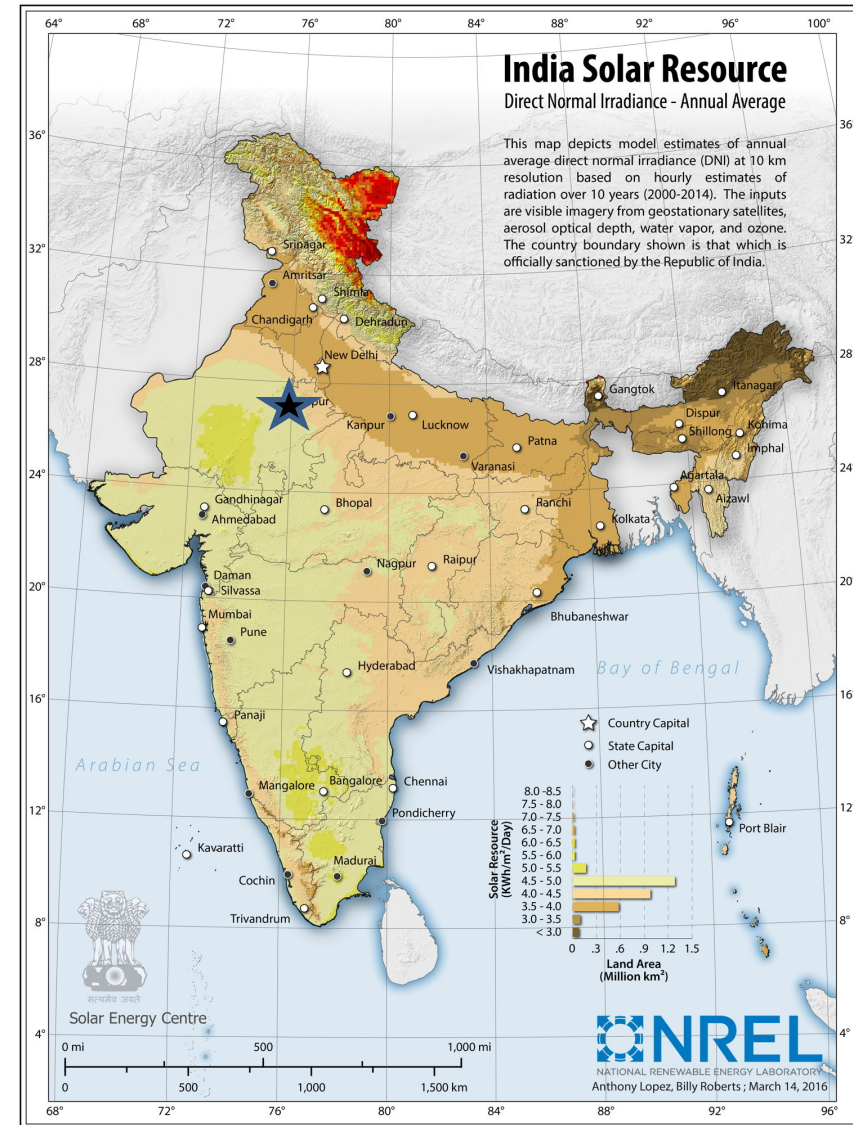
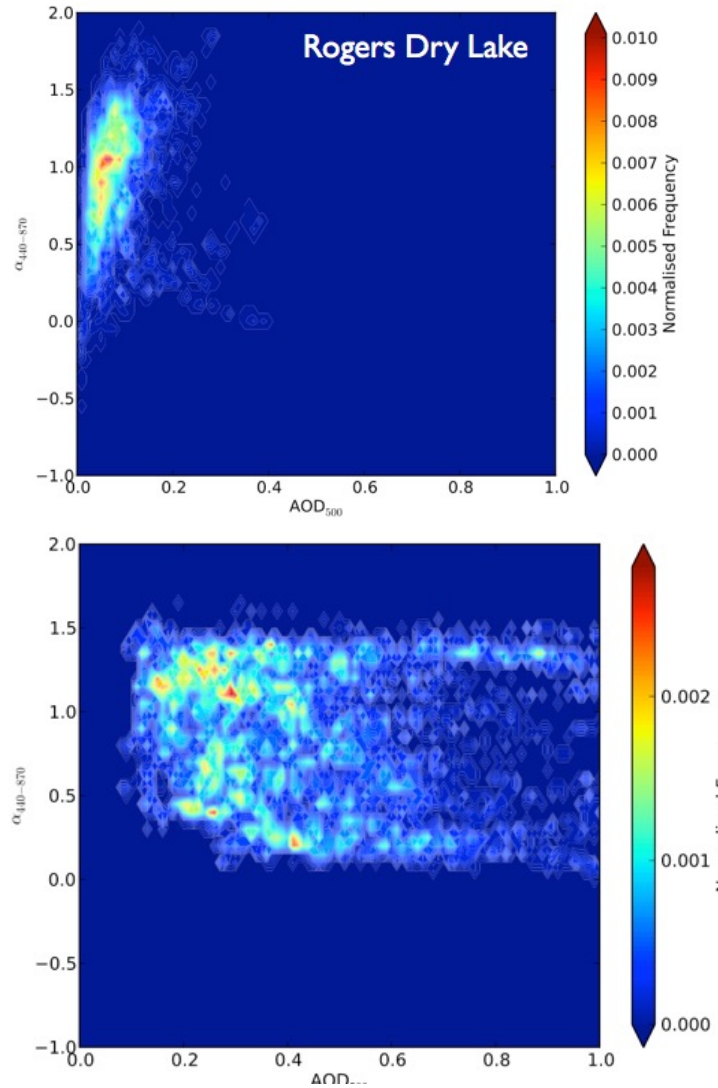
Low AOD



High AOD



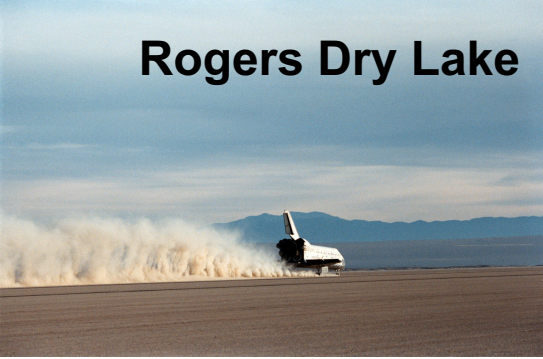
Complex atmospheres in India



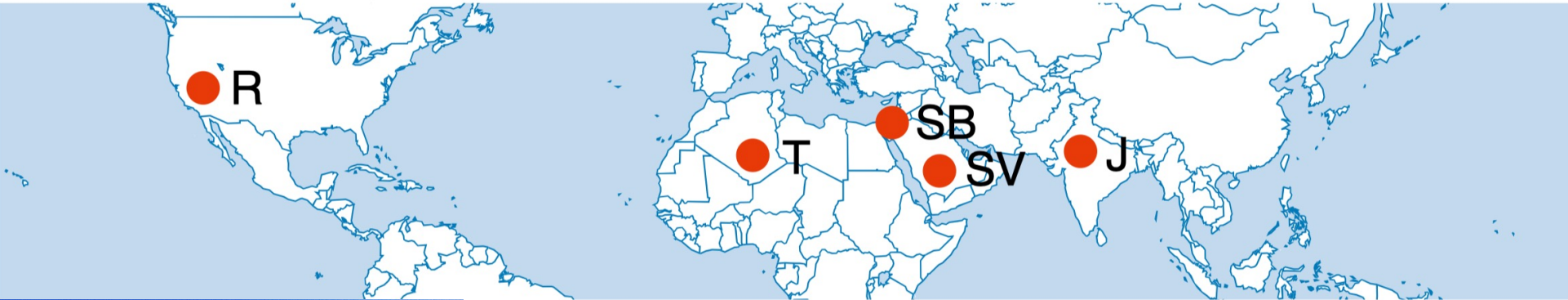
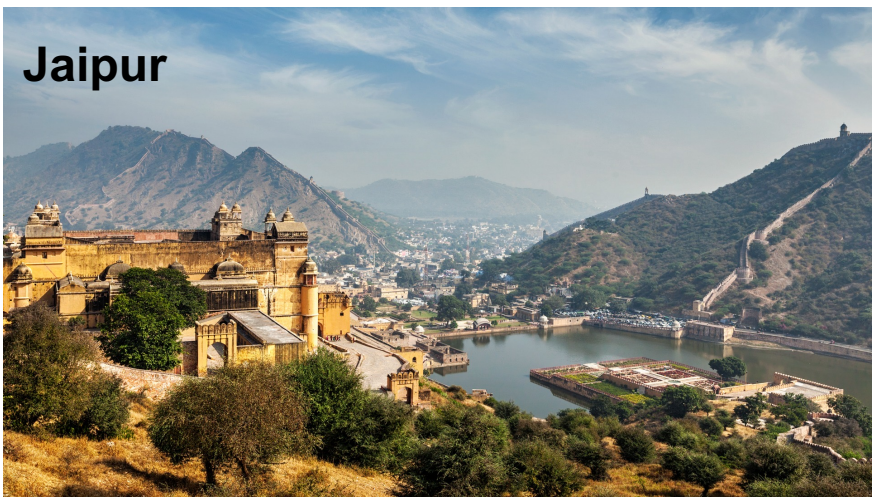
http://www.nrel.gov/international/ra_india.html

Atmospheric variation worldwide

Rogers Dry Lake



Jaipur



Tamanrasset



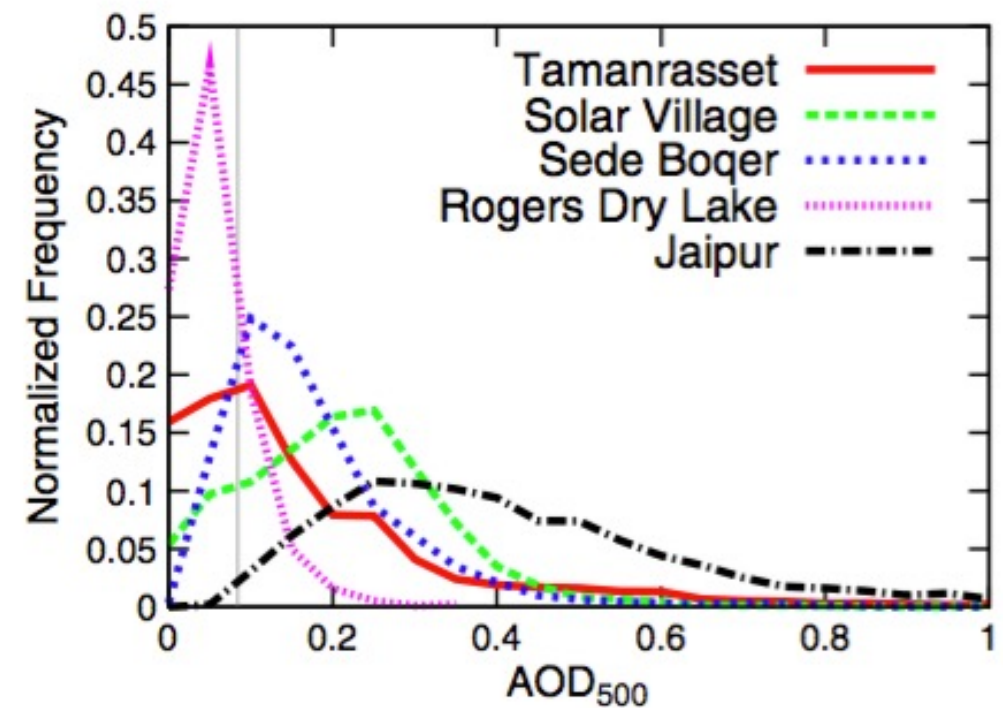
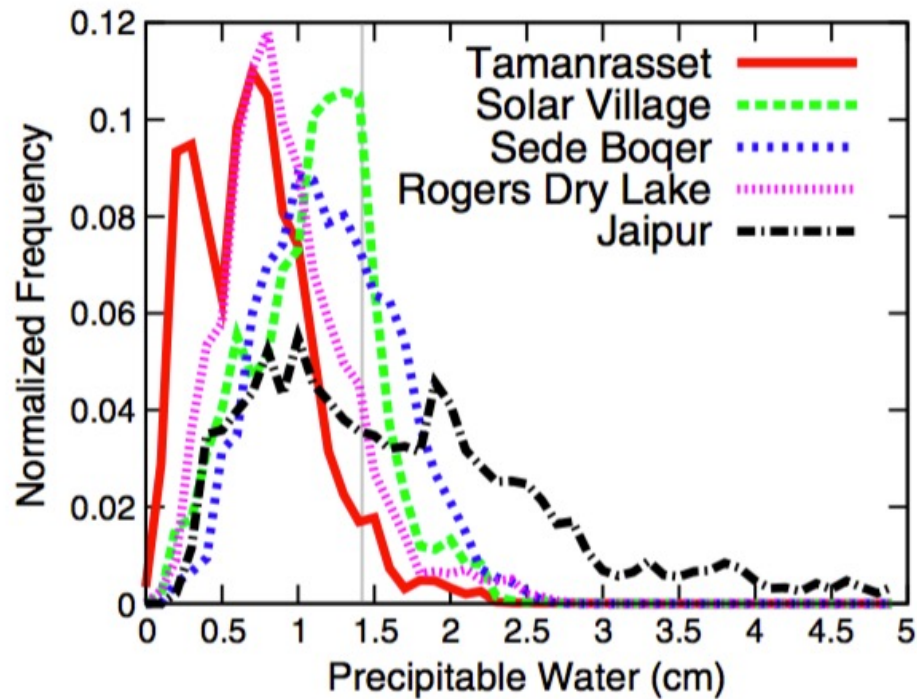
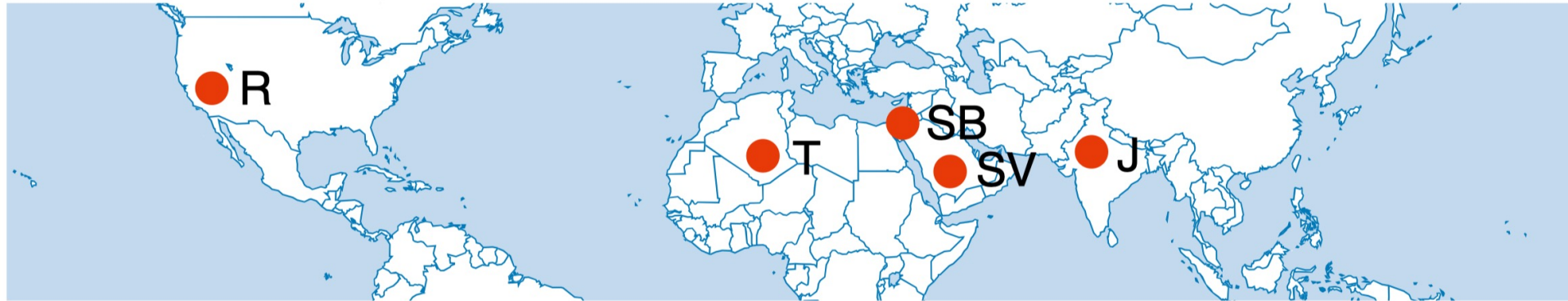
Sede Boqer



Solar Village



Atmospheric variation worldwide



Semiconductor Drift-Diffusion Equations

For electrons:

$$\nabla \left[\underbrace{-D_n \nabla n}_{\text{Diffusion}} + n \mu_n \left(\underbrace{\nabla \Phi}_{\text{Electric field}} + \underbrace{\frac{\nabla \chi}{q}}_{\text{Electron affinity}} + \underbrace{\frac{kT}{q} \nabla \ln N_c}_{\text{Density of states}} \right) \right] = \underbrace{g(x, y, z, \lambda)}_{\text{Generation rate}} - \underbrace{U}_{\text{Recombination rate}}$$

$$U = \underbrace{U_{SRH}}_{\text{Impurity recombination}} + \underbrace{U_{rad}}_{\text{Radiative recombination}} + \underbrace{U_{aug}}_{\text{Auger recombination}}$$

For holes:

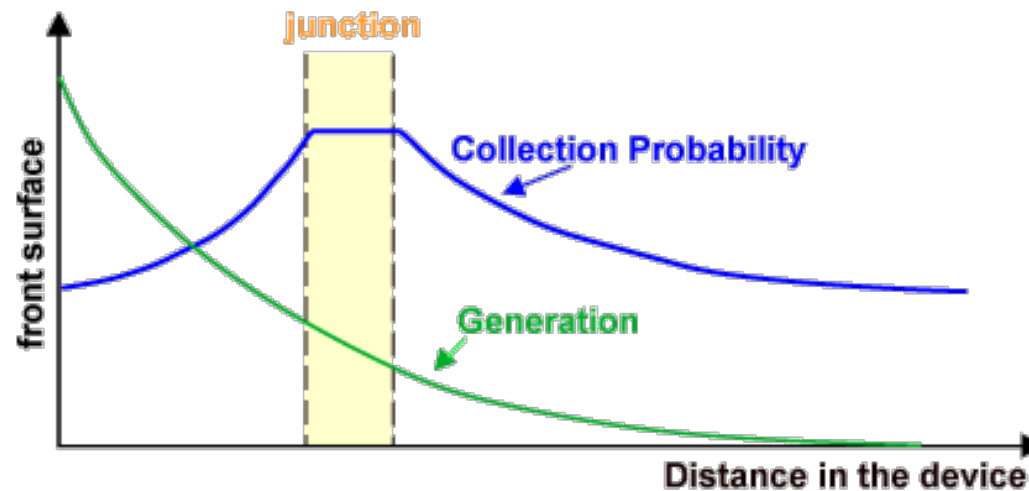
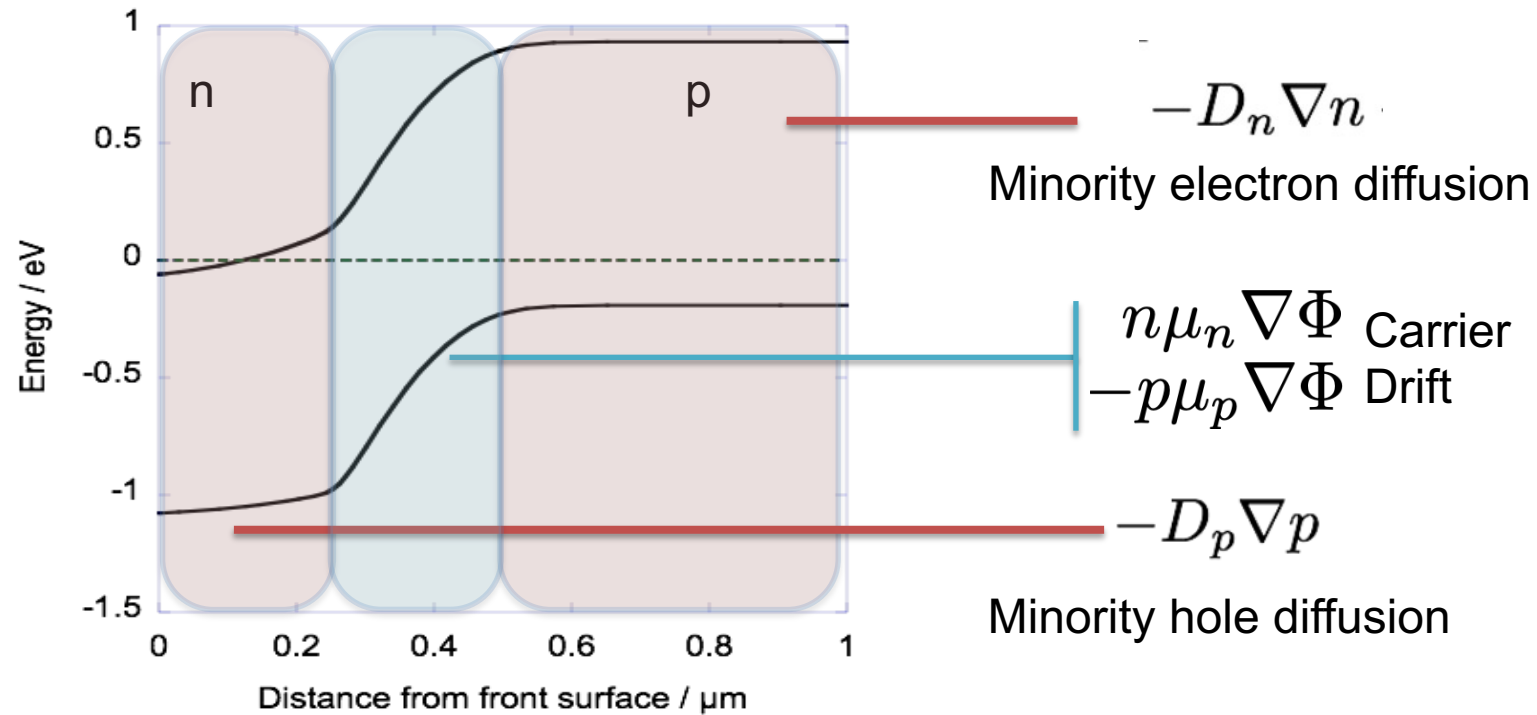
$$\nabla \left[-D_p \nabla p + p \mu_p \left(\nabla \Phi + \frac{\nabla \chi}{q} + \frac{kT}{q} \nabla \ln N_v \right) \right] = g(x, y, z, \lambda) - U$$

Poisson equation:
$$\nabla^2 \Phi = \frac{q}{\epsilon_0 \epsilon_r} (n - p - (N_D - N_A))$$

Numerical solution to D-D eqns for QE: Xiaofeng Li, *Prog. Photovolt: Res. Appl.*, vol. 21, no. 1, pp. 109–120, 2013.

Analytical solution to D-D eqns for QE : Jenny Nelson, *The Physics of Solar Cells*, Imperial College Press, 2003

Carrier collection probability at short-circuit (V=0)



Beer Lambert Law:

$$I = I_0 e^{-\alpha z}$$

Recombination terms:

$$U = \underbrace{U_{SRH}}_{\text{Impurity recombination}} + \underbrace{U_{rad}}_{\text{Radiative recombination}} + \underbrace{U_{aug}}_{\text{Auger recombination}}$$

Shockley-Read-Hall (SRH) recombination

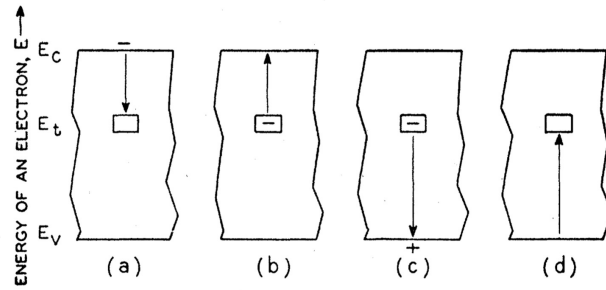
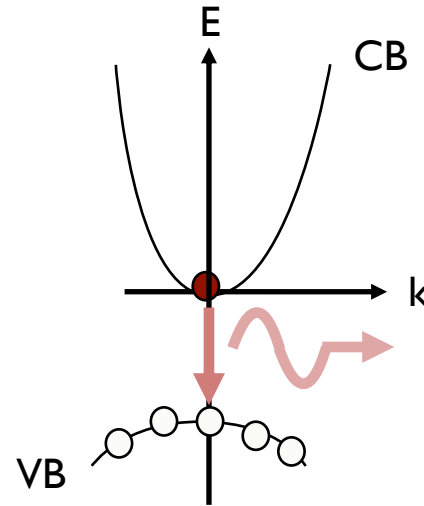


FIG. 1. The basic processes involved in recombination by trapping: (a) electron capture, (b) electron emission, (c) hole capture, (d) hole emission.

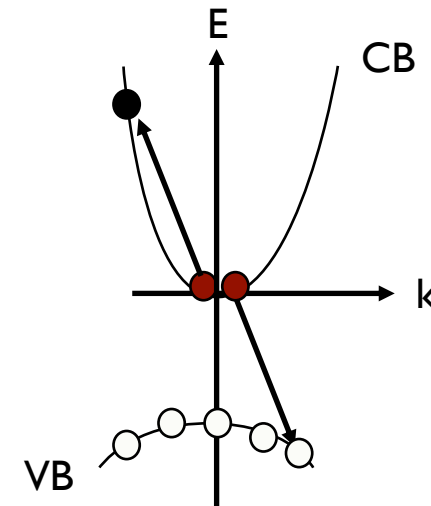
$$U_{SRH} = \frac{np - n_i^2}{\tau_n(p + p_t) + \tau_p(n + n_t)}$$

Radiative recombination



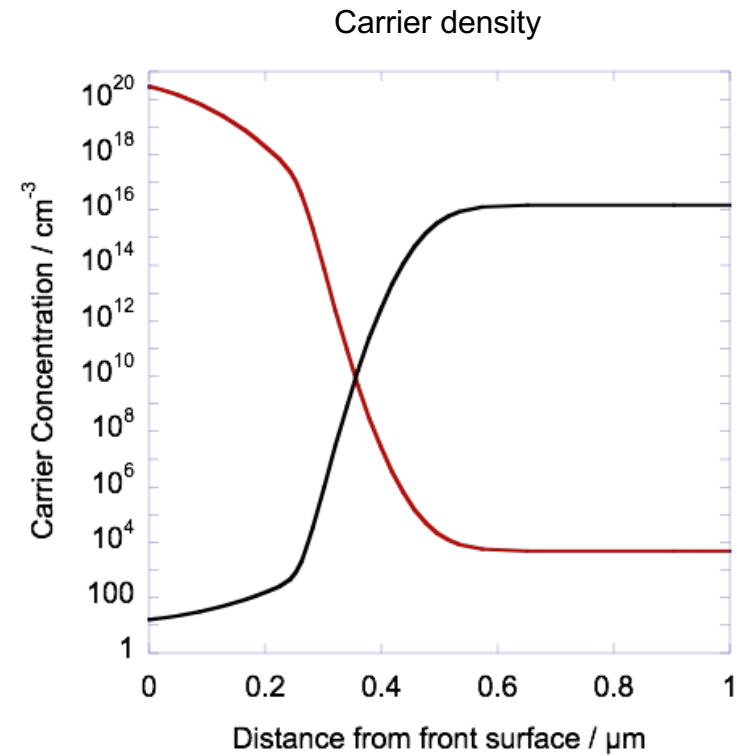
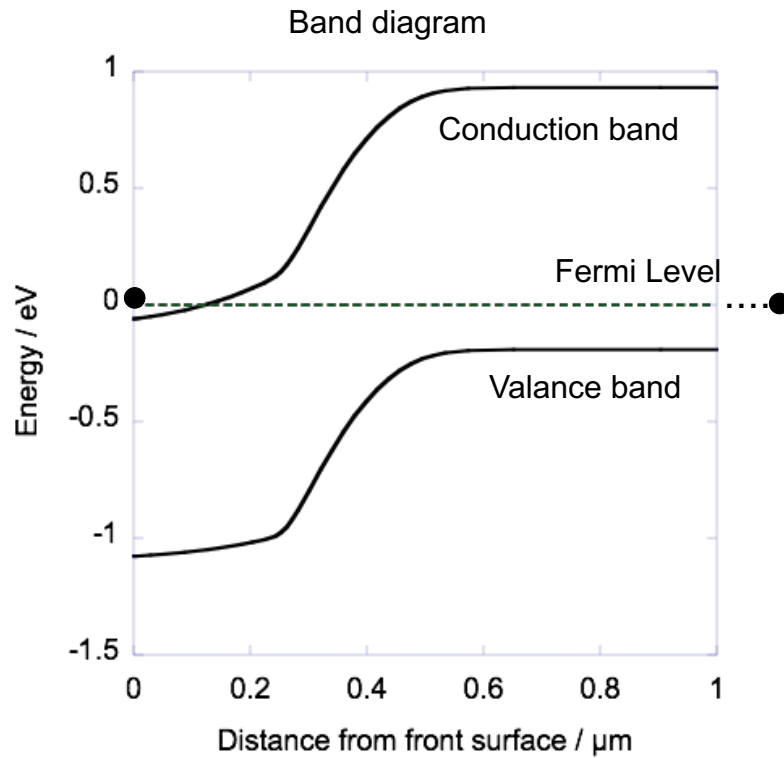
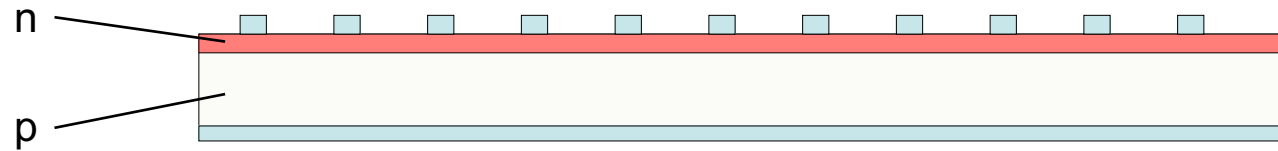
$$U_{rad} = B_{rad}(np - n_i^2)$$

Auger recombination

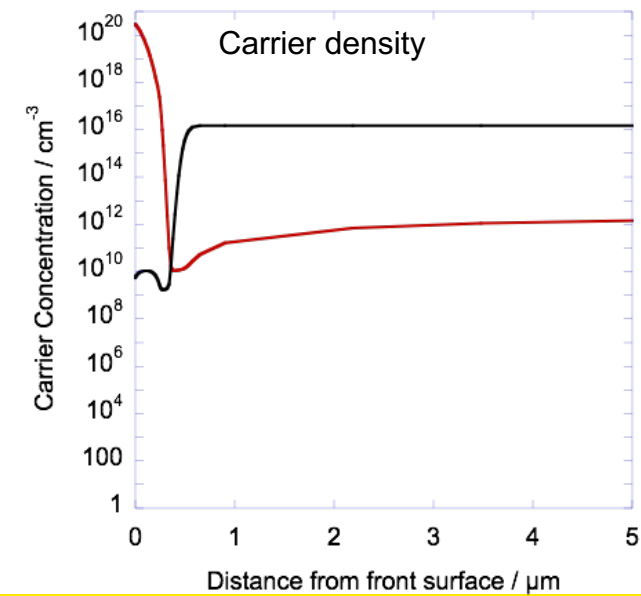
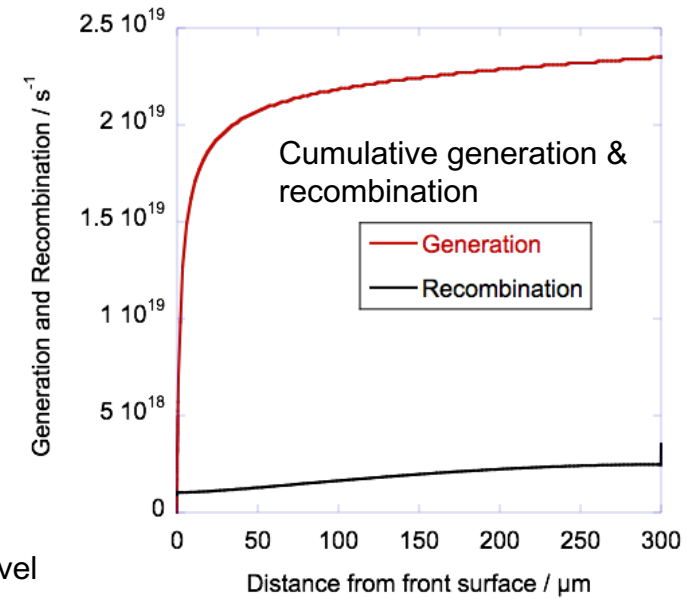
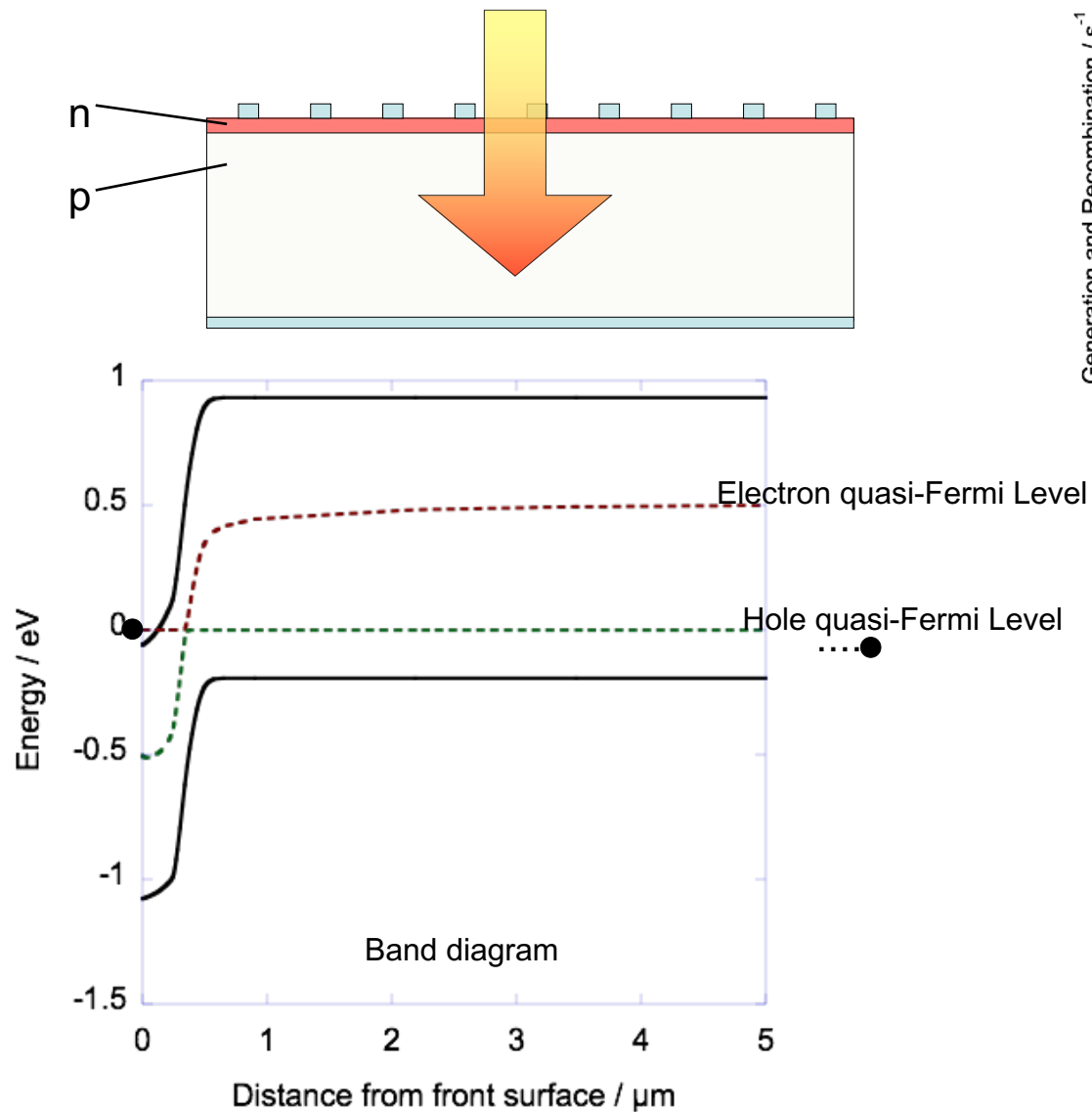


$$U_{aug} = (C_n n + C_p p)(np - n_i^2)$$

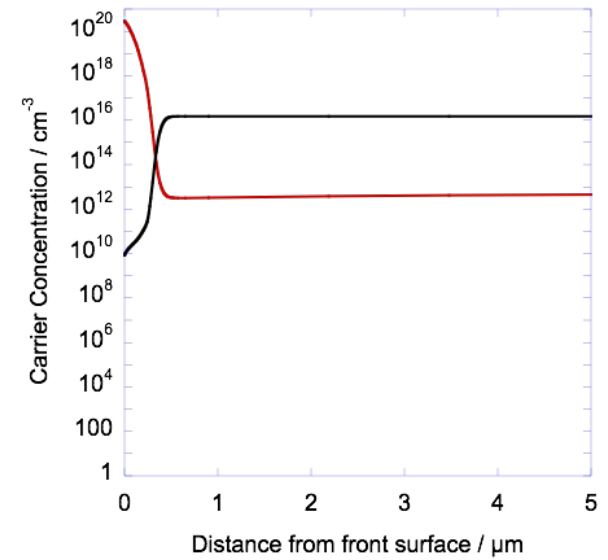
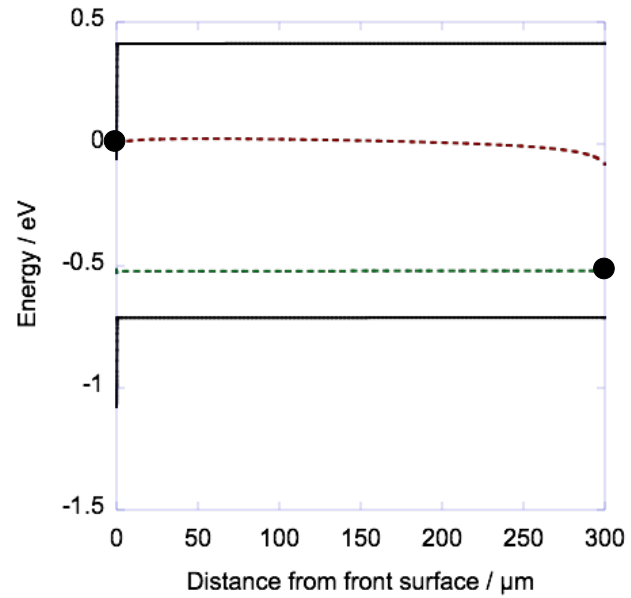
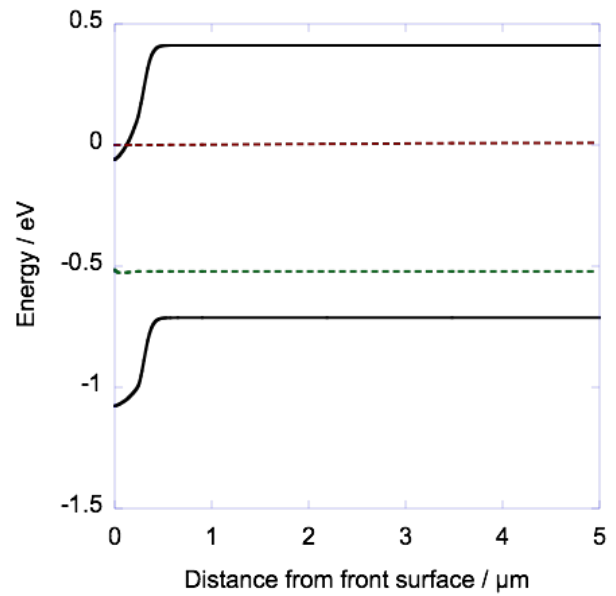
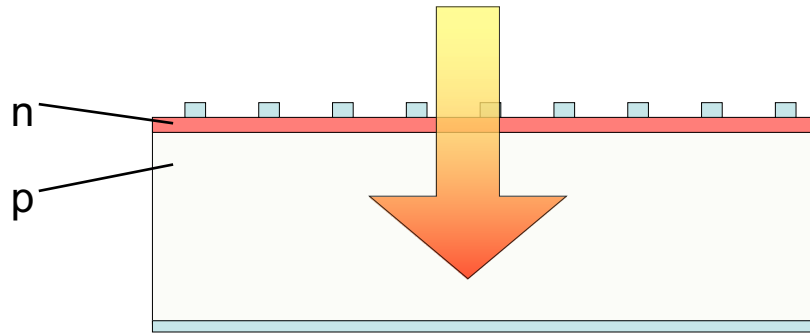
Silicon n/p solar cell : 0V Dark



Silicon n/p solar cell : 0V Illuminated - AM1.5G



Silicon n/p solar cell : Maximum power point Vmax Illuminated AM1.5G



p/n Junction : Depletion approximation

Shockley Diode Equation

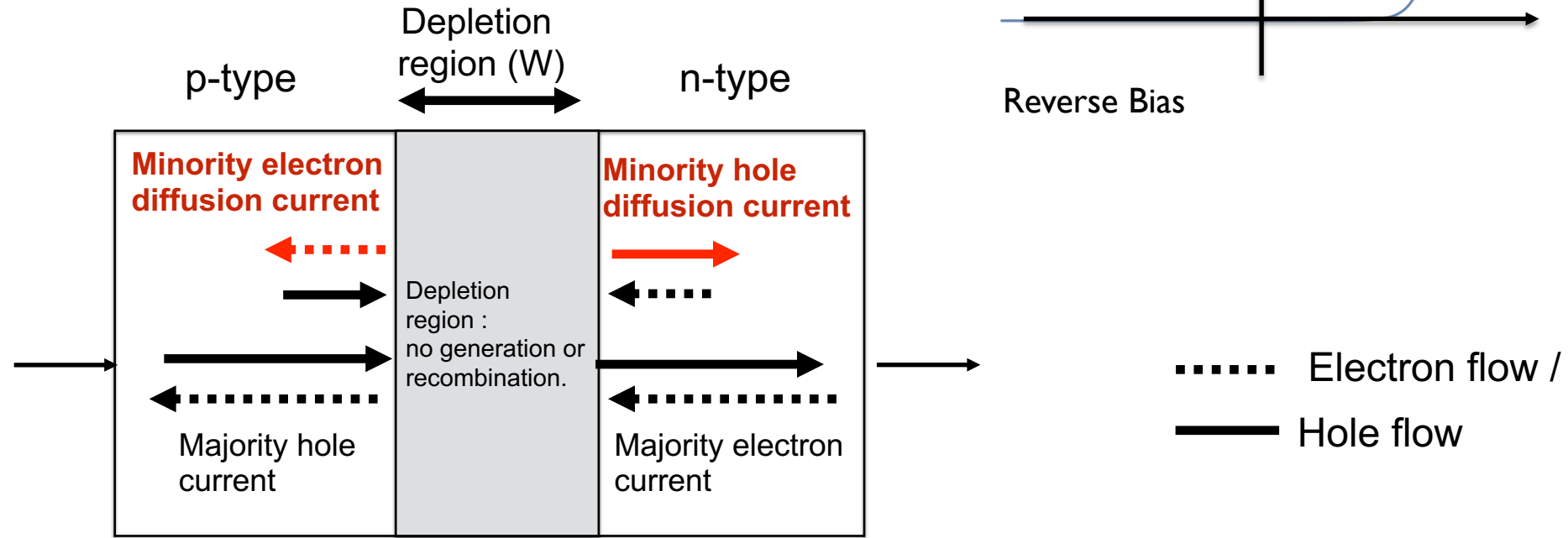
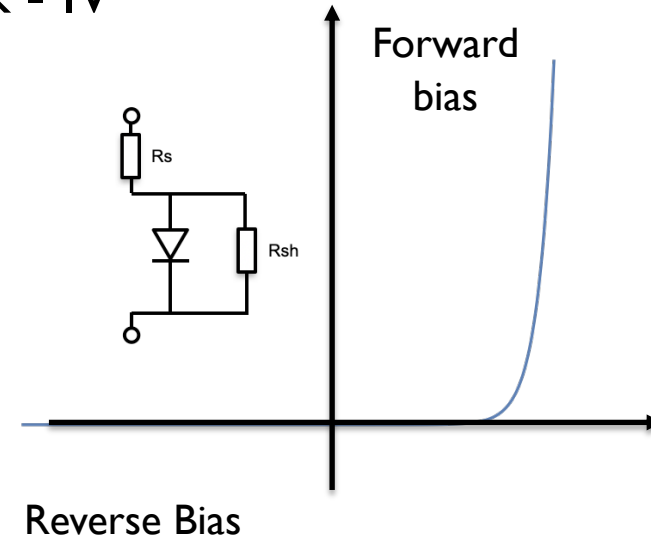
$$J(V) = J_0 \left(e^{\frac{qV}{kT}} - 1 \right)$$

where $J_0 = n_i^2 \left(\frac{qD_h}{L_h N_d} + \frac{qD_e}{L_e N_a} \right)$ $D = \mu \frac{kT}{q}$

Minority carrier diffusion length

$$L = \sqrt{D\tau}$$

Dark - IV



p/n Junction : Depletion approximation

Shockley Diode Equation

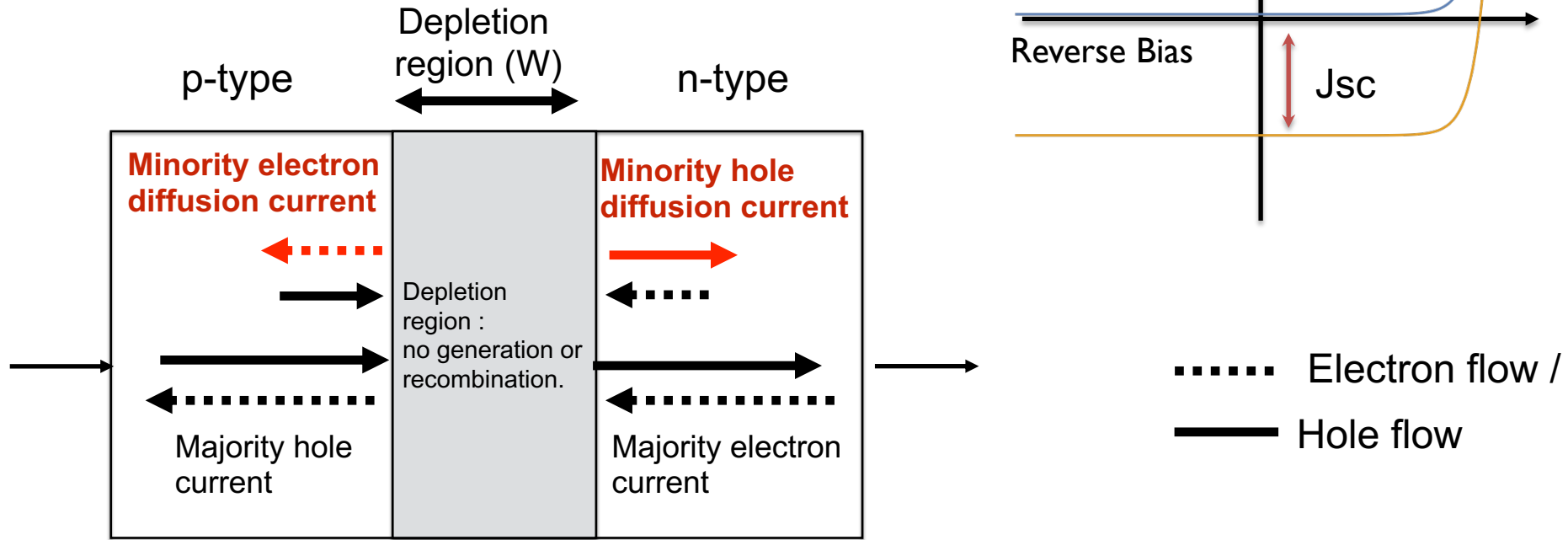
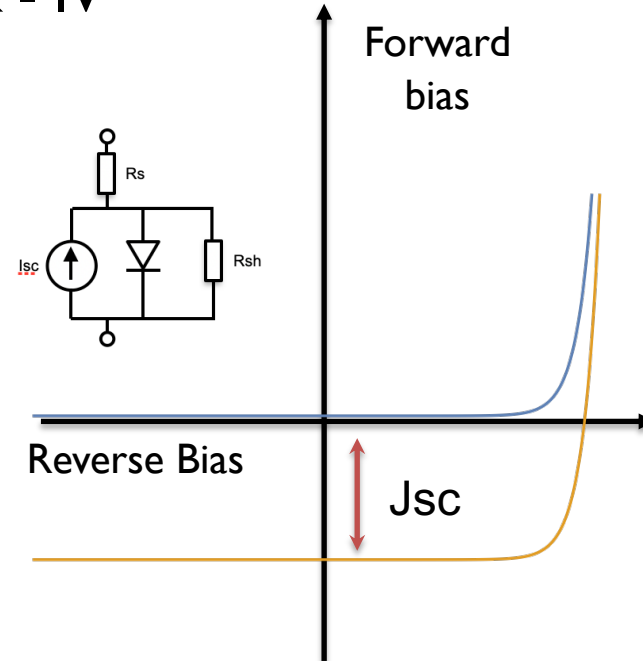
$$J(V) = J_0 \left(e^{\frac{qV}{kT}} - 1 \right) - \underline{J_{sc}}$$

where $J_0 = n_i^2 \left(\frac{qD_h}{L_h N_d} + \frac{qD_e}{L_e N_a} \right)$ $D = \mu \frac{kT}{q}$

Minority carrier diffusion length

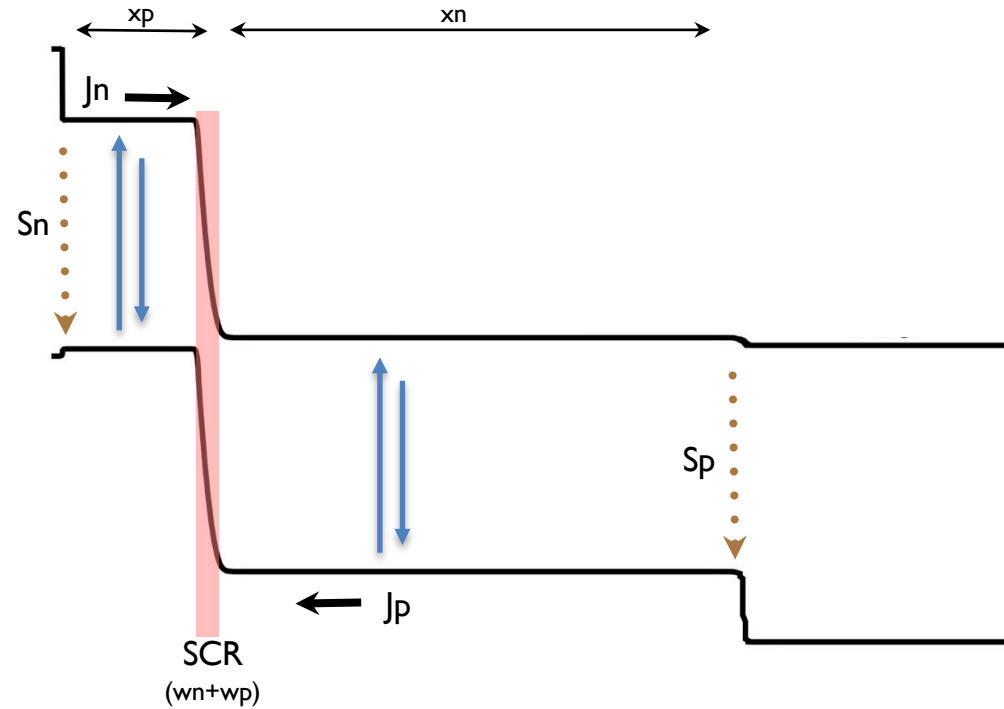
$$L = \sqrt{D\tau}$$

Dark - IV



Depletion approximation model for QE

J_n / J_p	Minority electron/hole current density
R	Surface reflection
α	Absorption coefficient
L_n / L_p	Minority electron, hole diffusion length
x_p / x_n	width of p / n regions
D_n / D_p	Carrier diffusivity for electrons and holes
w_n / w_p	Depletion widths on n/p side of the junction
n_0/p_0	Equilibrium electron/hole carrier density
S_n/S_p	Front / Rear surface recombination velocity
τ_n/τ_p	Electron / hole minority carrier lifetime
n_i	Intrinsic carrier concentration
T	Junction temperature
V	External junction bias



$$J_n(E, w_p) = \left(\frac{qb_s(1-R)\alpha L_n}{\alpha^2 L_n^2 - 1} \right) \left(\frac{\left(\frac{S_n L_n}{D_n} + \alpha L_n \right) - e^{-\alpha(x_p - w_p)} \left(\frac{S_n L_n}{D_n} \cosh \frac{x_p - w_p}{L_n} + \sinh \frac{x_p - w_p}{L_n} \right)}{\frac{S_n L_n}{D_n} \sinh \frac{x_p - w_p}{L_n} + \cosh \frac{x_p - w_p}{L_n}} - \alpha L_n e^{-\alpha(x_p - w_p)} \right)$$

$$J_{scr}(E, w_n, w_p) = qb_s(1-R)e^{-\alpha(x_p - w_p)}(1 - e^{-\alpha(w_p + w_n)})$$

$$J_p(E, w_n) = \left(\frac{qb_s(1-R)\alpha L_p}{\alpha^2 L_p^2 - 1} \right) e^{-\alpha(x_p + w_n)} \left(\alpha L_p - \frac{\frac{S_p L_p}{D_p} \cosh \frac{x_n - w_n}{L_p} - e^{-\alpha(x_n - w_n)} + \sinh \frac{x_n - w_n}{L_p}}{\frac{S_p L_p}{D_p} \sinh \frac{x_n - w_n}{L_p} + \cosh \frac{x_n - w_n}{L_p}} + \alpha L_p e^{-\alpha(x_n - w_n)} \right)$$

p/n Junction Diode : Dark-IV

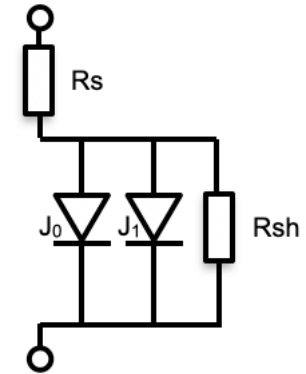
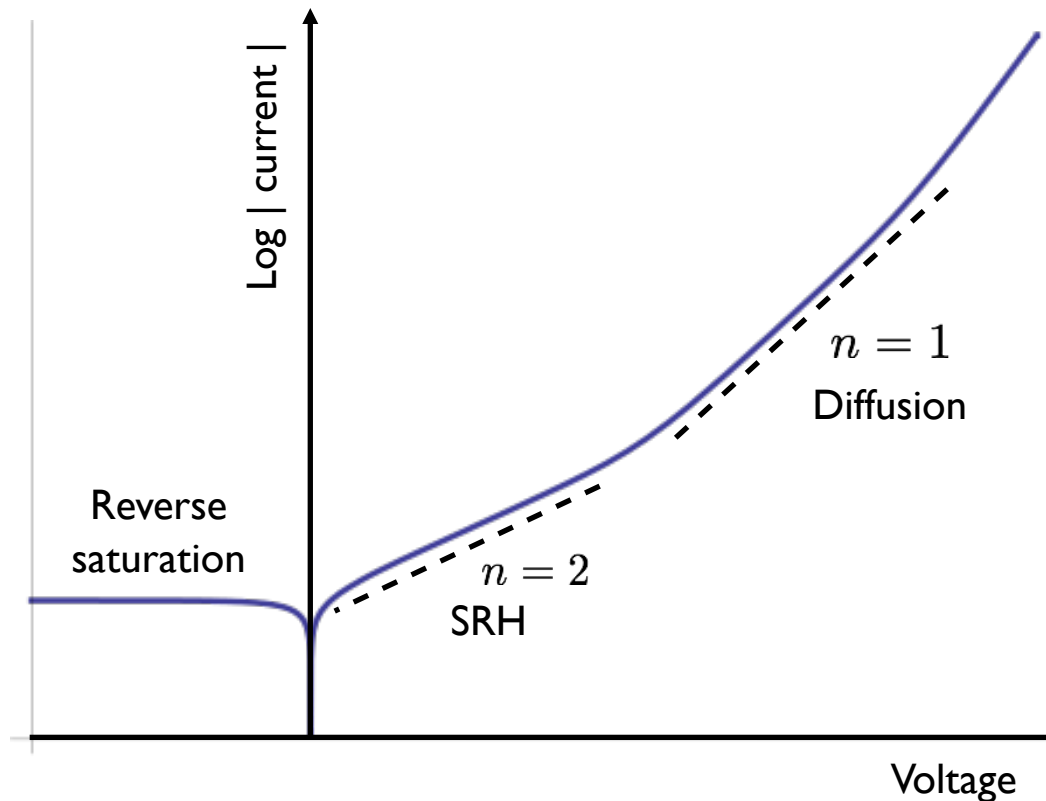
Diode Equation

$$J(V) \approx J_0 \left(e^{\frac{qV}{kT}} - 1 \right) \leftarrow \text{Diffusion (radiative \& non-radiative)}$$

$$+ J_1 \left(e^{\frac{qV}{2kT}} - 1 \right) \leftarrow \text{Impurity (SRH)}$$

Diode Equation with ideality factor

$$J_F(V) \approx J_s e^{\frac{qV}{nkT}}$$

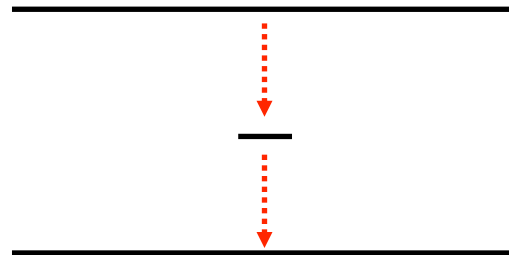


Shockley Read Hall Recombination

$$J(V) \approx J_0 \left(e^{\frac{qV}{kT}} - 1 \right) \leftarrow \text{Diffusion}$$

$$+ J_1 \left(e^{\frac{qV}{2kT}} - 1 \right) \leftarrow \text{Impurity}$$

Shockley Read Hall (SRH) recombination



- Non-radiative process
- Releases phonons

Deep & shallow levels

	Sb	P	As	Ti	C	Pt	Au	O
Si	0.039	0.045	0.054	0.21	0.25	0.25		0.16
								0.38
							0.54	0.51
							A	0.41
				0.34	0.35	0.36		
					D	0.3	D	0.29
	0.045	0.067	0.072	0.16				
	B	Al	Ga	In	Pd			

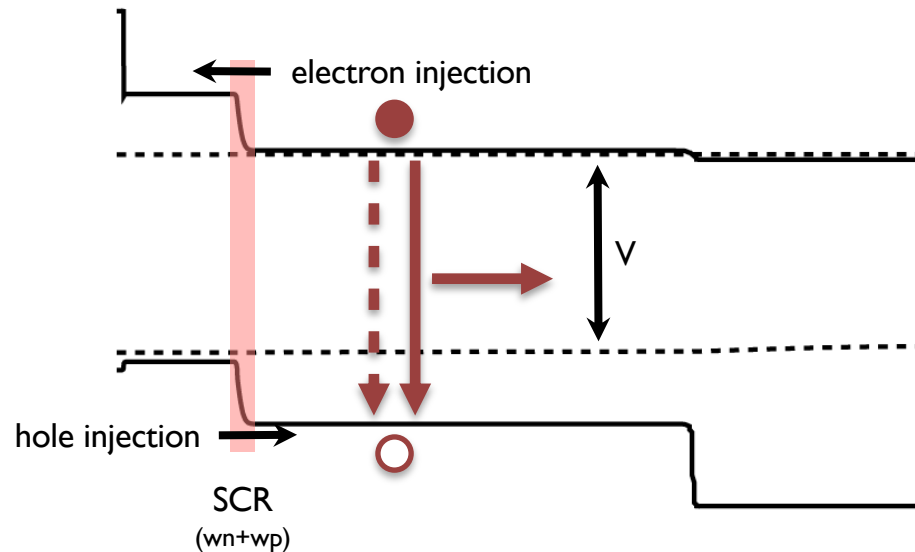
- Shallow levels are ionized at room temperature and can donate or accept electrons
- Deep levels trap carriers

$$J_1 = \sigma v_{th} N_t n_i \frac{qW}{2}$$

capture cross-section thermal velocity depletion width

trap concentration

Shockley diode models for J_0



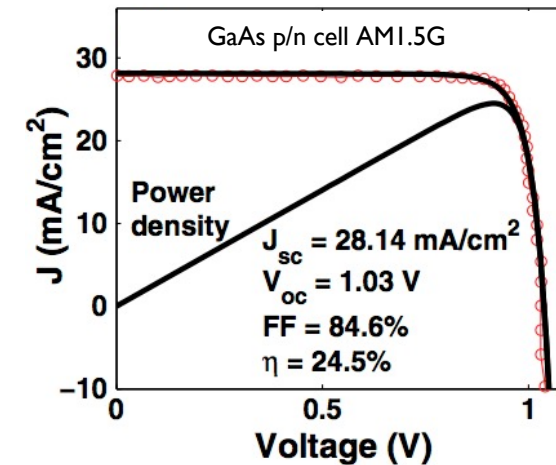
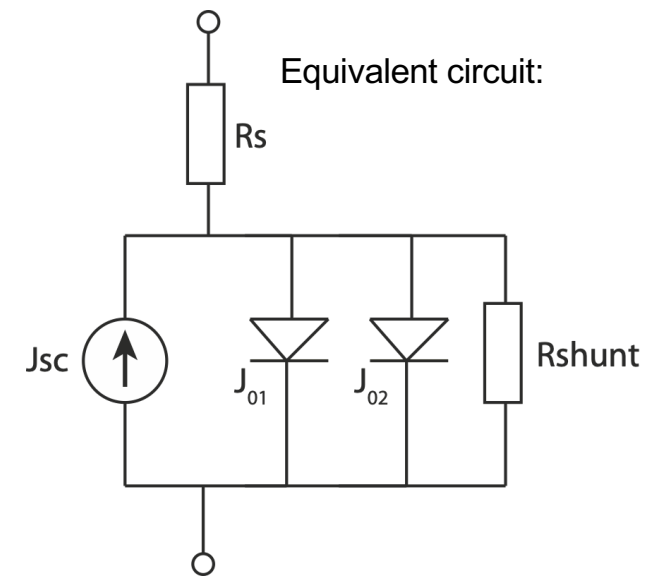
$$J_{\text{Total}} = J_{\text{SC}} - J_{01}(e^{qV/kT} - 1) - J_{02}(e^{qV/2kT} - 1)$$

Shockley diffusion current (Radiative & non-radiative):

$$J_{01} = \left(\frac{qD_n n_i^2}{L_n N_A} \frac{\cosh\left(\frac{W_p}{L_n}\right) + \frac{D_n}{S_n L_n} \sinh\left(\frac{W_p}{L_n}\right)}{\frac{D_n}{S_n L_n} \cosh\left(\frac{W_p}{L_n}\right) + \sinh\left(\frac{W_p}{L_n}\right)} + \frac{qD_p n_i^2}{L_p N_D} \frac{\cosh\left(\frac{W_n}{L_p}\right) + \frac{D_p}{S_p L_p} \sinh\left(\frac{W_n}{L_p}\right)}{\frac{D_p}{S_p L_p} \cosh\left(\frac{W_n}{L_p}\right) + \sinh\left(\frac{W_n}{L_p}\right)} \right)$$

Shockley-Read-Hall current: (non-radiative)

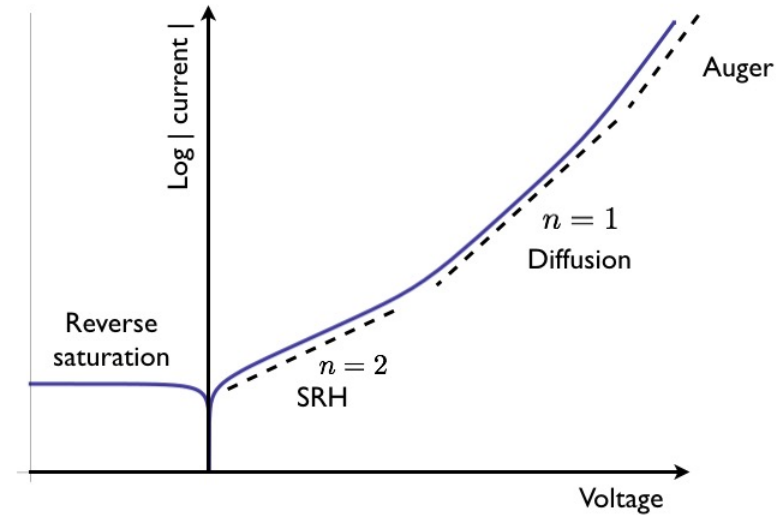
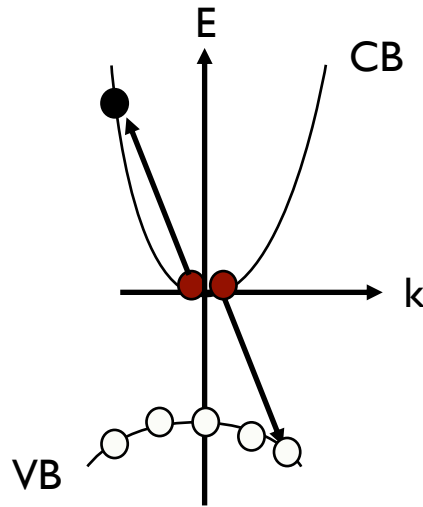
$$J_{02} = \frac{qn_i(W_n + W_p)}{\sqrt{\tau_n \tau_p}}$$



X. Li, et al. Prog. Photovolt: Res. Appl. 21, 109 (2013).

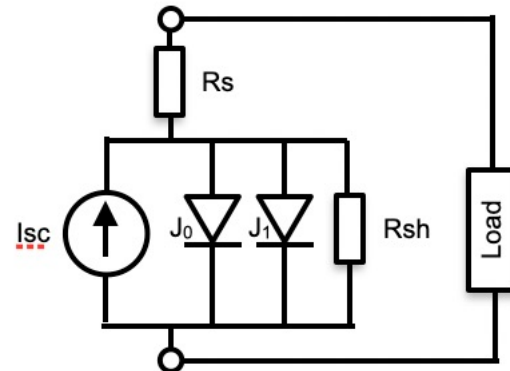
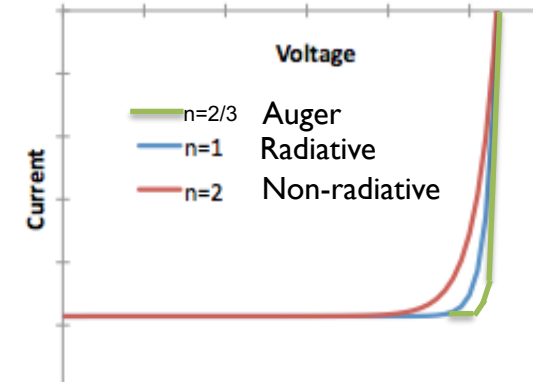
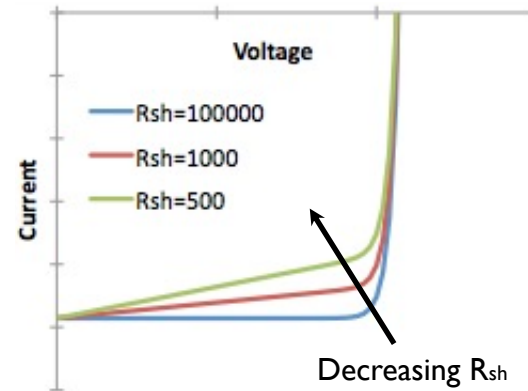
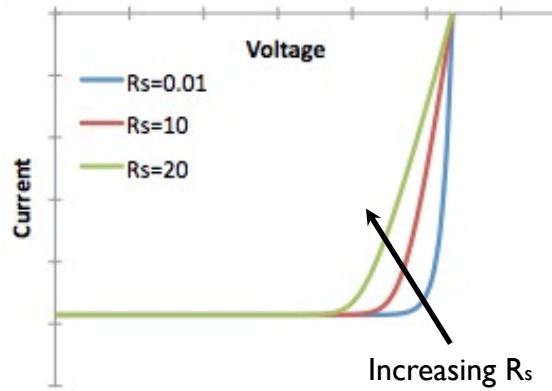
Auger Recombination

$$J(V) \approx J_0 \left(e^{\frac{qV}{kT}} - 1 \right) \leftarrow \text{Diffusion} \\ + J_1 \left(e^{\frac{qV}{2kT}} - 1 \right) \leftarrow \text{Impurity} \\ + J_2 \left(e^{\frac{3qV}{2kT}} - 1 \right) \leftarrow \text{Auger}$$



- Three particle process
 - e.g. two electrons one hole shown
- Momentum must be conserved
- Favoured at high carrier density
- Somewhat material dependent (m^*)

Fill Factor



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Session 5: Simple Si and GaAs cells using the depletion approximation

2nd August 2023

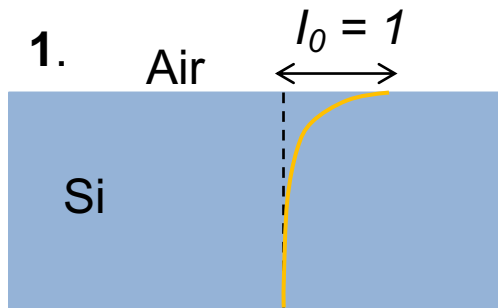
Ned Ekins-Daukes, Phoebe Pearce



Example 5a: Simple Si cell

Si is considered infinitely thick, with 200 μm of absorbing thickness (ignore back-surface reflection)

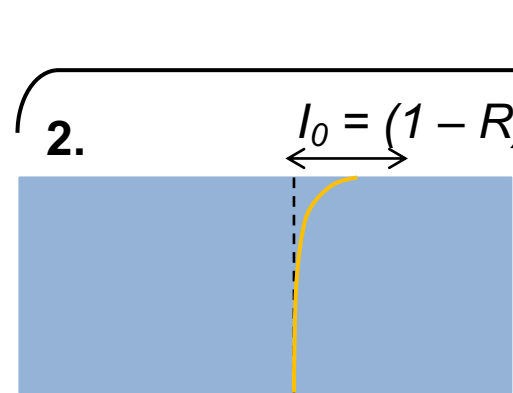
Calculate same result in this case!



Beer-Lambert absorption:

$$I(z) = I_0 e^{-\alpha(\lambda) z}$$

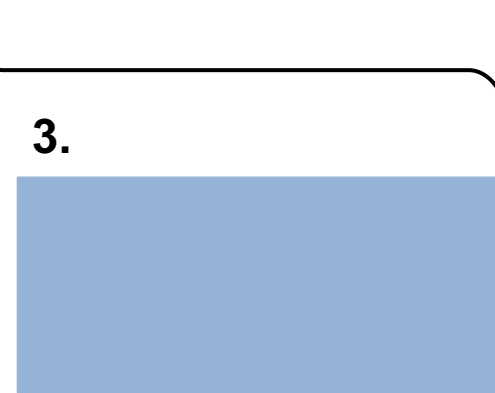
$$I_0 = 1$$



Fresnel eqn + Beer-Lambert absorption:

$$I(z) = I_0(\lambda) e^{-\alpha(\lambda) z}$$

$$I_0(\lambda) = 1 - R(\lambda)$$



Transfer matrix method
(Si treated *incoherently*)



Add ARC, Transfer-matrix method

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Sessions 6 & 7: Transfer-matrix method

2nd August 2023

Ned Ekins-Daukes, Phoebe Pearce



Transfer-matrix method (TMM) in Solcore

Defining structures

Materials $\text{Ga}_{0.51}\text{In}_{0.49}\text{P}$ = GaInP $\text{In} = 0.49$
 with optical properties $(n(\lambda), k(\lambda))$ retrieved from database

Layers 500 nm of InGaP

Stacks / Structures

Stack = [500 nm of InGaP
 + 1500 nm of GaAs
 + 70 nm of AlAs
 + ...]

calculate RAT of **Stack** with **AM0 spectrum**

Modelling optics

Transfer-matrix method (TMM)

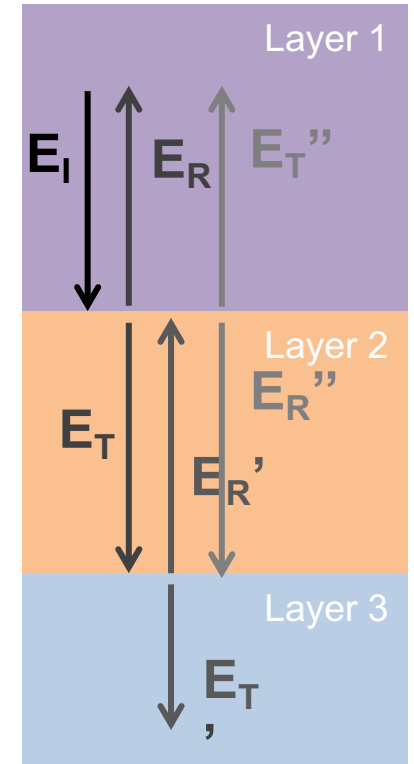
Efficiently handles **planar multilayer** stacks (including thin film interference effects)

$M_{\text{Layer 1}}$

$M_{\text{Layer 2}}$

Relates waves entering and exiting layer 2 (both directions)

$M_{\text{Layer 3}}$



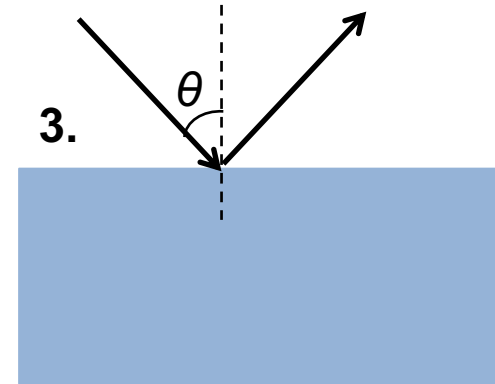
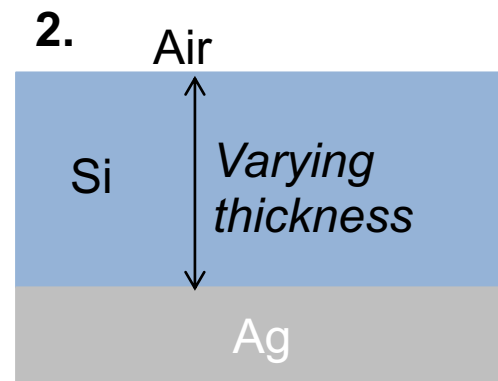
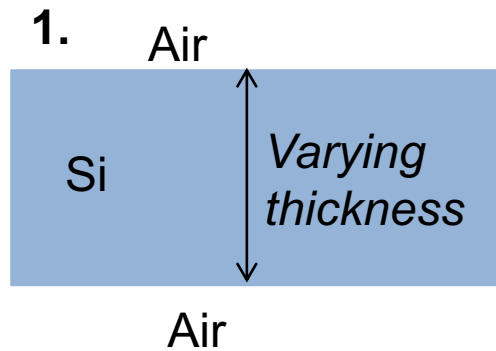
R, A, T of stack

$$M_{\text{stack}} = M_{01} \times M_{\text{Layer 1}} \times M_{\text{Layer 2}} \times M_{\text{Layer 3}} \times \dots$$

Solcore integrates & streamlines the **tmm** Python package

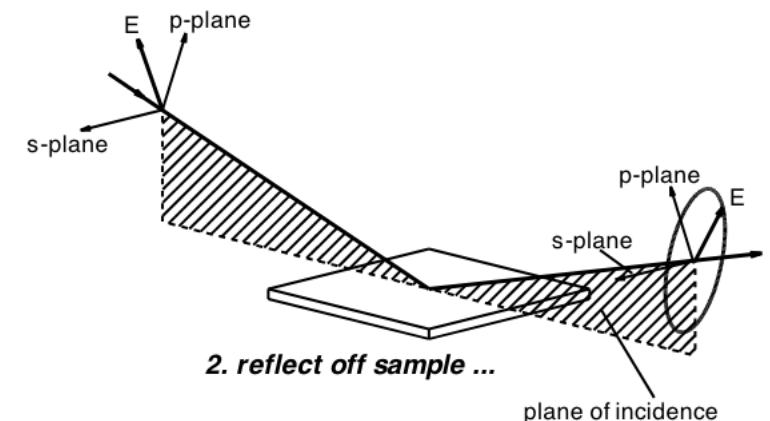
Example 6a: More exploration of TMM

No longer ignore back-surface reflection. Explore effect of different assumptions about coherency, the incidence angle, and the polarization of the incident light



Varying angle of incidence and polarization

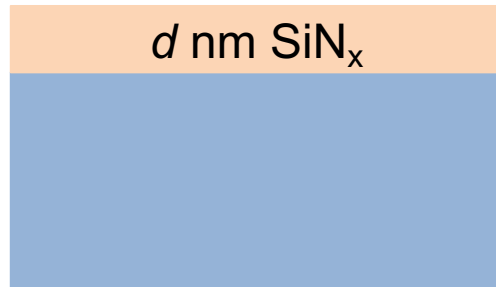
Treating a layer **incoherently** means **discarding the phase information** inside that layer; no **Fabry-Perot/thin-film interference**. The absorption profile is assumed to follow the Beer-Lambert law.



Example 6b: Simple ARC optimization

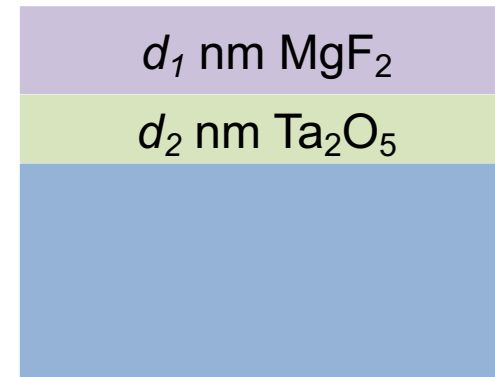
Find ARC layer thicknesses which minimize reflectance

1.



Vary d

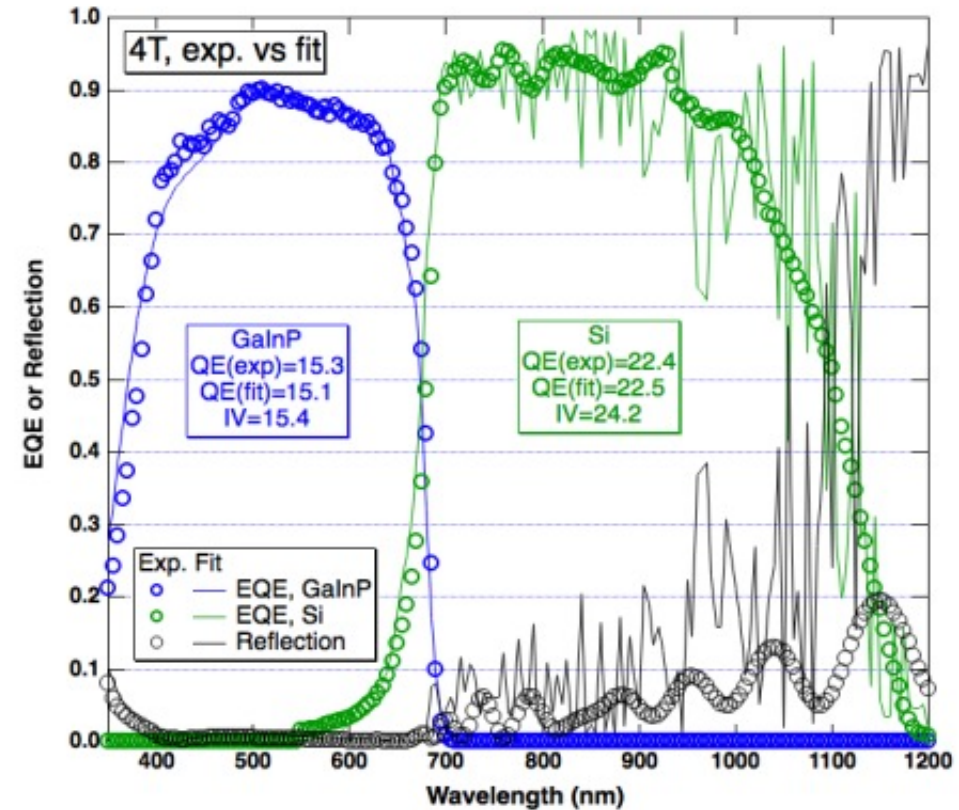
2.



Vary d_1 and d_2

Example 7: Planar GaInP/Si cell (2-terminal vs. 4-terminal)

Material	Thickness (nm)	Contrib. to j_{sc}
air	0	0
MgF ₂	97	0
ZnS	41	0
n-Al _{0.52} In _{0.48} P	17 (20)	0
n-Ga _{0.5} In _{0.5} P	950 (1000)	0.91
p-Al _{0.27} Ga _{0.26} In _{0.47} P	200	0
p-Al _{0.5} Ga _{0.5} As	500	0
ZnS	82	0
epoxy	10,000	0
glass, n=1.56	1,000,000	0
epoxy	10,000	0
PECVD SiO _x	100	0
SiN _x , n=1.91	70	0
SiN _x , n=2.4	15	0
n,p-Si	357,000 (150,000)	1
Al ₂ O ₃	15	0
SiN _x , n=1.91	120	0
Al	10,000	0



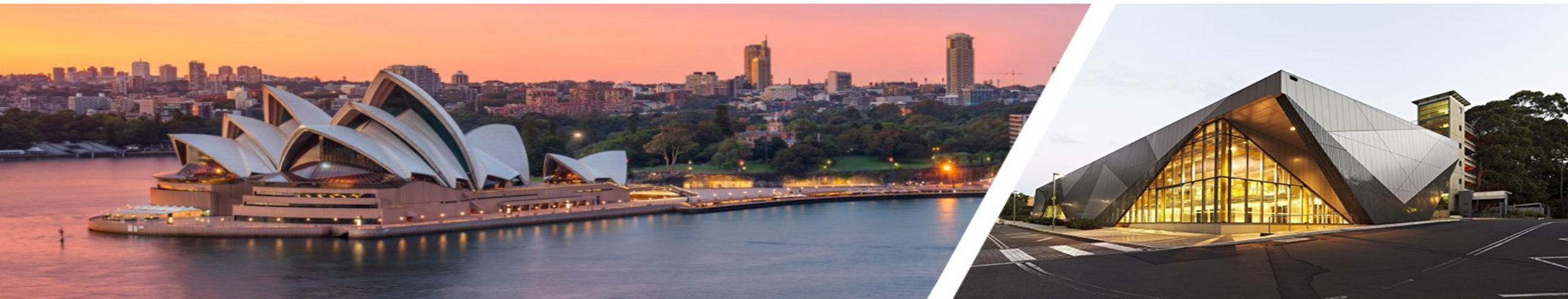
Note: the paper uses a textured Si bottom cell, while we assume all interfaces are planar. We will discuss the use of textures in III-V/Si and perovskite/Si tandem cells tomorrow.

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Sessions 8 - 10: Advanced optical modelling

3rd August 2023

Phoebe Pearce, Ned Ekins-Daukes



RayFlare installation

- Previously, we have used **Solcore** for all the examples.
 - Solcore has quite a lot of optics capabilities, but **it cannot do ray-tracing**
 - **RayFlare** is our dedicated optics package; it can reproduce what Solcore does, but also adds new functionality:
 - Ray-tracing
 - Angular redistribution matrix method (ARMM)
- Please go to **rayflare.readthedocs.io** and read the installation instructions
 - Basic installation: **pip install rayflare**
 - This will install everything except RCWA functionality (for diffraction gratings/2D periodic structures)
 - Installation instructions for RCWA functionality can be found in the documentation. Unfortunately, it does not work on Windows (but all other RayFlare functionality does work!)
- More instructions for running Linux inside Windows:
http://docs.solcore.solar/en/latest/Installation/Solcore_on_Windows.html

RayFlare capabilities

Simulations using a single method



Ray-tracing: Geometric optics for large-scale textures without diffraction effects



Transfer-matrix method: Wave optics for planar layers (coherent and incoherent)



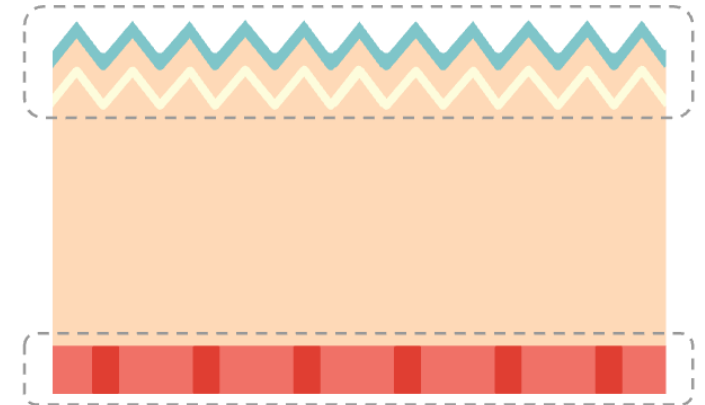
Rigorous coupled-wave analysis: Wave optics for planar or periodic structures e.g. gratings, photonic crystals

Ideal cases: E.g. perfect mirrors, Lambertian scattering

Calculate e.g. reflection, transmission, absorption per layer, depth-dependent absorption profiles

Simulations using angular redistribution matrices

Each surface is treated separately with an appropriate method



Documentation: <https://rayflare.readthedocs.io>

Transfer-matrix method (TMM)

Defining structures

Materials $\text{Ga}_{0.51}\text{In}_{0.49}\text{P}$ = GaInP $\text{In} = 0.49$
 with optical properties $(n(\lambda), k(\lambda))$ retrieved from database

Layers 500 nm of InGaP

Stacks / Structures

Stack = [500 nm of InGaP
 + 1500 nm of GaAs
 + 70 nm of AlAs
 + ...]

calculate RAT of **Stack** with AM0 spectrum

Modelling optics

Transfer-matrix method (TMM)

Efficiently handles **planar multilayer** stacks (including thin film interference effects)

$M_{\text{Layer 1}}$

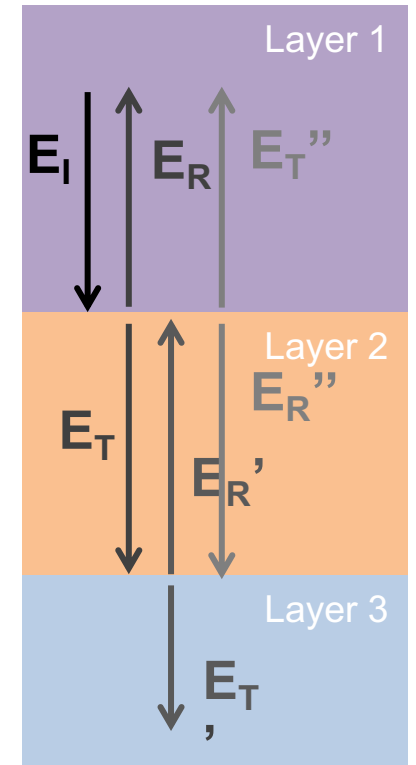
$M_{\text{Layer 2}}$

Relates waves entering and exiting layer 2 (both directions)

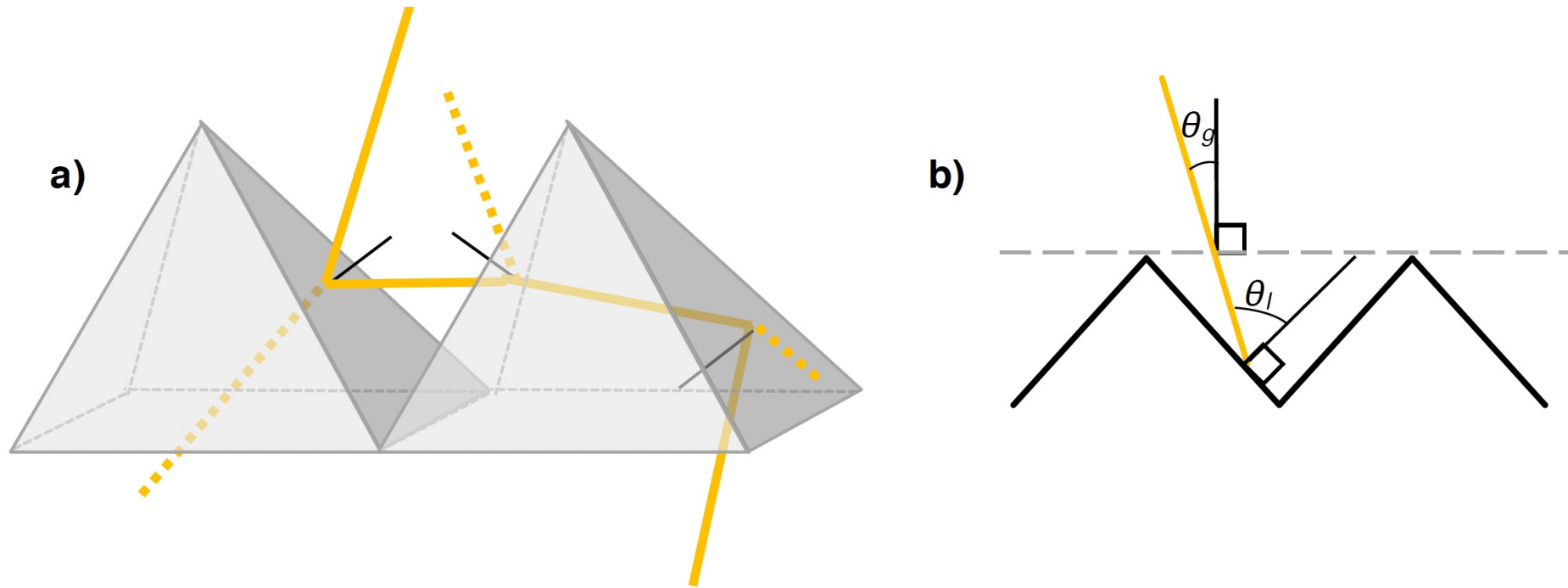
$M_{\text{Layer 3}}$

R, A, T of stack

$$M_{\text{stack}} = M_{01} \times M_{\text{Layer 1}} \times M_{\text{Layer 2}} \times M_{\text{Layer 3}} \times \dots$$



Ray-tracing



Reflection and transmission probabilities can be calculated using the Fresnel equations (for simple interfaces) or TMM (for interface with thin layers). If using TMM, can also calculate absorption per layer (and absorption profiles)

Rigorous coupled-wave analysis (RCWA)

(Also called the "Fourier Modal Method")

A method for solving Maxwell's equations, which transforms the problem to the frequency domain (for structures which are periodic in two dimensions).

Keeping more "Fourier orders" should make the solution more accurate, but increases the computation time

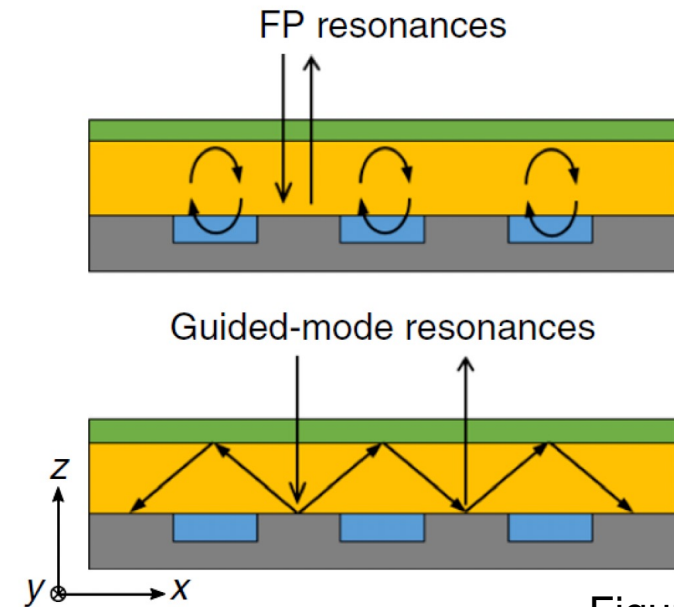
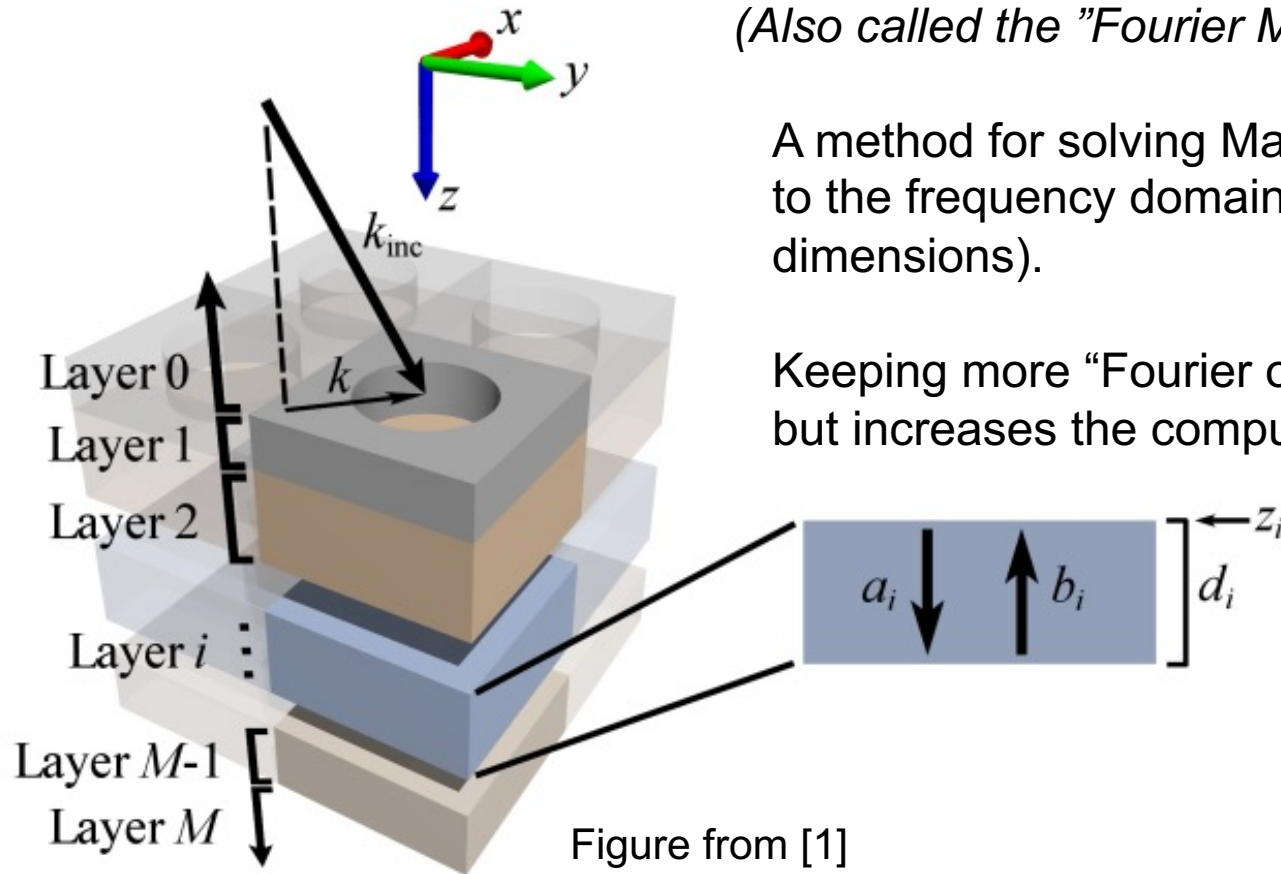


Figure from [2]

[1] H.-L. Chen *et al.*, *Nature Energy*, vol. 4, no. September, 2019, doi: [10.1038/s41560-019-0434-y](https://doi.org/10.1038/s41560-019-0434-y).

[2] <https://web.stanford.edu/group/fan/S4>

Angular Redistribution Matrix Method

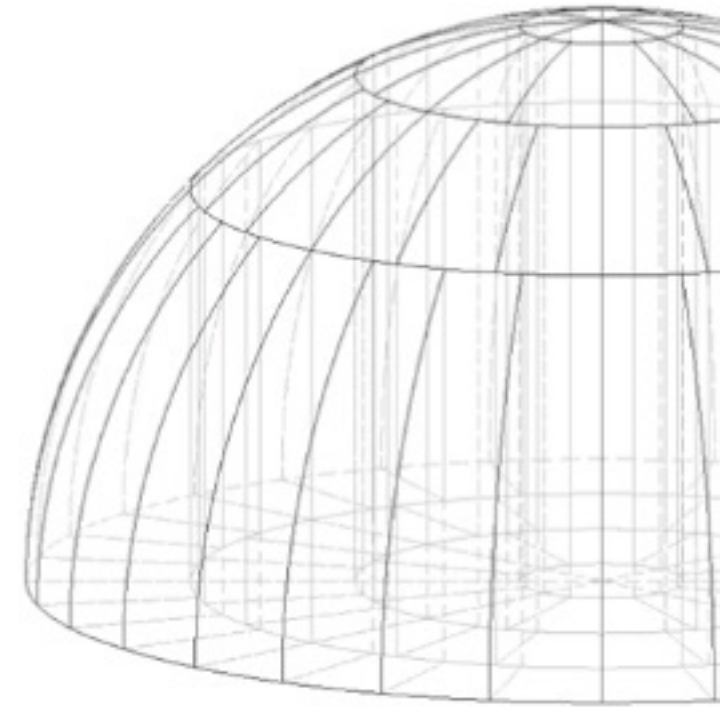
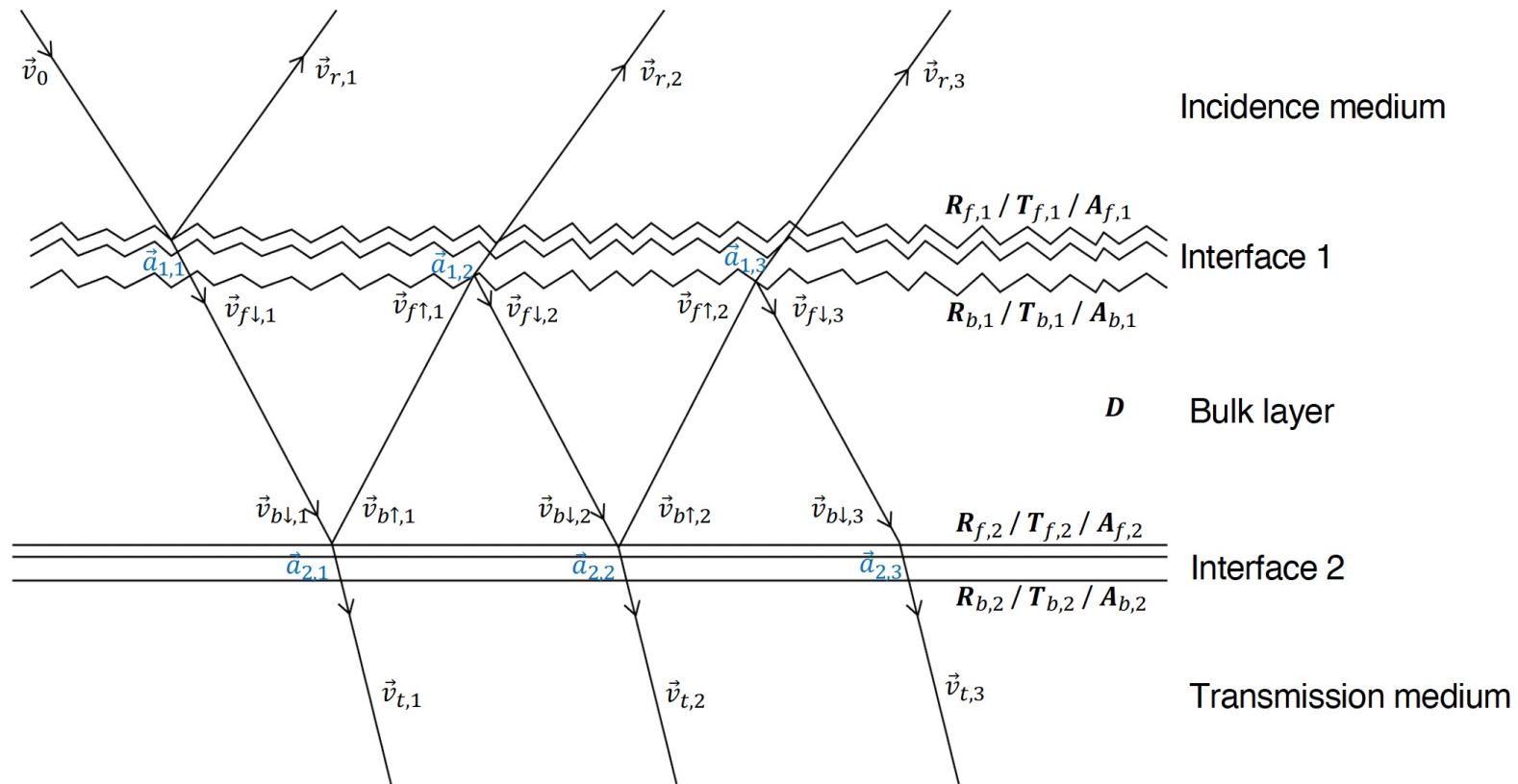
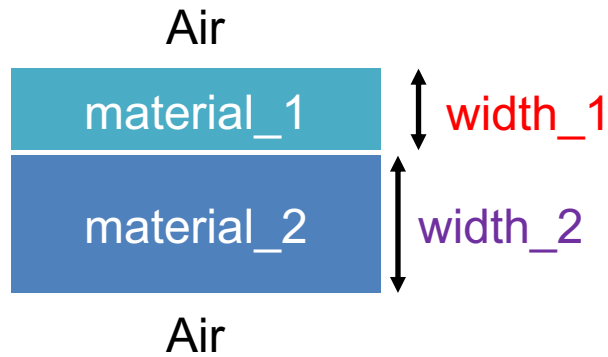


Image from [1]

[1] N. Tucher *et al.*, *Optics Express*, vol. 23, no. 24, p. A1720, 2015, doi: [10.1364/OE.23.0A1720](https://doi.org/10.1364/OE.23.0A1720).

Using a single method: what does it look like in the code?

TMM



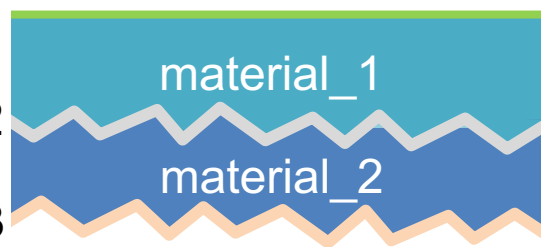
```
from rayflare.transfer_matrix_method import tmm_structure
```

```
TMM_stack = tmm_structure(  
    layer_stack=[Layer(width_1, material_1), Layer(width_2, material_2)],  
    incidence=Air,  
    transmission=Air)
```

texture_1

texture_2

texture_3



```
from rayflare.ray_tracing import rt_structure
```

```
RT_stack = rt_structure(  
    textures=[texture_1, texture_2, texture_3],  
    materials=[material_1, material_2],  
    widths=[width_1, width_2],  
    incidence=Air, transmission=Air)
```

Ray-tracing (RT)

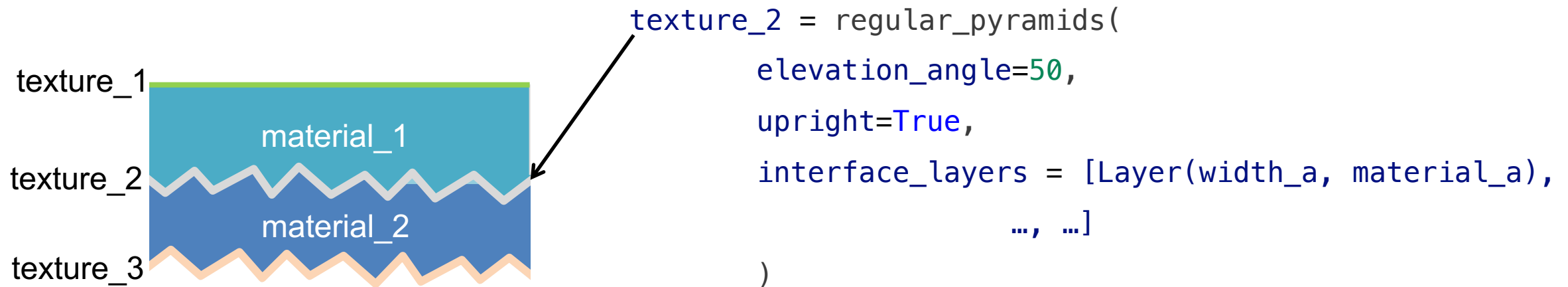


RCWA

```
from rayflare.rigorous_coupled_wave_analysis import rcwa_structure
```

```
RCWA_stack = rcwa_structure(  
    structure=[Layer(width_1, material_1), Layer(width_2, material_2)],  
    size=((100, 0), (0, 100)), # in nm  
    options=user_options,  
    incidence=Air, transmission=Air)
```

Some more detail about ray-tracing structures: rt_structure



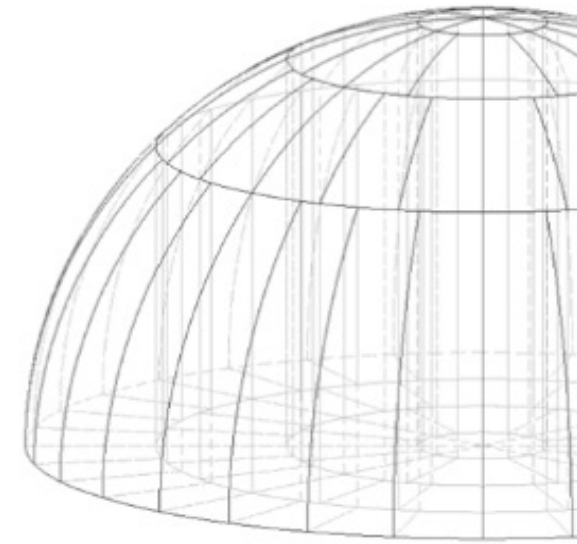
In `rt_structure`, it is assumed that the **bulk layers** (material_1, material_2 in the diagram) are thick enough (or absorbing enough) that we can **ignore thin-film interference**.

However, the **interface textures themselves can be modified with additional thin-film layers!** If there are interface layers, RayFlare will first calculate reflection/absorption/reflection probabilities using TMM, and then use these probabilities during the ray-tracing calculation:

→ **Fully integrated ray-tracing + TMM, inside `rt_structure`!**

But what if we want to combine other methods?

- Previous slide: integrated ray-tracing + TMM
- But what if we want to integrate e.g.:
 - TMM and RCWA
 - Ray-tracing and RCWA
 - Other methods we define ourselves (or maybe real measured data!)



→ Use the angular redistribution matrix method (ARMM), also called the “OPTOS method”

- Calculate angular redistribution matrices for each surface: how light incident from any angle is scattered by the surface (or absorbed). Use an appropriate method for each surface.

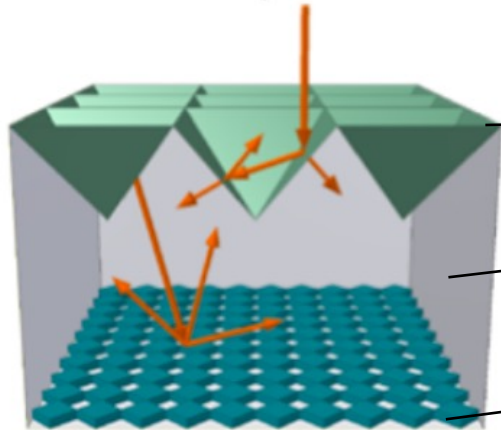
$$\mathbf{R}, \mathbf{T} = \begin{pmatrix} p(\{\theta_1, \phi_1\} \rightarrow \{\theta_1, \phi_1\}) & p(\{\theta_1, \phi_2\} \rightarrow \{\theta_1, \phi_1\}) & \dots & p(\{\theta_n, \phi_m\} \rightarrow \{\theta_1, \phi_1\}) \\ p(\{\theta_1, \phi_1\} \rightarrow \{\theta_1, \phi_2\}) & p(\{\theta_1, \phi_2\} \rightarrow \{\theta_1, \phi_2\}) & \dots & p(\{\theta_n, \phi_m\} \rightarrow \{\theta_1, \phi_2\}) \\ \vdots & \ddots & & \vdots \\ p(\{\theta_1, \phi_1\} \rightarrow \{\theta_n, \phi_m\}) & p(\{\theta_1, \phi_2\} \rightarrow \{\theta_n, \phi_m\}) & \dots & p(\{\theta_n, \phi_m\} \rightarrow \{\theta_n, \phi_m\}) \end{pmatrix}$$

ARMM (continued)

- Assume Beer-Lambert-like absorption in bulk medium which connects the two surfaces:

$$D = \begin{bmatrix} e^{-\alpha d/|\cos \theta_1|} & 0 & \dots & 0 \\ 0 & \ddots & & 0 \\ 0 & \vdots & \vdots & 0 \\ 0 & \dots & 0 & e^{-\alpha d/|\cos \theta_m|} \end{bmatrix}$$

- Now, we have turned the complex optics problem into **matrix multiplication**
- In the code:



```
from rayflare.structure import Interface, BulkLayer, Structure
```

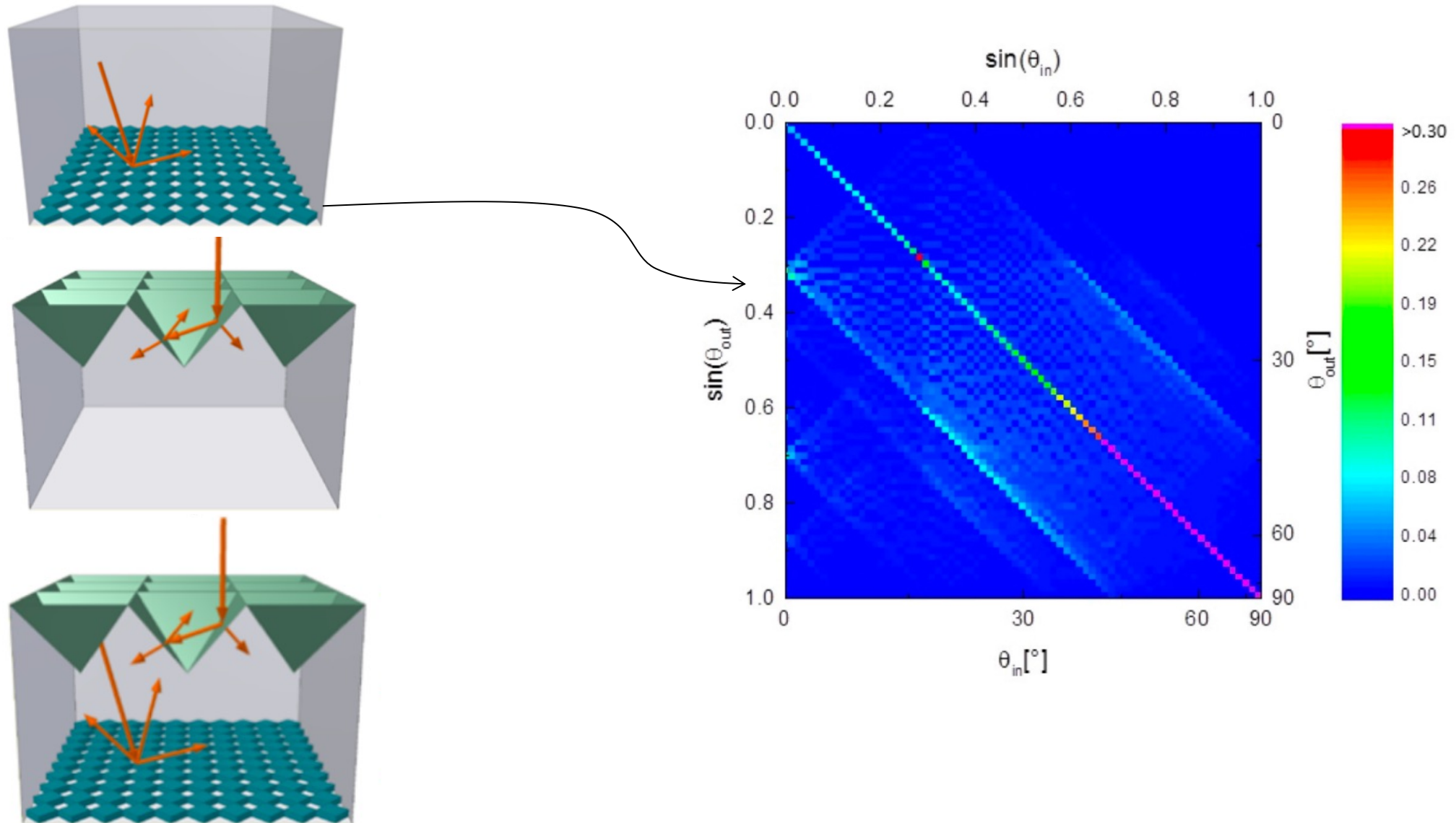
```
front_surf = Interface(method="RT_TMM", ...)
```

```
bulk_mat = BulkLayer(width=200e-6, material=material_1)
```

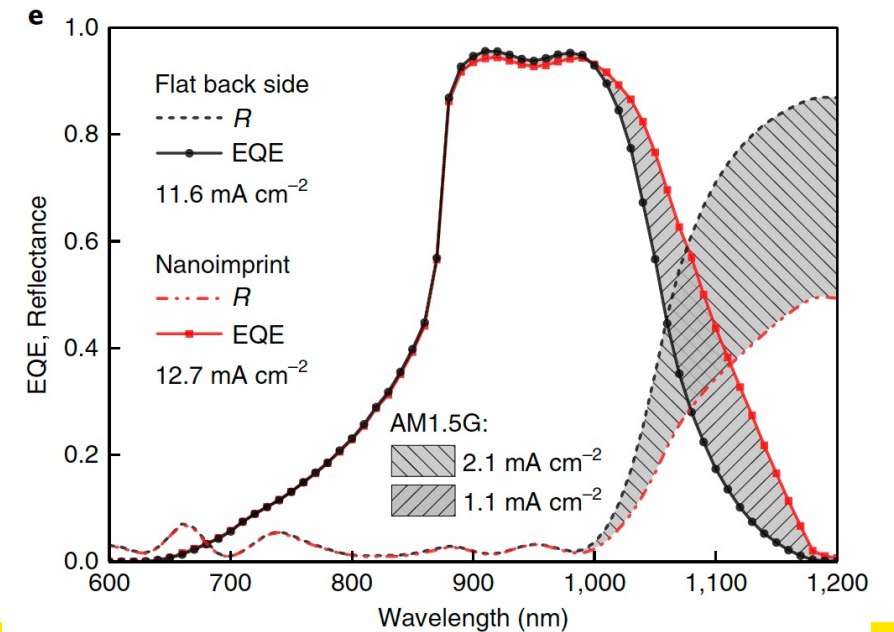
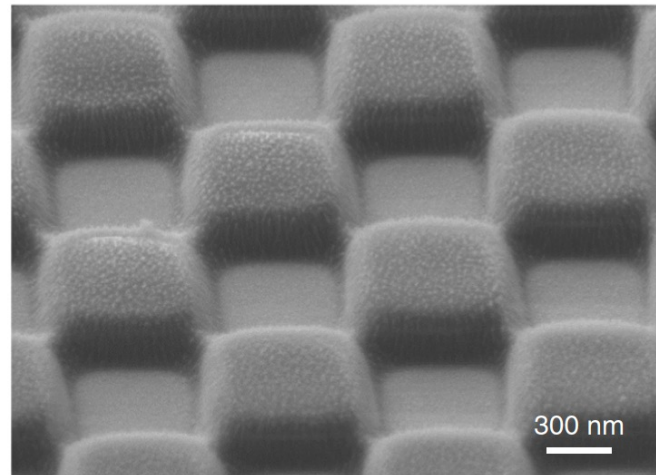
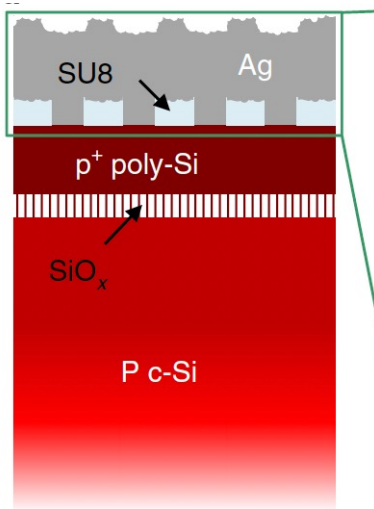
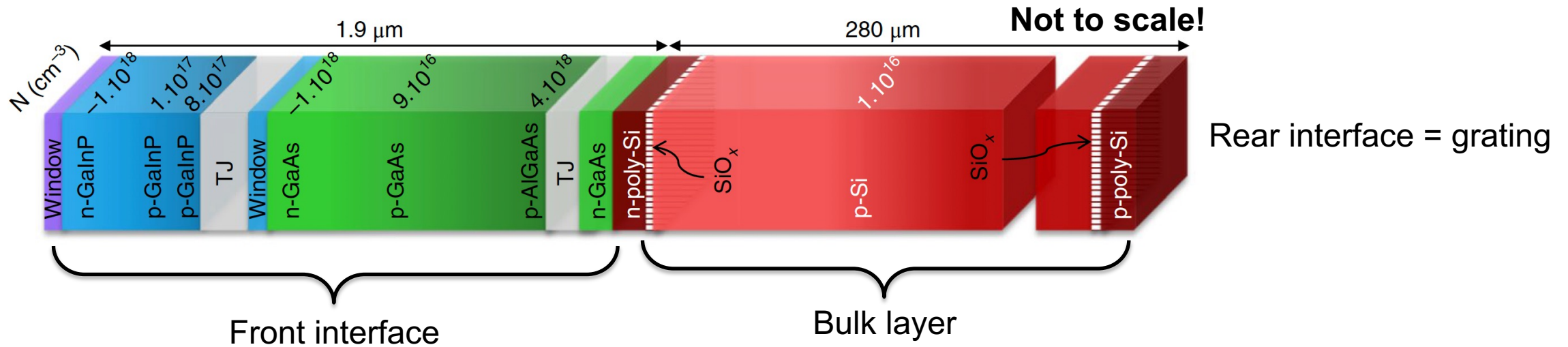
```
back_surf = Interface(method="RCWA", ...)
```

```
whole_stack = Structure([front_surf, bulk_mat, back_surf], incidence=Air, transmission=Air)
```

8. Textured Si: pyramids/grating



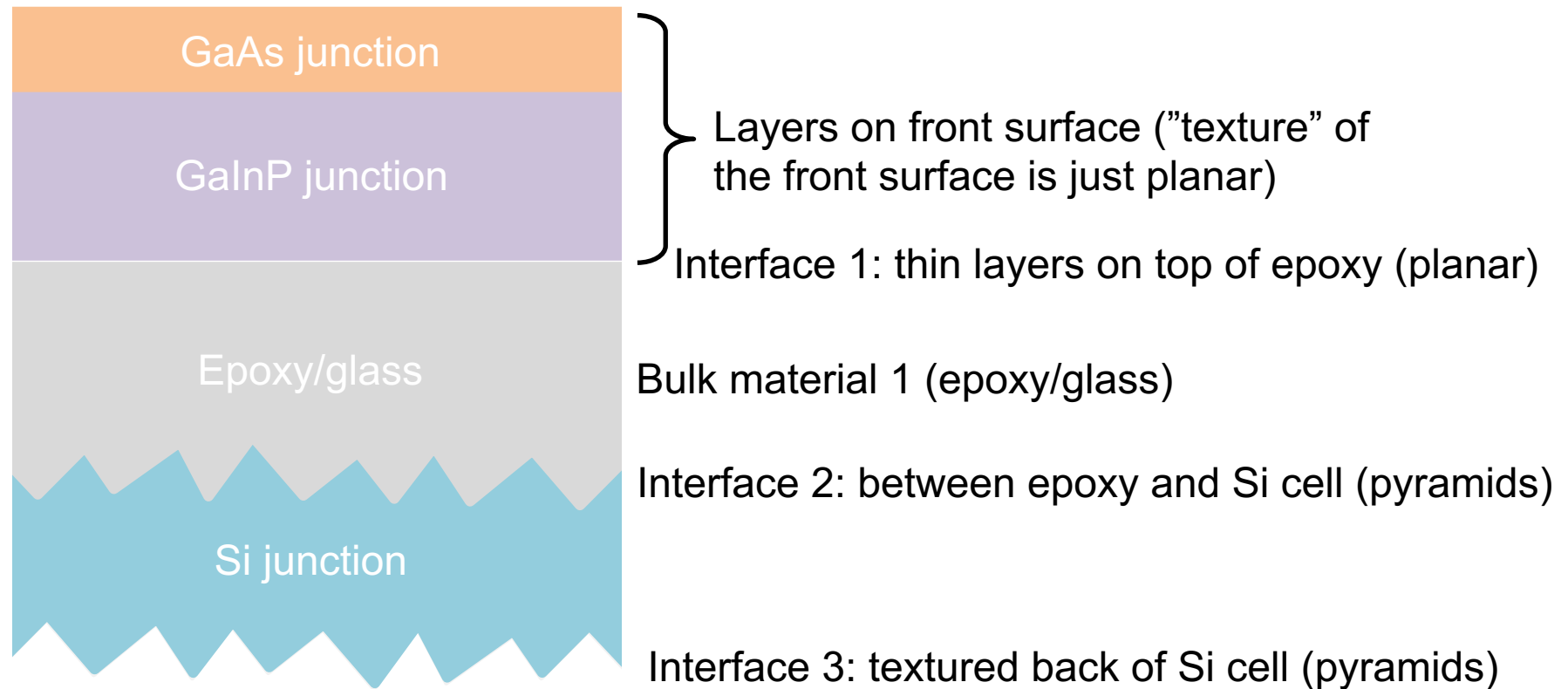
9a. III-V on Si, planar vs. rear grating, using ARMM



9b. III-V on Si, planar vs. pyramidal Si texture

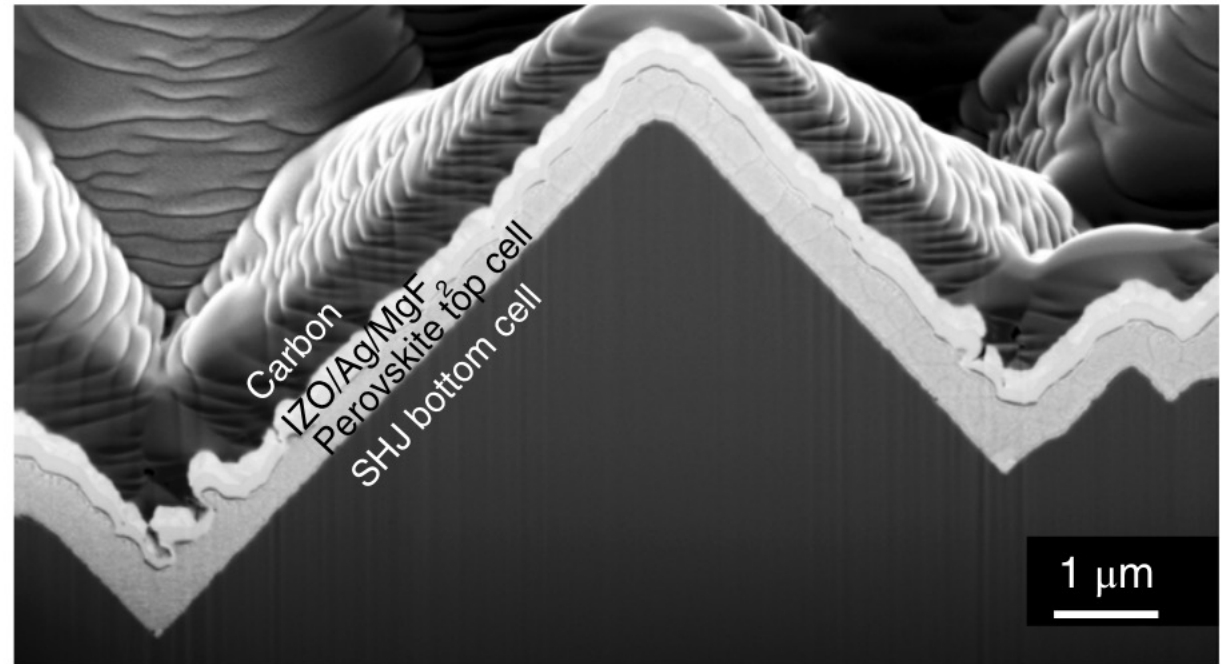
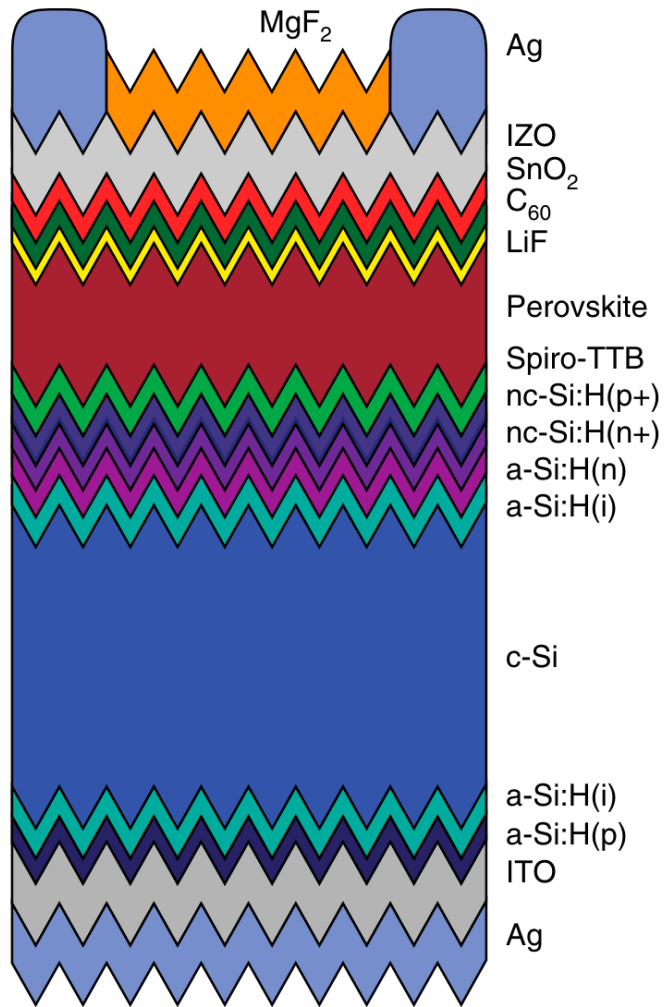
Use same III-V layer stack as previous example, but assume Si is pyramidally textured on both sides, and epoxy/glass is used to mechanically connect the III-V layers to the Si.

Use `rt_structure` to define stack



Extremely not to scale! Epoxy/glass is orders of magnitude thicker than GaAs/GaInP!

10. Conformal perovskite on pyramidal Si texture



Thank you!

We would really appreciate your feedback:

<https://tinyurl.com/bdu29k3x>



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